LMH5401-SP (5962R1721401VXC) Neutron Displacement Damage Characterization

ABSTRACT

This report presents the effect of neutron displacement damage (NDD) on the LMH5401-SP device. The results show that all devices were fully functional and within production test limits after having been irradiated up to 1 × 1013 n/cm^2 (1-MeV equivalent). A sample size of fifteen units was exposed to radiation testing per (MIL-STD-883, Method 1017 for Neutron Irradiation) and an additional unirradiated sample device was used for correlation. All devices used in the experiment were from lot date code 1808A and assembly lot 8001081MMT. Electrical testing was performed at Texas Instruments before and after neutron irradiation using the production test program for 5962R1721401VXC.

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1 Overview

The LMH5401-SP is a very high-performance, radiation hardened, differential amplifier optimized for radio frequency (RF), intermediate frequency (IF), or high-speed, dc-coupled, time-domain applications. The device is ideal for dc- or ac-coupled applications that may require a single-ended-to-differential (SEDE) conversion when driving an analog-to-digital converter (ADC). The LMH5401-SP generates very low levels of second- and third-order distortion when operating in SE-DE or differential-to-differential (DEDE) mode. General device information and testing conditions are listed in Table 1.

Table 1. Overview Information

TI Part Number	LMH5401-SP
SMD Number	5962-17214
Device Function	Low-Noise, Low-Power, Gain-Configurable Fully Differential Amplifier
Die Name	GHLMH5401AH1
Technology	CBICMOS
A/T Lot Number / Date Code	8001081MMT / 1808A
Unbiased Quantity Tested	15
Exposure Facility	VPT Rad
Neutron Fluence (1-MeV Equivalent)	1.0×10^{12}, 5.0×10^{12}, 1.0×10^{13} n/cm^2
Irradiation Temperature	25°C
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2 Test Procedures

The LMH5401-SP was electrically pre-tested using the production automated test equipment program. General test procedures were IAW MIL-STD-883, Method 1017 for Neutron Irradiation of LMH5401-SP as modified in Table 2.

Table 2. Neutron Irradiation Conditions

Group	Sample Qty	Neutron Fluence (n/cm^2)	Bias
A	5	1.0×10^{12}	Unbiased
B	5	5.0×10^{12}	Unbiased
C	5	1.0×10^{13}	Unbiased

Figure 1. LMH5401-SP Device

3 Facility

The University of Massachusetts's Fast Neutron Irradiation (FNI) facility is an experimental facility replaces three beam ports that originally existed on the left side of the research reactor. It is designed to give a fast flux level ≥ 1011 n/cm^2–s, with relatively low thermal fluence and gamma dose rates. Samples with a cross-sectional area as large as 30 cm (12 in) × 30 cm (12 in) and up to 15 cm (6 in) thick can be irradiated. The fast neutron flux is designed to be nearly uniform over the 30 cm (12 in) × 30 cm (12 in) area facing the core, and the fast fluence variation through the sample thickness is minimized via a single 180° rotation of the sample canister at the midpoint of the irradiation period. The FNI facility offers a significantly larger sample volume than previously available within the University of Massachusetts Lowell Research Reactor (UMLRR). The fluences are calculated based on 1-MeV equivalences.

Detailed information of the radiation facility is available at the following link:
www.uml.edu/docs/FNI%20Brochure_tcm18-90375.pdf

4 Results

There were no functional failures at any irradiation level. All parametric measurements remained well within data sheet (SBOS849) limits and within the production test limits, which are guard-banded from the data sheet limits for all exposure levels. The following list is an overview of the largest drifts seen post-test and on critical parameters. The full parameter list and graphs are found in Appendix A.

The largest shifts seen for various parameters are shown in the following list:

1. 2200.11__IOD_NEG_OUT_SINK_3V. Pre readings are approximately 2.019 mV, Post readings are approximately –2.071 mV. This accounts for < 6% shift of Fail Limit Range.

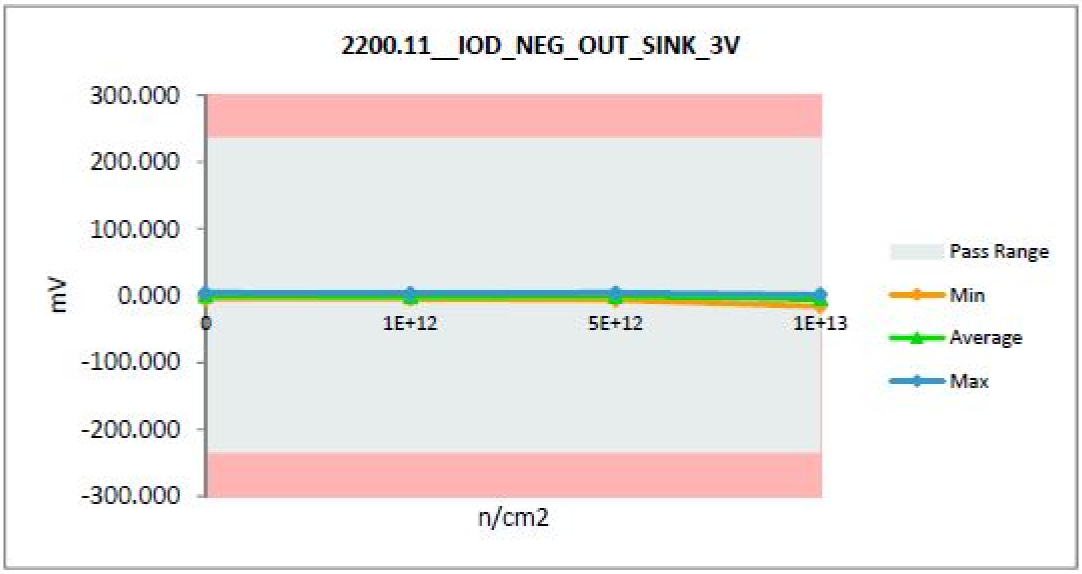

Figure 2. 2200.11__IOD_NEG_OUT_SINK_3V NDD Graph

2. 1600.7__IOD_POS_OUT_SOURCE_5V. Pre readings are approximately 22.451 mV, Post readings are approximately 12.673 mV. This accounts for < 4% shift of Fail Limit Range.

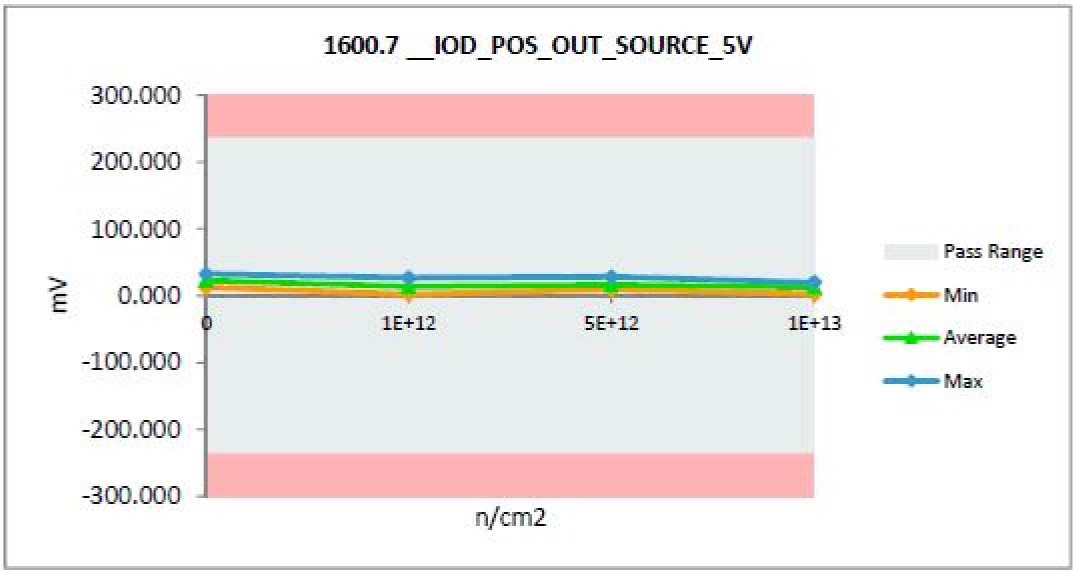

Figure 3. 600.7__IOD_POS_OUT_SOURCE_5V NDD Graph

3. 2200.5__IOD_POS_OUT_NO_LOAD_3V. Pre readings are approximately –0.086 mV, Post readings are approximately –1.386 mV. This accounts for < 3% shift of Fail Limit Range.

Figure 4. 2200.5__IOD_POS_OUT_NO_LOAD_3V NDD Graph

Critical parameters such as PSRR and IQ are well within the datasheet limit with minimal drift, < 3% which accounts for < 2% of the Fail Limit Range

The Fail Limit range is a guard-banded limit that Texas Instruments puts into test programs to insure device performance. It is always set within the data sheet limits to insure the device meets all data sheet parameters.

Table 3 lists the full LMH5401-SP specification compliance matrix.

Table 3. LMH5401-SP Specification Compliance Matrix

PARAMETER		TEST CONDITIONS	LMH5401 Data Sheet SBOS849 - December 2017				TEST #	
SYMBOL	DESCRIPTION		MIN	TYP	MAX	UNIT	VS = 5 V	VS = 3 V
Output resistance	Resistance measured at output pins		6.6		12.25	Ω	1400.1, 1400.2	2000.1, 2000.2
CMRR	Common-mode rejection ratio	Differential, 1-Vpp input shift, dc		–72		dB	1500.1	2100.1
VOUT	Output voltage	Out+, high	(VS+)–1.3	(VS+)–1.1		V	1600.3	2200.3
		Out–, high	(VS+)–1.3	(VS+)–1.1		V	1600.4	2200.4
		Out+, low	(VS–)+1.3	(VS–)+1.1		V	1600.1	2200.1
		Out–, low	(VS–)+1.3	(VS–)+1.1		V	1600.2	2200.2
IDD	Differential output current	3 V, VOUT = 0 V	30	40		mA	—	2200.5, 2200.6, 2200.7, 2200.8, 2200.9, 2200.10, 2200.11, 2200.12, 2200.13, 2200.14
		5 V, VOUT = 0 V	40	50			1600.5, 1600.6, 1600.7, 1600.8, 1600.9, 1600.10, 1600.11, 1600.12, 1600.13, 1600.14	—
PSRR	Power-supply rejection ratio	VS+		–82	–48	dB	1700.1	2300.1
		VS–		–80	–44		1700.2	2300.2
IQ	Quiescent current	3 V, PD = 0 (part enabled)	44	54	63	mA	—	2300.3, 2300.4
		3 V, PD = 1 (part disabled)	1	1.6	5		—	2300.5, 2300.6, 2500.2
		5 V, PD = 0 (part enabled)	46	60	78		1700.3, 1700.4	—
		5 V, PD = 1 (part disabled)	1	3	6		1700.5, 1700.6, 1900.2	—
VCM gain	Output common mode gain	VCM gain = 0 V	0.98	1	1.01	V/V	1800.1, 1800.2, 1800.3	2400.1, 2400.2, 2400.3
VT	Enable or disable threshold voltage		0.9	1.1	1.2	V	1900.1	2500.1
IPD	Power down bias current	PD = 2.5 V		10	±100	uA	1900.3	2500.3
IIB	Input bias current			70	150	uA	2700.1, 2700.2	2700.4, 2700.5
VIO	Input offset voltage			±0.5	±5	mV	2700.3	2700.6
IIO	Input offset current			±1	±20	uA	2700.7	2700.8

Test Results

This appendix contains the detailed test results.

Delta Threshold	10.00%

NDD Report
LMH5401-SP

NDD Report
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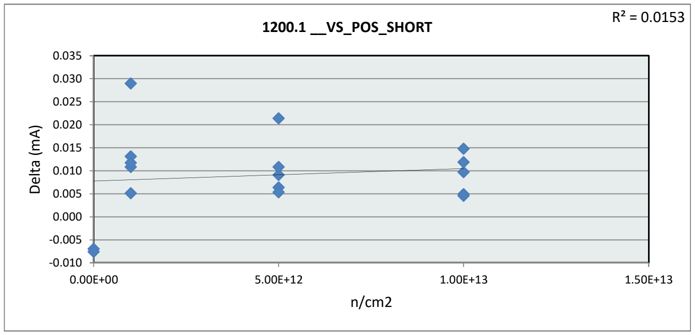
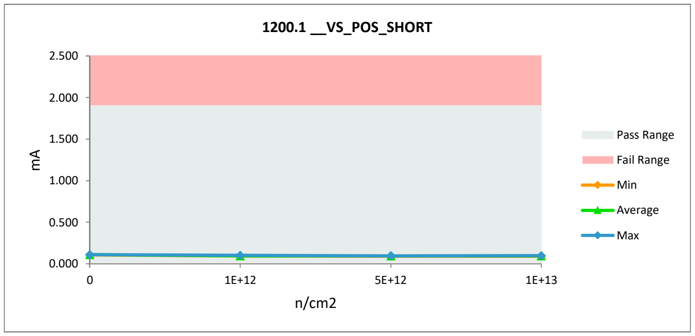
		1200.1 __VS_POS_SHORT		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	1.9	1.9	
	Min Limit	0.001	0.001	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	0.100	0.107	-0.007
0	106	0.102	0.109	-0.008
1E+12	1	0.123	0.094	0.029
1E+12	2	0.102	0.092	0.011
1E+12	3	0.105	0.091	0.013
1E+12	4	0.105	0.099	0.005
1E+12	5	0.104	0.092	0.012
5E+12	13	0.113	0.092	0.021
5E+12	14	0.101	0.092	0.009
5E+12	15	0.100	0.094	0.006
5E+12	16	0.100	0.095	0.005
5E+12	17	0.101	0.090	0.011
1E+13	6	0.101	0.096	0.005
1E+13	7	0.101	0.096	0.005
1E+13	9	0.101	0.091	0.010
1E+13	10	0.108	0.093	0.015
1E+13	12	0.102	0.091	0.012
	Max	0.123	0.109	0.029
	Average	0.104	0.095	0.009
	Min	0.100	0.090	-0.008
	Std Dev	0.006	0.006	0.009



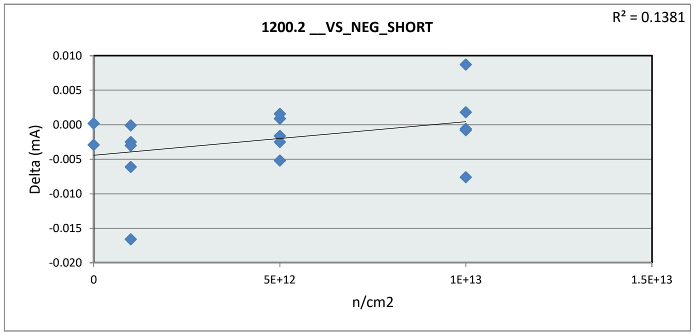
	1200.1 __VS_POS_SHORT			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.9	mA		
Min Limit	0.001	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.001	0.001	0.001	0.001
Min	0.107	0.091	0.090	0.091
Average	0.108	0.094	0.093	0.093
Max	0.109	0.099	0.095	0.096
UL	1.900	1.900	1.900	1.900



NDD Report
LMH5401-SP

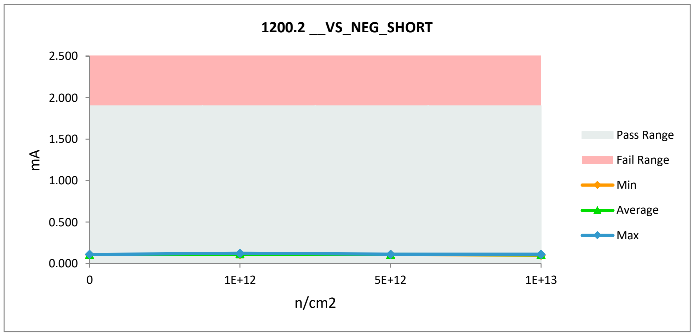
	1200.2 __VS_NEG_SHORT	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	mA	mA
Max Limit	1.9	1.9
Min Limit	0.001	0.001

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	0.109	0.112	-0.003
0	106	0.107	0.107	0.000
1E+12	1	0.107	0.109	-0.002
1E+12	2	0.108	0.125	-0.017
1E+12	3	0.108	0.108	0.000
1E+12	4	0.111	0.117	-0.006
1E+12	5	0.108	0.111	-0.003
5E+12	13	0.109	0.108	0.001
5E+12	14	0.107	0.108	-0.002
5E+12	15	0.109	0.107	0.002
5E+12	16	0.110	0.112	-0.002
5E+12	17	0.108	0.113	-0.005
1E+13	6	0.108	0.108	-0.001
1E+13	7	0.111	0.109	0.002
1E+13	9	0.108	0.108	-0.001
1E+13	10	0.105	0.113	-0.008
1E+13	12	0.110	0.101	0.009
	Max	0.111	0.125	0.009
	Average	0.108	0.110	-0.002
	Min	0.105	0.101	-0.017
	Std Dev	0.001	0.005	0.005



	1200.2 __VS_NEG_SHORT	
Test Site	1	
Tester	ETS364	
Test Number	EF868301	
Max Limit	1.9	mA
Min Limit	0.001	mA

n/cm2	0	1E+12	5E+12	1E+13
LL	0.001	0.001	0.001	0.001
Min	0.107	0.108	0.107	0.101
Average	0.109	0.114	0.110	0.108
Max	0.112	0.125	0.113	0.113
UL	1.900	1.900	1.900	1.900



NDD Report
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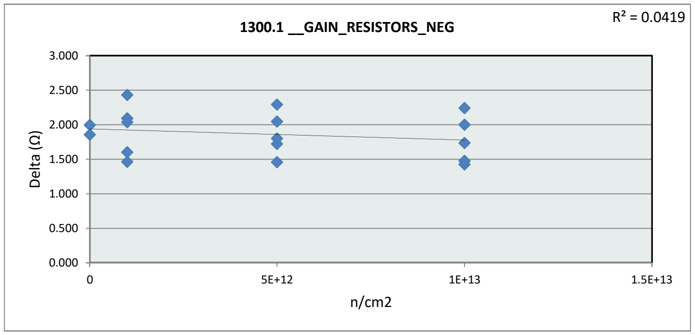
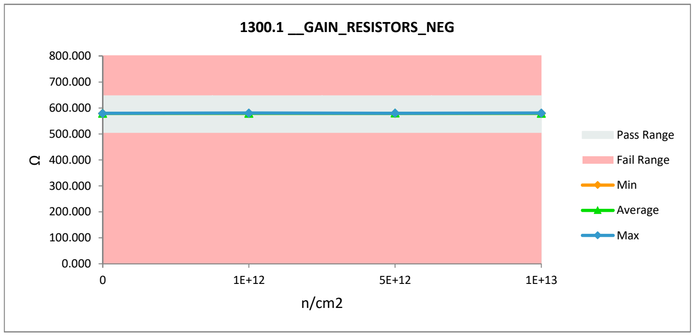
	1300.1 __GAIN_RESISTORS_NE	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	Ω	Ω
Max Limit	646.25	646.25
Min Limit	503.75	503.75

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	581.055	579.058	1.997
0	106	581.047	579.190	1.858
1E+12	1	580.814	579.351	1.463
1E+12	2	581.608	579.514	2.094
1E+12	3	581.071	579.467	1.604
1E+12	4	581.382	578.949	2.433
1E+12	5	581.281	579.243	2.038
5E+12	13	581.359	579.313	2.046
5E+12	14	581.312	579.019	2.293
5E+12	15	581.265	579.545	1.721
5E+12	16	581.079	579.622	1.457
5E+12	17	581.499	579.700	1.799
1E+13	6	581.195	579.197	1.999
1E+13	7	581.063	579.637	1.426
1E+13	9	580.620	579.142	1.478
1E+13	10	581.047	579.312	1.735
1E+13	12	581.437	579.197	2.240
	Max	581.608	579.700	2.433
	Average	581.184	579.321	1.863
	Min	580.620	578.949	1.426
	Std Dev	0.249	0.228	0.314



	1300.1 __GAIN_RESISTORS_N	
Test Site	1	
Tester	ETS364	
Test Number	EF868301	
Max Limit	646.25	Ω
Min Limit	503.75	Ω

n/cm2	0	1E+12	5E+12	1E+13
LL	503.750	503.750	503.750	503.750
Min	579.058	578.949	579.019	579.142
Average	579.124	579.305	579.440	579.297
Max	579.190	579.514	579.700	579.637
UL	646.250	646.250	646.250	646.250



NDD Report
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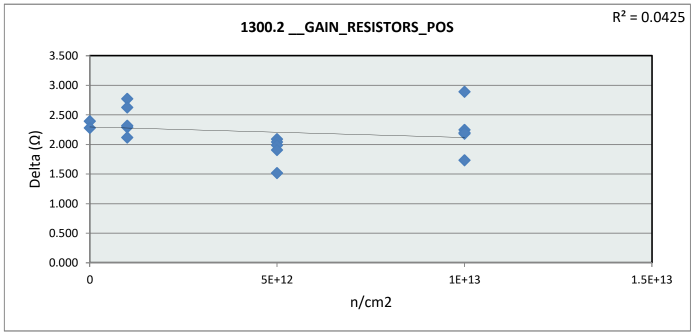
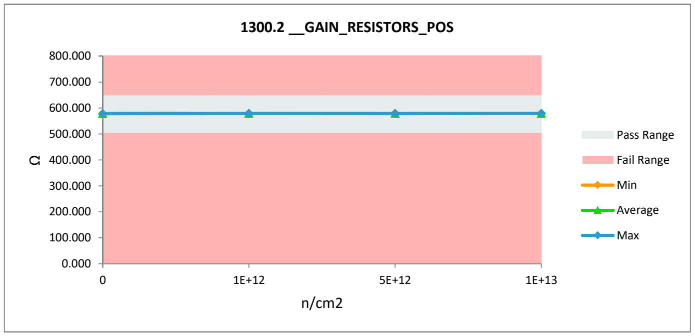
		1300.2 __GAIN_RESISTORS_POS		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	Ω	Ω	
	Max Limit	646.25	646.25	
	Min Limit	503.75	503.75	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	580.492	578.100	2.391
0	106	580.197	577.916	2.281
1E+12	1	580.802	578.034	2.769
1E+12	2	581.323	578.696	2.628
1E+12	3	580.507	578.388	2.119
1E+12	4	580.585	578.295	2.289
1E+12	5	580.810	578.495	2.315
5E+12	13	580.903	578.812	2.091
5E+12	14	580.500	578.457	2.042
5E+12	15	581.036	579.051	1.985
5E+12	16	580.531	578.626	1.904
5E+12	17	580.445	578.927	1.518
1E+13	6	580.950	578.704	2.246
1E+13	7	580.670	578.488	2.182
1E+13	9	580.601	578.403	2.197
1E+13	10	580.430	578.696	1.733
1E+13	12	581.502	578.611	2.891
	Max	581.502	579.051	2.891
	Average	580.723	578.512	2.211
	Min	580.197	577.916	1.518
	Std Dev	0.338	0.307	0.345



	1300.2 __GAIN_RESISTORS_P			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	646.25	Ω		
Min Limit	503.75	Ω		
n/cm2	0	1E+12	5E+12	1E+13
LL	503.750	503.750	503.750	503.750
Min	577.916	578.034	578.457	578.403
Average	578.008	578.382	578.775	578.581
Max	578.100	578.696	579.051	578.704
UL	646.250	646.250	646.250	646.250



NDD Report
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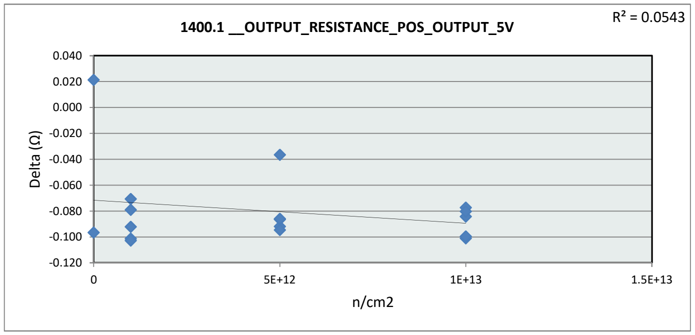
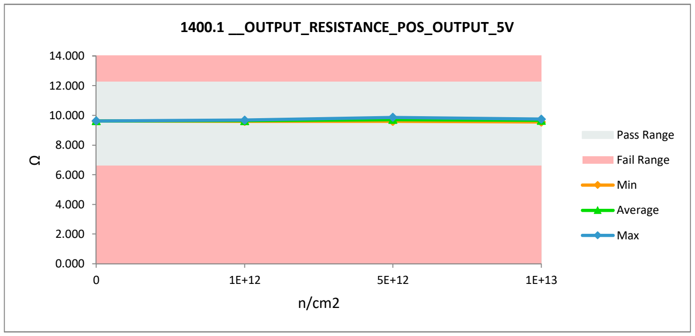
		1400.1 __OUTPUT_RESISTANCE_		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	Ω	Ω	
	Max Limit	12.25	12.25	
	Min Limit	6.6	6.6	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	9.519	9.616	-0.097
0	106	9.653	9.631	0.021
1E+12	1	9.551	9.622	-0.071
1E+12	2	9.565	9.666	-0.101
1E+12	3	9.551	9.653	-0.103
1E+12	4	9.512	9.592	-0.079
1E+12	5	9.582	9.674	-0.092
5E+12	13	9.557	9.593	-0.036
5E+12	14	9.527	9.619	-0.092
5E+12	15	9.782	9.869	-0.087
5E+12	16	9.632	9.726	-0.095
5E+12	17	9.650	9.736	-0.086
1E+13	6	9.470	9.555	-0.084
1E+13	7	9.551	9.652	-0.101
1E+13	9	9.584	9.662	-0.077
1E+13	10	9.575	9.656	-0.080
1E+13	12	9.640	9.740	-0.100
	Max	9.782	9.869	0.021
	Average	9.582	9.662	-0.080
	Min	9.470	9.555	-0.103
	Std Dev	0.072	0.074	0.031

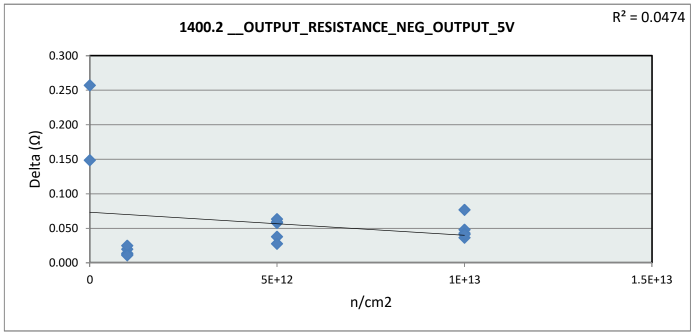


	1400.1 __OUTPUT_RESISTANC			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	12.25	Ω		
Min Limit	6.6	Ω		
n/cm2	0	1E+12	5E+12	1E+13
LL	6.600	6.600	6.600	6.600
Min	9.616	9.592	9.593	9.555
Average	9.623	9.641	9.709	9.653
Max	9.631	9.674	9.869	9.740
UL	12.250	12.250	12.250	12.250

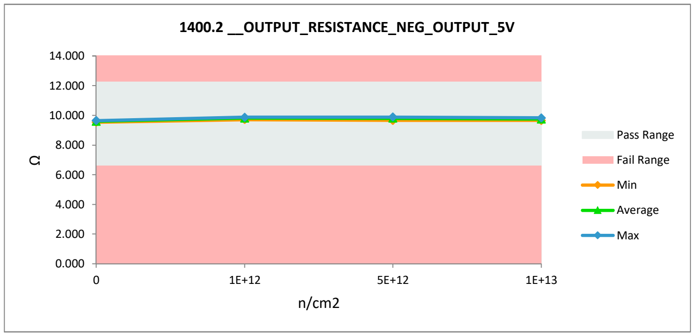


NDD Report
LMH5401-SP

		1400.2 __OUTPUT_RESISTANCE_		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	Ω	Ω	
	Max Limit	12.25	12.25	
	Min Limit	6.6	6.6	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	9.801	9.544	0.257
0	106	9.794	9.646	0.149
1E+12	1	9.815	9.795	0.020
1E+12	2	9.856	9.844	0.012
1E+12	3	9.726	9.712	0.013
1E+12	4	9.782	9.757	0.025
1E+12	5	9.880	9.869	0.011
5E+12	13	9.782	9.744	0.038
5E+12	14	9.721	9.663	0.058
5E+12	15	9.917	9.858	0.059
5E+12	16	9.889	9.825	0.063
5E+12	17	9.919	9.891	0.028
1E+13	6	9.708	9.661	0.048
1E+13	7	9.799	9.763	0.036
1E+13	9	9.779	9.736	0.043
1E+13	10	9.781	9.704	0.076
1E+13	12	9.866	9.825	0.041
	Max	9.919	9.891	0.257
	Average	9.813	9.755	0.057
	Min	9.708	9.544	0.011
	Std Dev	0.066	0.094	0.061



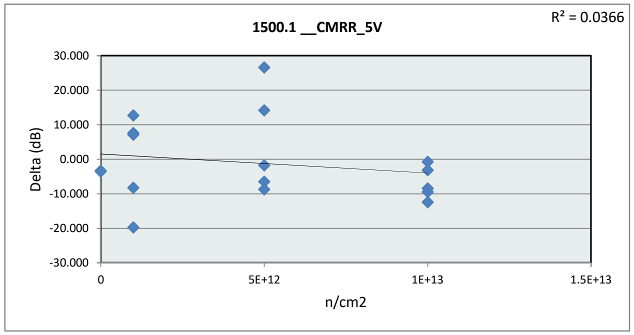
	1400.2 __OUTPUT_RESISTANC			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	12.25	Ω		
Min Limit	6.6	Ω		
n/cm2	0	1E+12	5E+12	1E+13
LL	6.600	6.600	6.600	6.600
Min	9.544	9.712	9.663	9.661
Average	9.595	9.795	9.796	9.738
Max	9.646	9.869	9.891	9.825
UL	12.250	12.250	12.250	12.250



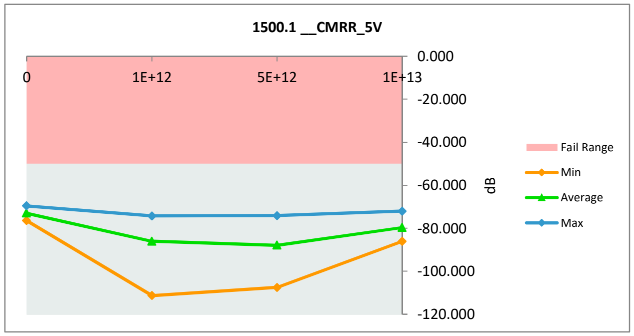
NDD Report
LMH5401-SP

	1500.1 __CMRR_5V	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	dB	dB
Max Limit	-50	-50
Min Limit		

n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	-79.860	-76.473	-3.388
0	106	-73.127	-69.612	-3.515
1E+12	1	-82.543	-74.298	-8.245
1E+12	2	-75.885	-83.489	7.604
1E+12	3	-96.204	-76.467	-19.737
1E+12	4	-98.701	-111.355	12.654
1E+12	5	-78.217	-85.301	7.084
5E+12	13	-75.956	-74.226	-1.730
5E+12	14	-88.098	-81.557	-6.540
5E+12	15	-90.702	-81.938	-8.764
5E+12	16	-81.062	-107.629	26.566
5E+12	17	-80.388	-94.553	14.165
1E+13	6	-72.940	-72.154	-0.786
1E+13	7	-89.266	-79.844	-9.422
1E+13	9	-87.140	-78.718	-8.422
1E+13	10	-94.379	-81.984	-12.394
1E+13	12	-89.312	-86.161	-3.150
	Max	-72.940	-69.612	26.566
	Average	-84.340	-83.280	-1.060
	Min	-98.701	-111.355	-19.737
	Std Dev	8.077	11.526	11.411

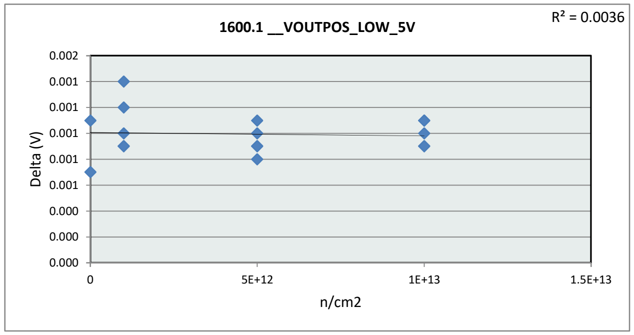


	1500.1 __CMRR_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-50	dB		
Min Limit		dB		
n/cm2	0	1E+12	5E+12	1E+13
LL				
Min	-76.473	-111.355	-107.629	-86.161
Average	-73.042	-86.182	-87.980	-79.772
Max	-69.612	-74.298	-74.226	-72.154
UL	-50.000	-50.000	-50.000	-50.000

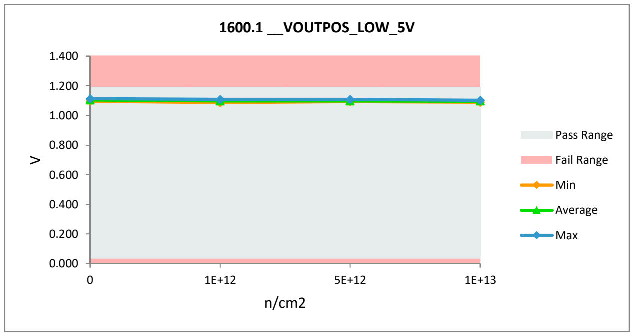


NDD Report
LMH5401-SP

		1600.1 __VOUTPOS_LOW_5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	V	V	
	Max Limit	1.19	1.19	
	Min Limit	0.033	0.033	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.097	1.096	0.001
0	106	1.114	1.113	0.001
1E+12	1	1.109	1.108	0.001
1E+12	2	1.089	1.087	0.001
1E+12	3	1.102	1.102	0.001
1E+12	4	1.094	1.092	0.001
1E+12	5	1.093	1.092	0.001
5E+12	13	1.110	1.109	0.001
5E+12	14	1.097	1.096	0.001
5E+12	15	1.097	1.096	0.001
5E+12	16	1.096	1.095	0.001
5E+12	17	1.095	1.094	0.001
1E+13	6	1.095	1.094	0.001
1E+13	7	1.097	1.096	0.001
1E+13	9	1.103	1.102	0.001
1E+13	10	1.089	1.088	0.001
1E+13	12	1.102	1.101	0.001
	Max	1.114	1.113	0.001
	Average	1.099	1.098	0.001
	Min	1.089	1.087	0.001
	Std Dev	0.007	0.007	0.000



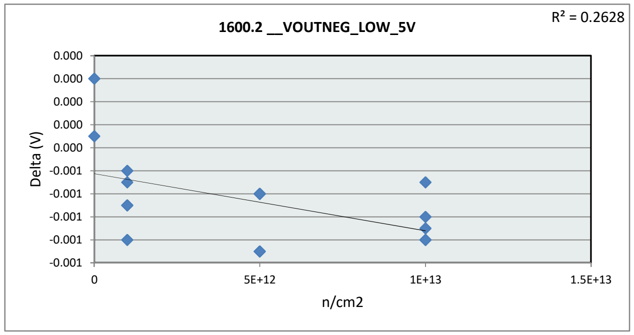
	1600.1 __VOUTPOS_LOW_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.19	V		
Min Limit	0.033	V		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.033	0.033	0.033	0.033
Min	1.096	1.087	1.094	1.088
Average	1.105	1.096	1.098	1.096
Max	1.113	1.108	1.109	1.102
UL	1.190	1.190	1.190	1.190



NDD Report
LMH5401-SP

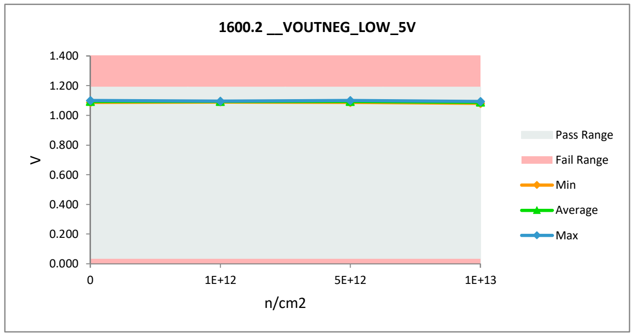
	1600.2 __VOUTNEG_LOW_5V	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	V	V
Max Limit	1.19	1.19
Min Limit	0.033	0.033

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.086	1.087	0.000
0	106	1.099	1.099	0.000
1E+12	1	1.092	1.092	-0.001
1E+12	2	1.089	1.090	-0.001
1E+12	3	1.093	1.094	-0.001
1E+12	4	1.090	1.091	-0.001
1E+12	5	1.091	1.092	-0.001
5E+12	13	1.094	1.095	-0.001
5E+12	14	1.085	1.086	-0.001
5E+12	15	1.099	1.100	-0.001
5E+12	16	1.092	1.092	-0.001
5E+12	17	1.093	1.094	-0.001
1E+13	6	1.088	1.089	-0.001
1E+13	7	1.087	1.088	-0.001
1E+13	9	1.092	1.093	-0.001
1E+13	10	1.080	1.081	-0.001
1E+13	12	1.089	1.090	-0.001
	Max	1.099	1.100	0.000
	Average	1.091	1.091	-0.001
	Min	1.080	1.081	-0.001
	Std Dev	0.005	0.005	0.000



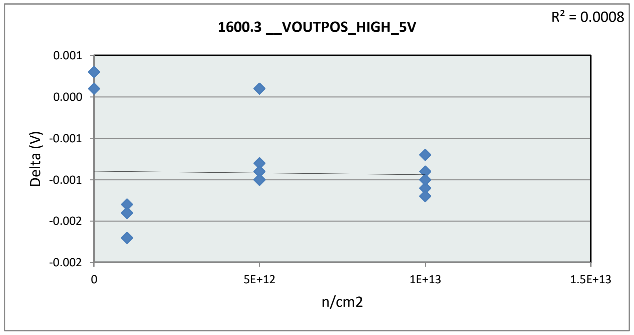
	1600.2 __VOUTNEG_LOW_5V	
Test Site	1	
Tester	ETS364	
Test Number	EF868301	
Max Limit	1.19	V
Min Limit	0.033	V

n/cm2	0	1E+12	5E+12	1E+13
LL	0.033	0.033	0.033	0.033
Min	1.087	1.090	1.086	1.081
Average	1.093	1.092	1.094	1.088
Max	1.099	1.095	1.100	1.093
UL	1.190	1.190	1.190	1.190

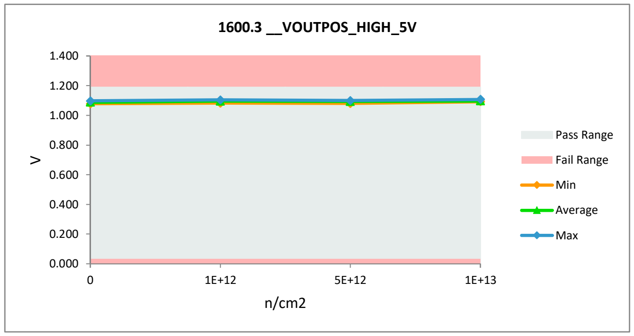


NDD Report
LMH5401-SP

		1600.3 __VOUTPOS_HIGH_5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	V	V	
	Max Limit	1.19	1.19	
	Min Limit	0.033	0.033	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.097	1.097	0.000
0	106	1.078	1.078	0.000
1E+12	1	1.081	1.082	-0.001
1E+12	2	1.103	1.105	-0.002
1E+12	3	1.089	1.091	-0.002
1E+12	4	1.097	1.098	-0.001
1E+12	5	1.100	1.101	-0.001
5E+12	13	1.081	1.081	0.000
5E+12	14	1.094	1.095	-0.001
5E+12	15	1.095	1.096	-0.001
5E+12	16	1.097	1.098	-0.001
5E+12	17	1.099	1.100	-0.001
1E+13	6	1.094	1.095	-0.001
1E+13	7	1.096	1.097	-0.001
1E+13	9	1.091	1.092	-0.001
1E+13	10	1.107	1.108	-0.001
1E+13	12	1.093	1.094	-0.001
	Max	1.107	1.108	0.000
	Average	1.094	1.095	-0.001
	Min	1.078	1.078	-0.002
	Std Dev	0.008	0.008	0.001



	1600.3 __VOUTPOS_HIGH_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.19	V		
Min Limit	0.033	V		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.033	0.033	0.033	0.033
Min	1.078	1.082	1.081	1.092
Average	1.088	1.096	1.094	1.097
Max	1.097	1.105	1.100	1.108
UL	1.190	1.190	1.190	1.190



NDD Report
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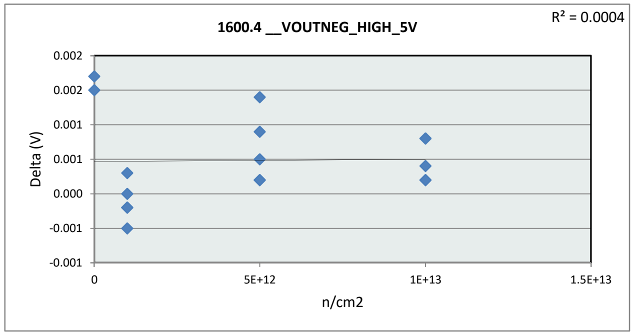
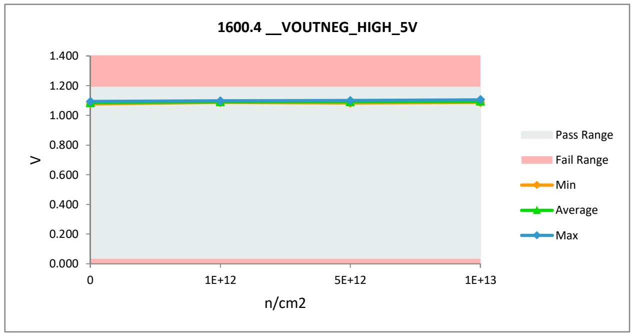
		1600.4 __VOUTNEG_HIGH_5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	V	V	
	Max Limit	1.19	1.19	
	Min Limit	0.033	0.033	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.095	1.093	0.002
0	106	1.079	1.077	0.002
1E+12	1	1.087	1.087	0.000
1E+12	2	1.098	1.098	0.000
1E+12	3	1.085	1.086	0.000
1E+12	4	1.092	1.092	0.000
1E+12	5	1.092	1.092	-0.001
5E+12	13	1.084	1.083	0.001
5E+12	14	1.099	1.099	0.000
5E+12	15	1.089	1.088	0.001
5E+12	16	1.093	1.093	0.000
5E+12	17	1.092	1.092	0.000
1E+13	6	1.092	1.092	0.001
1E+13	7	1.096	1.096	0.000
1E+13	9	1.087	1.087	0.001
1E+13	10	1.105	1.105	0.000
1E+13	12	1.093	1.092	0.000
	Max	1.105	1.105	0.002
	Average	1.092	1.091	0.000
	Min	1.079	1.077	-0.001
	Std Dev	0.006	0.007	0.001

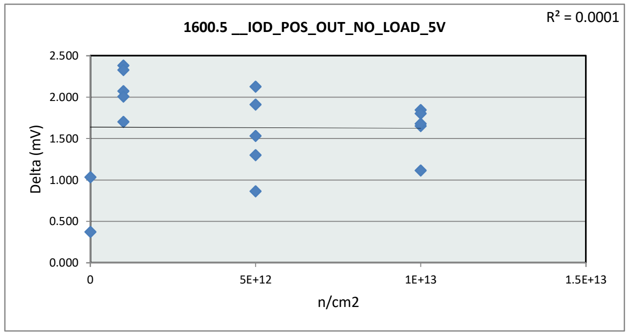


	1600.4 __VOUTNEG_HIGH_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.19	V		
Min Limit	0.033	V		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.033	0.033	0.033	0.033
Min	1.077	1.086	1.083	1.087
Average	1.085	1.091	1.091	1.094
Max	1.093	1.098	1.099	1.105
UL	1.190	1.190	1.190	1.190

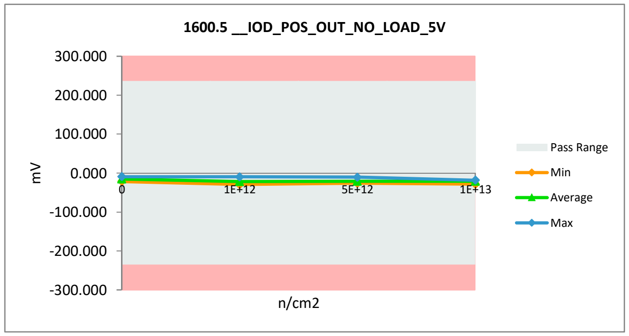


NDD Report
LMH5401-SP

		1600.5 __IOD_POS_OUT_NO_LO		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	235	235	
	Min Limit	-235	-235	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-21.267	-21.638	0.371
0	106	-8.184	-9.217	1.033
1E+12	1	-7.738	-9.812	2.074
1E+12	2	-27.234	-29.242	2.008
1E+12	3	-16.772	-19.152	2.380
1E+12	4	-23.063	-24.763	1.700
1E+12	5	-24.952	-27.279	2.327
5E+12	13	-9.682	-10.546	0.864
5E+12	14	-19.675	-21.208	1.533
5E+12	15	-23.104	-24.403	1.299
5E+12	16	-22.815	-24.724	1.910
5E+12	17	-24.071	-26.198	2.128
1E+13	6	-18.916	-20.569	1.653
1E+13	7	-20.968	-22.084	1.115
1E+13	9	-16.708	-18.551	1.843
1E+13	10	-26.642	-28.446	1.804
1E+13	12	-16.583	-18.262	1.679
	Max	-7.738	-9.217	2.380
	Average	-19.316	-20.947	1.631
	Min	-27.234	-29.242	0.371
	Std Dev	6.071	6.232	0.543



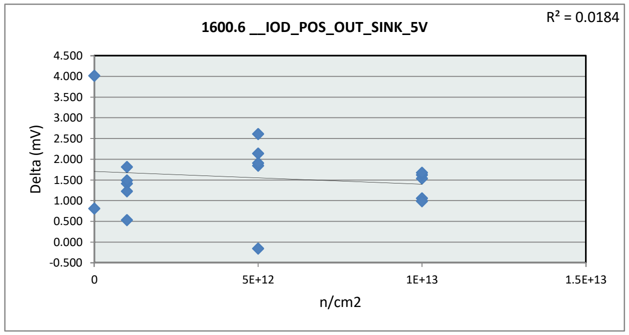
	1600.5 __IOD_POS_OUT_NO_			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	-21.638	-29.242	-26.199	-28.446
Average	-15.427	-22.050	-21.416	-21.582
Max	-9.217	-9.812	-10.546	-18.262
UL	235.000	235.000	235.000	235.000



NDD Report
LMH5401-SP

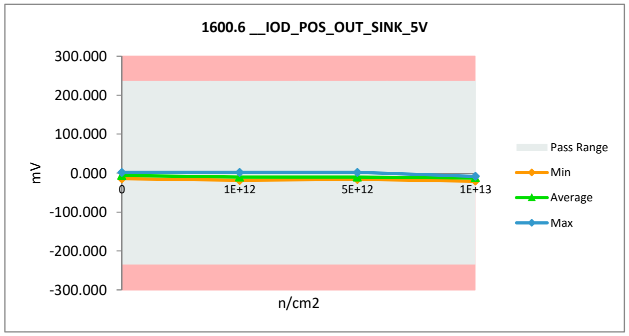
	1600.6 __IOD_POS_OUT_SINK_	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	mV	mV
Max Limit	235	235
Min Limit	-235	-235

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-10.510	-14.522	4.013
0	106	2.728	1.921	0.807
1E+12	1	2.382	1.850	0.532
1E+12	2	-16.829	-18.643	1.814
1E+12	3	-7.123	-8.531	1.409
1E+12	4	-12.547	-13.772	1.226
1E+12	5	-13.542	-15.028	1.486
5E+12	13	1.517	1.676	-0.160
5E+12	14	-9.949	-11.795	1.846
5E+12	15	-14.226	-16.837	2.611
5E+12	16	-10.826	-12.968	2.142
5E+12	17	-12.787	-14.694	1.906
1E+13	6	-10.304	-11.841	1.537
1E+13	7	-10.510	-12.128	1.618
1E+13	9	-7.258	-8.317	1.059
1E+13	10	-19.933	-20.918	0.985
1E+13	12	-7.080	-8.753	1.673
	Max	2.728	1.921	4.013
	Average	-9.223	-10.782	1.559
	Min	-19.933	-20.918	-0.160
	Std Dev	6.390	6.881	0.903



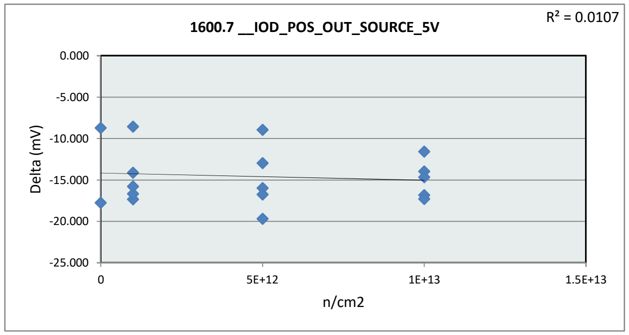
	1600.6 __IOD_POS_OUT_SINK	
Test Site	1	
Tester	ETS364	
Test Number	EF868301	
Max Limit	235	mV
Min Limit	-235	mV

n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	-14.522	-18.643	-16.837	-20.918
Average	-6.300	-10.825	-10.924	-12.392
Max	1.922	1.850	1.676	-8.317
UL	235.000	235.000	235.000	235.000

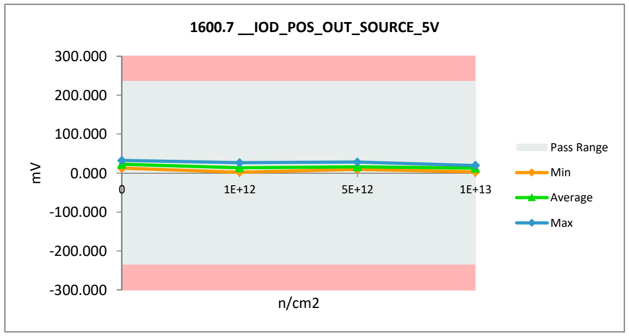


NDD Report
LMH5401-SP

		1600.7 __IOD_POS_OUT_SOURC		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	235	235	
	Min Limit	-235	-235	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-5.206	12.542	-17.748
0	106	23.636	32.360	-8.724
1E+12	1	17.469	26.051	-8.582
1E+12	2	-15.106	2.226	-17.332
1E+12	3	5.981	20.093	-14.112
1E+12	4	-7.616	9.074	-16.690
1E+12	5	-9.047	6.736	-15.783
5E+12	13	18.899	27.841	-8.942
5E+12	14	-5.063	14.620	-19.683
5E+12	15	3.487	16.441	-12.955
5E+12	16	-4.912	11.087	-15.999
5E+12	17	-7.725	9.029	-16.754
1E+13	6	-0.606	10.967	-11.573
1E+13	7	-2.096	11.868	-13.964
1E+13	9	4.670	19.353	-14.683
1E+13	10	-13.962	2.872	-16.835
1E+13	12	0.992	18.304	-17.311
	Max	23.636	32.360	-8.582
	Average	0.223	14.792	-14.569
	Min	-15.106	2.226	-19.683
	Std Dev	11.167	8.450	3.384



	1600.7 __IOD_POS_OUT_SOU			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	12.542	2.226	9.029	2.872
Average	22.451	12.836	15.804	12.673
Max	32.360	26.051	27.841	19.353
UL	235.000	235.000	235.000	235.000



NDD Report
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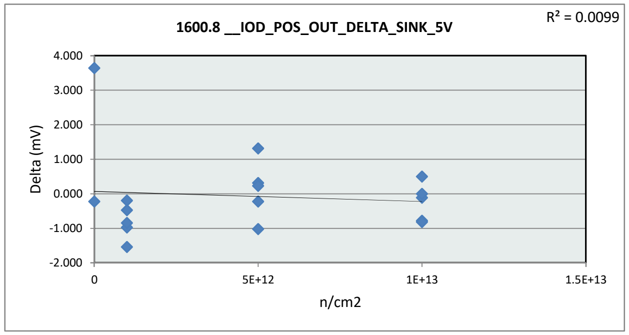
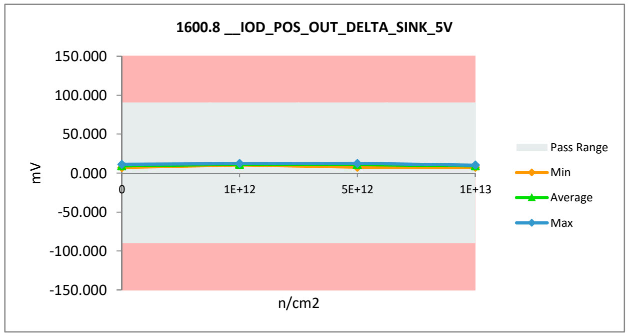
		1600.8 __IOD_POS_OUT_DELTA		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	90	90	
	Min Limit	-90	-90	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	10.757	7.115	3.642
0	106	10.912	11.138	-0.226
1E+12	1	10.121	11.662	-1.542
1E+12	2	10.405	10.599	-0.194
1E+12	3	9.650	10.621	-0.971
1E+12	4	10.517	10.991	-0.474
1E+12	5	11.410	12.251	-0.841
5E+12	13	11.198	12.222	-1.024
5E+12	14	9.726	9.412	0.314
5E+12	15	8.877	7.565	1.312
5E+12	16	11.988	11.756	0.232
5E+12	17	11.283	11.505	-0.221
1E+13	6	8.611	8.728	-0.116
1E+13	7	10.458	9.955	0.502
1E+13	9	9.450	10.234	-0.784
1E+13	10	6.709	7.528	-0.819
1E+13	12	9.503	9.509	-0.005
	Max	11.988	12.251	3.642
	Average	10.093	10.164	-0.072
	Min	6.709	7.115	-1.542
	Std Dev	1.267	1.645	1.174



	1600.8 __IOD_POS_OUT_DELT			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	90	mV		
Min Limit	-90	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-90.000	-90.000	-90.000	-90.000
Min	7.115	10.599	7.565	7.528
Average	9.127	11.225	10.492	9.191
Max	11.138	12.251	12.222	10.234
UL	90.000	90.000	90.000	90.000



NDD Report
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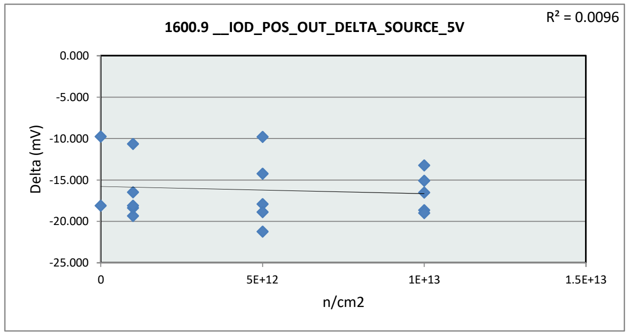
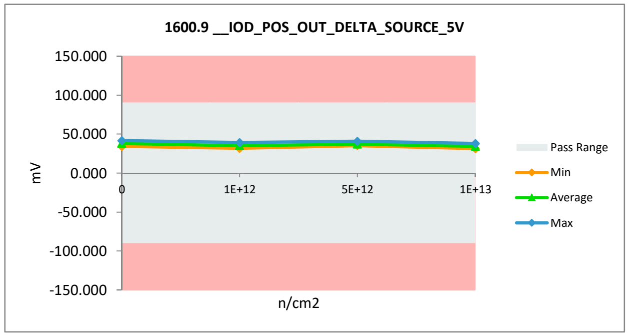
		1600.9 __IOD_POS_OUT_DELTA		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	90	90	
	Min Limit	-90	-90	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	16.061	34.180	-18.119
0	106	31.820	41.576	-9.757
1E+12	1	25.208	35.863	-10.655
1E+12	2	12.128	31.468	-19.340
1E+12	3	22.753	39.245	-16.492
1E+12	4	15.447	33.838	-18.391
1E+12	5	15.905	34.015	-18.111
5E+12	13	28.581	38.388	-9.807
5E+12	14	14.612	35.827	-21.215
5E+12	15	26.590	40.844	-14.254
5E+12	16	17.903	35.812	-17.909
5E+12	17	16.346	35.227	-18.882
1E+13	6	18.310	31.536	-13.226
1E+13	7	18.872	33.952	-15.079
1E+13	9	21.378	37.904	-16.526
1E+13	10	12.679	31.318	-18.639
1E+13	12	17.576	36.566	-18.990
	Max	31.820	41.576	-9.757
	Average	19.539	35.739	-16.199
	Min	12.128	31.318	-21.215
	Std Dev	5.674	3.090	3.520



	1600.9 __IOD_POS_OUT_DELT			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	90	mV		
Min Limit	-90	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-90.000	-90.000	-90.000	-90.000
Min	34.180	31.468	35.227	31.318
Average	37.878	34.886	37.220	34.255
Max	41.576	39.245	40.844	37.904
UL	90.000	90.000	90.000	90.000



NDD Report
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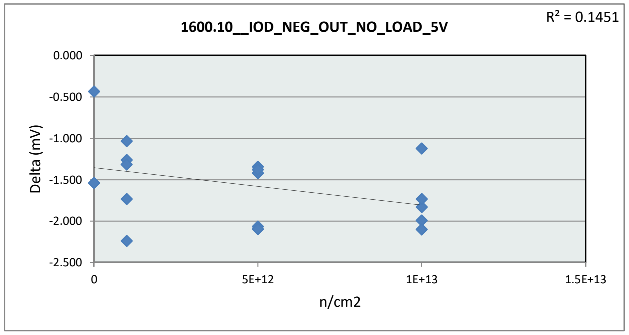
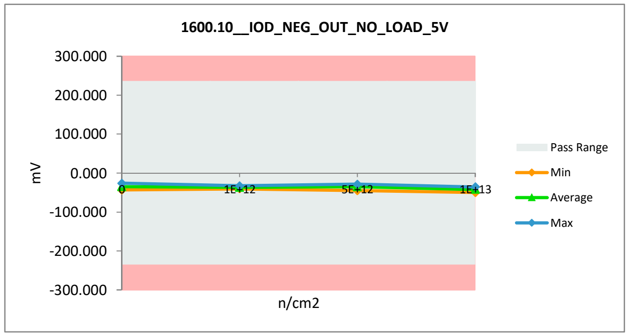
		1600.10__IOD_NEG_OUT_NO_L		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	235	235	
	Min Limit	-235	-235	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-44.324	-43.888	-0.437
0	106	-27.604	-26.063	-1.541
1E+12	1	-38.081	-36.349	-1.733
1E+12	2	-41.725	-40.463	-1.262
1E+12	3	-35.340	-33.101	-2.239
1E+12	4	-39.843	-38.528	-1.314
1E+12	5	-37.623	-36.588	-1.036
5E+12	13	-34.607	-32.540	-2.067
5E+12	14	-46.875	-45.453	-1.421
5E+12	15	-30.826	-28.730	-2.096
5E+12	16	-37.658	-36.314	-1.344
5E+12	17	-35.829	-34.450	-1.379
1E+13	6	-43.289	-41.458	-1.831
1E+13	7	-44.818	-43.695	-1.122
1E+13	9	-37.716	-35.724	-1.992
1E+13	10	-52.043	-49.944	-2.099
1E+13	12	-40.991	-39.259	-1.732
	Max	-27.604	-26.063	-0.437
	Average	-39.364	-37.797	-1.567
	Min	-52.043	-49.944	-2.239
	Std Dev	5.959	6.083	0.474



	1600.10__IOD_NEG_OUT_NO			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	-43.888	-40.463	-45.453	-49.944
Average	-34.975	-37.006	-35.498	-42.016
Max	-26.063	-33.101	-28.730	-35.724
UL	235.000	235.000	235.000	235.000



NDD Report
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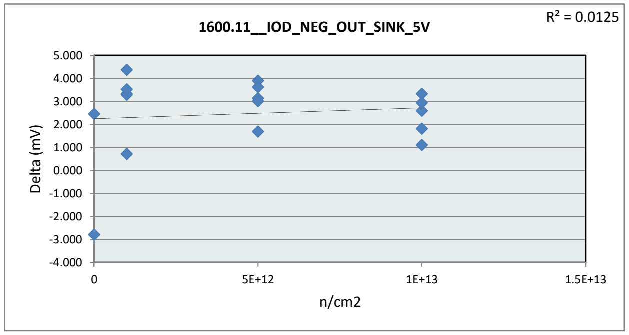
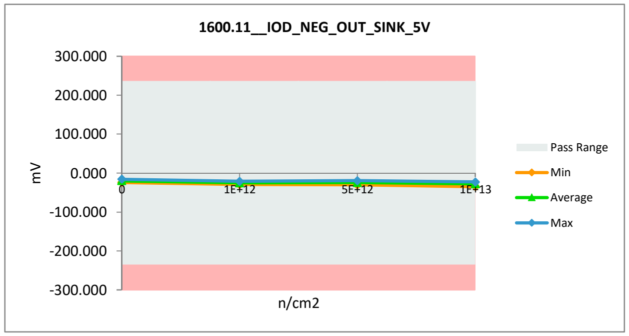
		1600.11__IOD_NEG_OUT_SINK_		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	235	235	
	Min Limit	-235	-235	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-27.028	-24.239	-2.789
0	106	-13.254	-15.711	2.457
1E+12	1	-23.417	-27.792	4.375
1E+12	2	-25.861	-29.202	3.342
1E+12	3	-18.159	-21.454	3.295
1E+12	4	-23.469	-24.191	0.723
1E+12	5	-23.000	-26.530	3.531
5E+12	13	-19.414	-23.317	3.903
5E+12	14	-28.540	-30.231	1.691
5E+12	15	-16.299	-19.440	3.141
5E+12	16	-23.243	-26.258	3.014
5E+12	17	-21.667	-25.298	3.631
1E+13	6	-23.492	-26.823	3.331
1E+13	7	-26.558	-29.502	2.944
1E+13	9	-20.301	-22.902	2.601
1E+13	10	-32.806	-34.619	1.813
1E+13	12	-24.391	-25.495	1.104
	Max	-13.254	-15.711	4.375
	Average	-22.994	-25.471	2.477
	Min	-32.806	-34.619	-2.789
	Std Dev	4.689	4.385	1.676



	1600.11__IOD_NEG_OUT_SIN			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	-24.239	-29.202	-30.231	-34.619
Average	-19.975	-25.834	-24.909	-27.868
Max	-15.711	-21.454	-19.440	-22.902
UL	235.000	235.000	235.000	235.000



NDD Report
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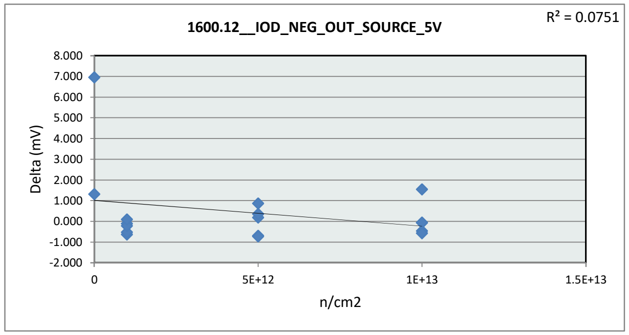
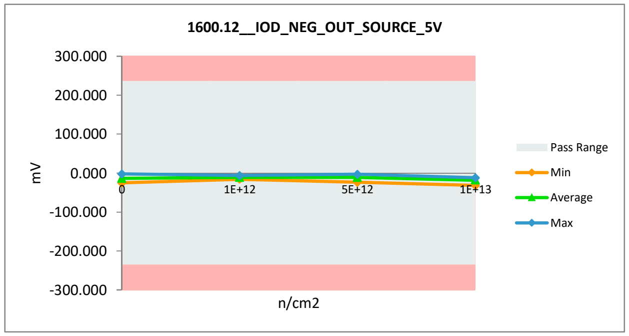
		1600.12__IOD_NEG_OUT_SOUR		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	235	235	
	Min Limit	-235	-235	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-18.255	-25.214	6.959
0	106	-1.027	-2.339	1.312
1E+12	1	-6.599	-6.486	-0.113
1E+12	2	-16.658	-16.021	-0.636
1E+12	3	-11.009	-10.480	-0.529
1E+12	4	-13.659	-13.442	-0.217
1E+12	5	-11.406	-11.497	0.091
5E+12	13	-4.312	-3.620	-0.692
5E+12	14	-24.045	-24.233	0.188
5E+12	15	-5.873	-5.148	-0.725
5E+12	16	-13.702	-14.569	0.867
5E+12	17	-9.727	-10.081	0.354
1E+13	6	-14.625	-14.155	-0.470
1E+13	7	-19.242	-19.179	-0.063
1E+13	9	-12.525	-11.954	-0.572
1E+13	10	-30.116	-31.666	1.550
1E+13	12	-14.482	-14.425	-0.057
	Max	-1.027	-2.339	6.959
	Average	-13.368	-13.795	0.426
	Min	-30.116	-31.666	-0.725
	Std Dev	7.187	7.867	1.815



	1600.12__IOD_NEG_OUT_SOU			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	-25.214	-16.021	-24.233	-31.666
Average	-13.777	-11.585	-11.530	-18.276
Max	-2.339	-6.486	-3.620	-11.954
UL	235.000	235.000	235.000	235.000



NDD Report
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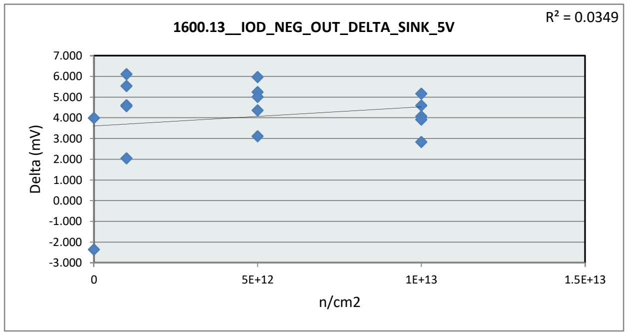
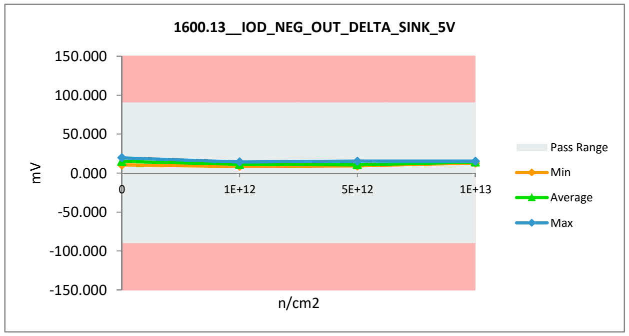
		1600.13__IOD_NEG_OUT_DELTA		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	90	90	
	Min Limit	-90	-90	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	17.296	19.649	-2.352
0	106	14.349	10.351	3.998
1E+12	1	14.663	8.557	6.107
1E+12	2	15.865	11.261	4.604
1E+12	3	17.181	11.647	5.534
1E+12	4	16.374	14.337	2.037
1E+12	5	14.624	10.057	4.566
5E+12	13	15.193	9.223	5.970
5E+12	14	18.335	15.222	3.112
5E+12	15	14.527	9.290	5.236
5E+12	16	14.414	10.056	4.358
5E+12	17	14.162	9.152	5.010
1E+13	6	19.796	14.634	5.162
1E+13	7	18.260	14.193	4.067
1E+13	9	17.414	12.822	4.593
1E+13	10	19.237	15.325	3.912
1E+13	12	16.600	13.764	2.836
	Max	19.796	19.649	6.107
	Average	16.370	12.326	4.044
	Min	14.162	8.557	-2.352
	Std Dev	1.834	3.012	1.970



	1600.13__IOD_NEG_OUT_DEL			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	90	mV		
Min Limit	-90	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-90.000	-90.000	-90.000	-90.000
Min	10.351	8.557	9.152	12.822
Average	15.000	11.172	10.589	14.148
Max	19.649	14.337	15.222	15.326
UL	90.000	90.000	90.000	90.000



NDD Report
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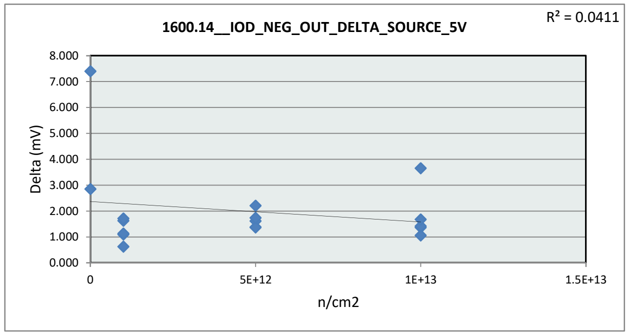
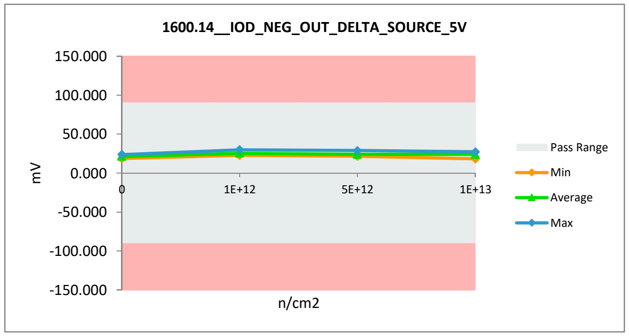
		1600.14__IOD_NEG_OUT_DELTA		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	90	90	
	Min Limit	-90	-90	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	26.069	18.673	7.396
0	106	26.576	23.723	2.853
1E+12	1	31.482	29.863	1.620
1E+12	2	25.067	24.442	0.626
1E+12	3	24.330	22.620	1.710
1E+12	4	26.184	25.086	1.098
1E+12	5	26.218	25.091	1.127
5E+12	13	30.295	28.920	1.375
5E+12	14	22.830	21.220	1.610
5E+12	15	24.953	23.583	1.370
5E+12	16	23.956	21.746	2.210
5E+12	17	26.102	24.369	1.733
1E+13	6	28.664	27.303	1.361
1E+13	7	25.576	24.516	1.059
1E+13	9	25.190	23.770	1.420
1E+13	10	21.927	18.278	3.649
1E+13	12	26.509	24.835	1.674
	Max	31.482	29.863	7.396
	Average	25.996	24.002	1.994
	Min	21.927	18.278	0.626
	Std Dev	2.407	3.055	1.562



	1600.14__IOD_NEG_OUT_DEL			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	90	mV		
Min Limit	-90	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-90.000	-90.000	-90.000	-90.000
Min	18.673	22.620	21.220	18.278
Average	21.198	25.420	23.968	23.740
Max	23.723	29.863	28.920	27.303
UL	90.000	90.000	90.000	90.000



NDD Report
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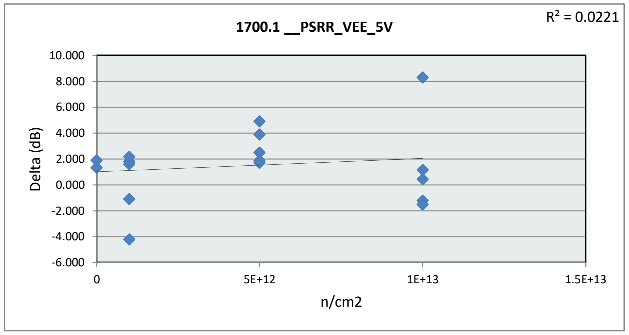
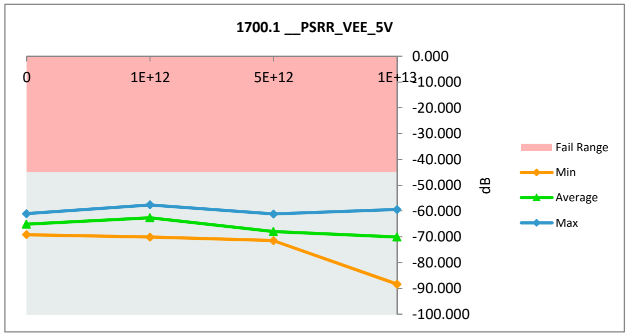
	1700.1 __PSRR_VEE_5V	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	dB	dB
Max Limit	-45	-45
Min Limit		

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-67.843	-69.168	1.325
0	106	-59.235	-61.126	1.891
1E+12	1	-56.057	-57.648	1.591
1E+12	2	-68.397	-70.191	1.795
1E+12	3	-61.874	-60.789	-1.085
1E+12	4	-64.950	-60.740	-4.210
1E+12	5	-61.923	-64.099	2.176
5E+12	13	-59.473	-61.170	1.696
5E+12	14	-69.002	-71.484	2.482
5E+12	15	-67.871	-69.738	1.867
5E+12	16	-66.447	-70.341	3.894
5E+12	17	-62.819	-67.739	4.919
1E+13	6	-64.731	-65.884	1.152
1E+13	7	-76.168	-74.946	-1.222
1E+13	9	-63.375	-61.867	-1.508
1E+13	10	-80.062	-88.372	8.310
1E+13	12	-59.081	-59.522	0.441
	Max	-56.057	-57.648	8.310
	Average	-65.253	-66.754	1.501
	Min	-80.062	-88.372	-4.210
	Std Dev	6.134	7.495	2.769



	1700.1 __PSRR_VEE_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-45	dB		
Min Limit		dB		
n/cm2	0	1E+12	5E+12	1E+13
LL				
Min	-69.168	-70.191	-71.484	-88.372
Average	-65.147	-62.693	-68.094	-70.118
Max	-61.126	-57.648	-61.170	-59.522
UL	-45.000	-45.000	-45.000	-45.000



NDD Report
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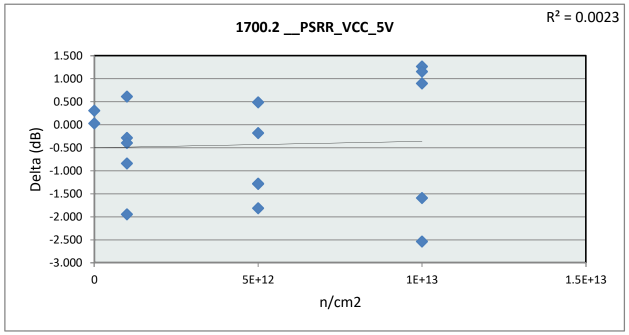
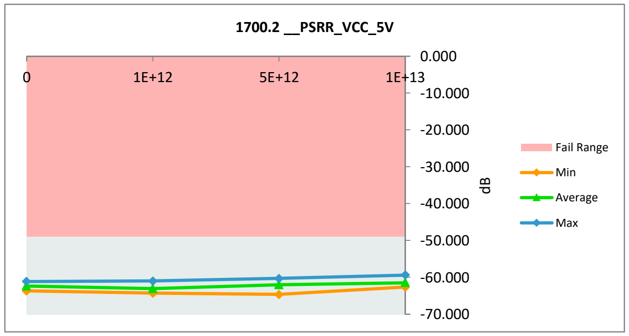
		1700.2 __PSRR_VCC_5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	dB	dB	
	Max Limit	-49	-49	
	Min Limit			
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-60.831	-61.137	0.306
0	106	-63.697	-63.726	0.028
1E+12	1	-61.831	-60.987	-0.844
1E+12	2	-64.098	-63.813	-0.285
1E+12	3	-64.750	-64.352	-0.397
1E+12	4	-62.404	-63.018	0.614
1E+12	5	-65.168	-63.224	-1.943
5E+12	13	-61.371	-61.193	-0.178
5E+12	14	-59.881	-60.370	0.489
5E+12	15	-65.928	-64.641	-1.287
5E+12	16	-62.649	-61.368	-1.281
5E+12	17	-64.638	-62.821	-1.817
1E+13	6	-60.474	-61.742	1.268
1E+13	7	-59.752	-60.909	1.157
1E+13	9	-64.196	-62.604	-1.592
1E+13	10	-61.740	-62.635	0.895
1E+13	12	-61.946	-59.411	-2.535
	Max	-59.752	-59.411	1.268
	Average	-62.668	-62.233	-0.435
	Min	-65.928	-64.641	-2.535
	Std Dev	1.917	1.485	1.161

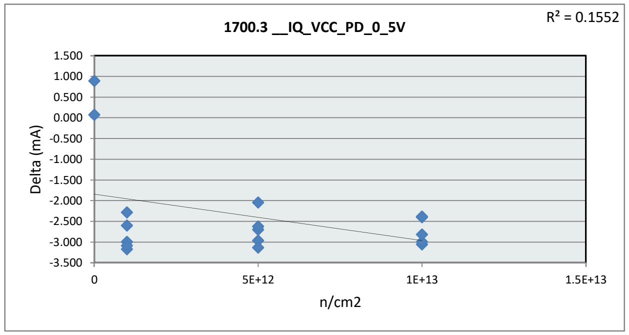


	1700.2 __PSRR_VCC_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-49	dB		
Min Limit		dB		
n/cm2	0	1E+12	5E+12	1E+13
LL				
Min	-63.726	-64.352	-64.641	-62.635
Average	-62.432	-63.079	-62.079	-61.460
Max	-61.137	-60.987	-60.370	-59.411
UL	-49.000	-49.000	-49.000	-49.000

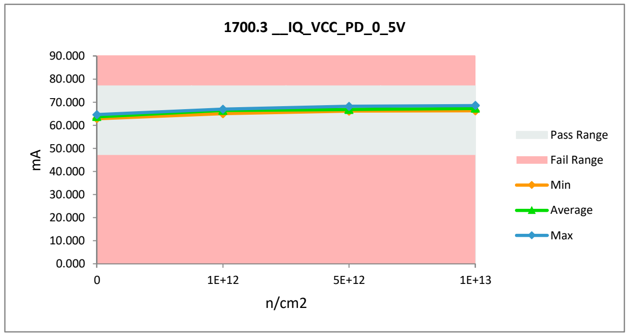


NDD Report
LMH5401-SP

		1700.3 __IQ_VCC_PD_0_5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	77	77	
	Min Limit	47	47	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	65.459	64.567	0.892
0	106	62.951	62.874	0.077
1E+12	1	62.433	65.030	-2.597
1E+12	2	63.932	66.928	-2.996
1E+12	3	63.425	66.595	-3.170
1E+12	4	64.493	66.773	-2.281
1E+12	5	63.102	66.186	-3.084
5E+12	13	64.326	66.368	-2.042
5E+12	14	65.444	68.148	-2.704
5E+12	15	63.151	66.114	-2.963
5E+12	16	64.304	66.931	-2.627
5E+12	17	63.274	66.411	-3.137
1E+13	6	64.849	67.247	-2.398
1E+13	7	64.371	67.425	-3.054
1E+13	9	63.943	66.938	-2.995
1E+13	10	66.146	68.532	-2.386
1E+13	12	63.476	66.289	-2.813
	Max	66.146	68.532	0.892
	Average	64.064	66.433	-2.369
	Min	62.433	62.874	-3.170
	Std Dev	1.009	1.327	1.132



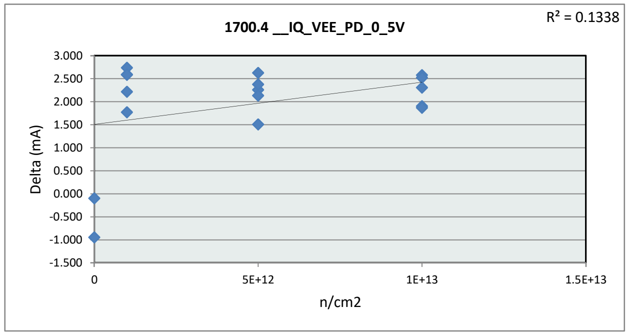
	1700.3 __IQ_VCC_PD_0_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	77	mA		
Min Limit	47	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	47.000	47.000	47.000	47.000
Min	62.874	65.030	66.114	66.289
Average	63.721	66.302	66.794	67.286
Max	64.567	66.928	68.148	68.532
UL	77.000	77.000	77.000	77.000



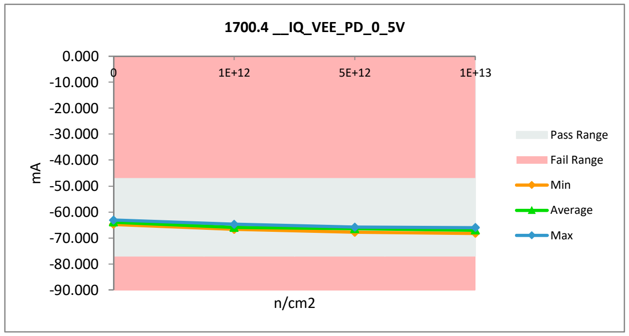
NDD Report
LMH5401-SP

	1700.4 __IQ_VEE_PD_0_5V	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	mA	mA
Max Limit	-47	-47
Min Limit	-77	-77

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-65.730	-64.780	-0.951
0	106	-63.194	-63.093	-0.101
1E+12	1	-62.551	-64.766	2.215
1E+12	2	-64.068	-66.659	2.590
1E+12	3	-63.592	-66.328	2.736
1E+12	4	-64.735	-66.509	1.774
1E+12	5	-63.326	-65.911	2.585
5E+12	13	-64.589	-66.094	1.505
5E+12	14	-65.603	-67.864	2.261
5E+12	15	-63.435	-65.809	2.373
5E+12	16	-64.516	-66.647	2.131
5E+12	17	-63.481	-66.106	2.625
1E+13	6	-65.100	-67.006	1.907
1E+13	7	-64.584	-67.164	2.580
1E+13	9	-64.147	-66.671	2.524
1E+13	10	-66.382	-68.252	1.870
1E+13	12	-63.702	-66.008	2.306
	Max	-62.551	-63.093	2.736
	Average	-64.278	-66.216	1.937
	Min	-66.382	-68.252	-0.951
	Std Dev	1.021	1.207	0.999



	1700.4 __IQ_VEE_PD_0_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-47	mA		
Min Limit	-77	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-77.000	-77.000	-77.000	-77.000
Min	-64.780	-66.659	-67.864	-68.252
Average	-63.936	-66.035	-66.504	-67.020
Max	-63.093	-64.766	-65.809	-66.008
UL	-47.000	-47.000	-47.000	-47.000



NDD Report
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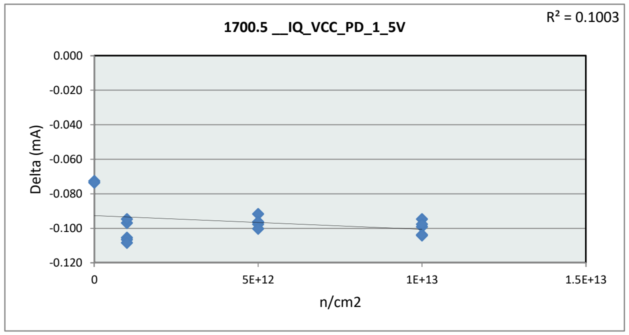
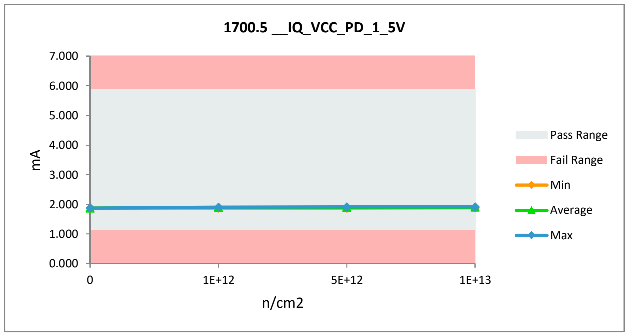
		1700.5 __IQ_VCC_PD_1_5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	5.875	5.875	
	Min Limit	1.125	1.125	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.796	1.868	-0.073
0	106	1.802	1.875	-0.074
1E+12	1	1.796	1.893	-0.097
1E+12	2	1.787	1.892	-0.105
1E+12	3	1.799	1.906	-0.106
1E+12	4	1.796	1.904	-0.108
1E+12	5	1.779	1.874	-0.095
5E+12	13	1.805	1.901	-0.096
5E+12	14	1.817	1.908	-0.092
5E+12	15	1.785	1.882	-0.098
5E+12	16	1.784	1.881	-0.096
5E+12	17	1.772	1.872	-0.100
1E+13	6	1.803	1.898	-0.095
1E+13	7	1.808	1.913	-0.104
1E+13	9	1.814	1.913	-0.099
1E+13	10	1.816	1.913	-0.098
1E+13	12	1.780	1.884	-0.104
	Max	1.817	1.913	-0.073
	Average	1.796	1.893	-0.096
	Min	1.772	1.868	-0.108
	Std Dev	0.014	0.016	0.010



	1700.5 __IQ_VCC_PD_1_5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	5.875	mA		
Min Limit	1.125	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	1.125	1.125	1.125	1.125
Min	1.868	1.874	1.872	1.884
Average	1.872	1.894	1.889	1.904
Max	1.875	1.906	1.909	1.913
UL	5.875	5.875	5.875	5.875



NDD Report
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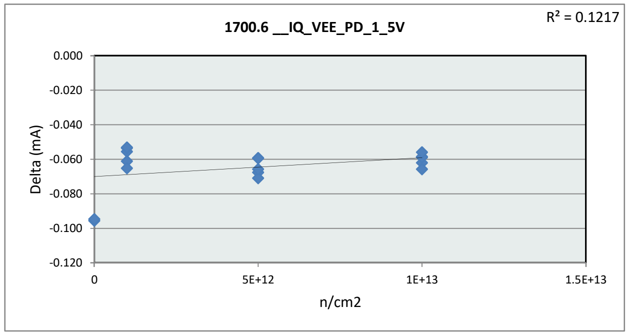
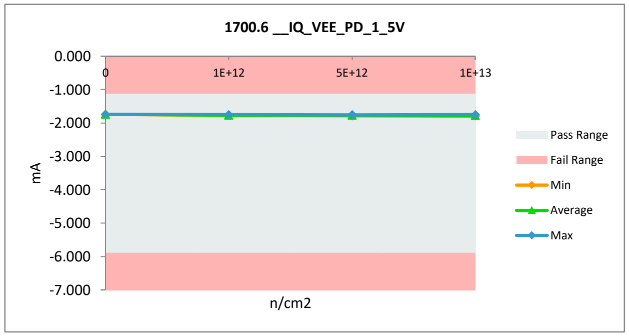
	1700.6 __IQ_VEE_PD_1_5V	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	mA	mA
Max Limit	-1.125	-1.125
Min Limit	-5.875	-5.875

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-1.839	-1.743	-0.096
0	106	-1.837	-1.743	-0.095
1E+12	1	-1.826	-1.770	-0.056
1E+12	2	-1.820	-1.767	-0.053
1E+12	3	-1.842	-1.781	-0.061
1E+12	4	-1.833	-1.780	-0.053
1E+12	5	-1.822	-1.756	-0.065
5E+12	13	-1.849	-1.781	-0.068
5E+12	14	-1.849	-1.789	-0.059
5E+12	15	-1.830	-1.759	-0.071
5E+12	16	-1.828	-1.762	-0.066
5E+12	17	-1.817	-1.757	-0.059
1E+13	6	-1.845	-1.783	-0.062
1E+13	7	-1.848	-1.789	-0.058
1E+13	9	-1.850	-1.791	-0.059
1E+13	10	-1.851	-1.795	-0.056
1E+13	12	-1.822	-1.757	-0.066
	Max	-1.817	-1.743	-0.053
	Average	-1.836	-1.771	-0.065
	Min	-1.851	-1.795	-0.096
	Std Dev	0.012	0.017	0.012



	1700.6 __IQ_VEE_PD_1_5V	
Test Site	1	
Tester	ETS364	
Test Number	EF868301	
Max Limit	-1.125	mA
Min Limit	-5.875	mA

n/cm2	0	1E+12	5E+12	1E+13
LL	-5.875	-5.875	-5.875	-5.875
Min	-1.743	-1.781	-1.789	-1.795
Average	-1.743	-1.771	-1.770	-1.783
Max	-1.743	-1.756	-1.757	-1.757
UL	-1.125	-1.125	-1.125	-1.125



NDD Report
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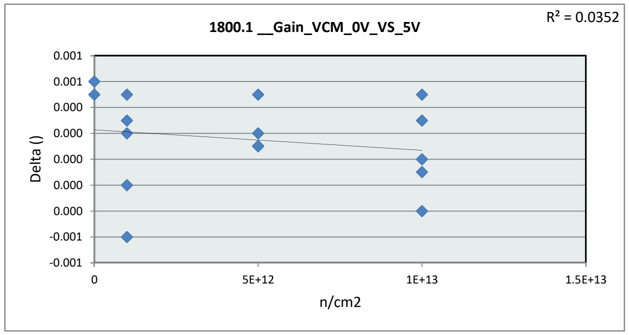
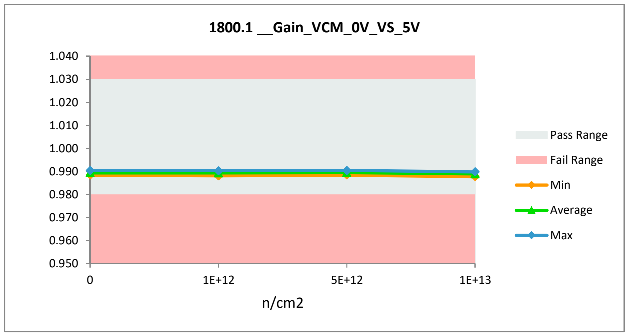
		1800.1 __Gain_VCM_0V_VS_5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit			
	Max Limit	1.03	1.03	
	Min Limit	0.98	0.98	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	0.989	0.988	0.001
0	106	0.991	0.990	0.001
1E+12	1	0.990	0.990	0.000
1E+12	2	0.988	0.988	0.000
1E+12	3	0.990	0.990	-0.001
1E+12	4	0.989	0.988	0.001
1E+12	5	0.989	0.989	0.000
5E+12	13	0.991	0.990	0.000
5E+12	14	0.988	0.988	0.000
5E+12	15	0.990	0.990	0.000
5E+12	16	0.989	0.989	0.000
5E+12	17	0.990	0.989	0.001
1E+13	6	0.989	0.989	0.000
1E+13	7	0.988	0.988	0.000
1E+13	9	0.989	0.990	0.000
1E+13	10	0.988	0.988	0.001
1E+13	12	0.990	0.989	0.000
	Max	0.991	0.990	0.001
	Average	0.989	0.989	0.000
	Min	0.988	0.988	-0.001
	Std Dev	0.001	0.001	0.000

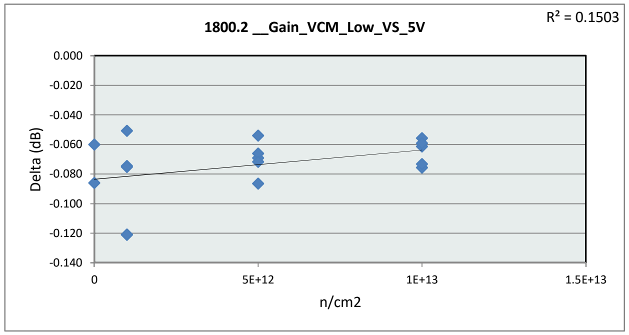


	1800.1 __Gain_VCM_0V_VS_5			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.03			
Min Limit	0.98			
n/cm2	0	1E+12	5E+12	1E+13
LL	0.980	0.980	0.980	0.980
Min	0.988	0.988	0.988	0.988
Average	0.989	0.989	0.989	0.989
Max	0.990	0.990	0.990	0.990
UL	1.030	1.030	1.030	1.030

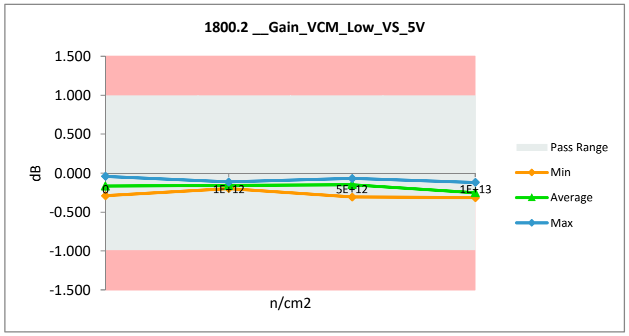


NDD Report
LMH5401-SP

		1800.2 __Gain_VCM_Low_VS_5V		
Test Site		1	1	
Tester		ETS364	ETS364	
Test Number		EF868301	EF868301	
Unit		dB	dB	
Max Limit		0.99	0.99	
Min Limit		-0.99	-0.99	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-0.353	-0.293	-0.060
0	106	-0.128	-0.043	-0.086
1E+12	1	-0.195	-0.121	-0.074
1E+12	2	-0.319	-0.198	-0.121
1E+12	3	-0.265	-0.190	-0.075
1E+12	4	-0.290	-0.169	-0.121
1E+12	5	-0.167	-0.116	-0.051
5E+12	13	-0.212	-0.143	-0.069
5E+12	14	-0.375	-0.309	-0.066
5E+12	15	-0.157	-0.071	-0.086
5E+12	16	-0.190	-0.119	-0.072
5E+12	17	-0.161	-0.107	-0.054
1E+13	6	-0.372	-0.316	-0.056
1E+13	7	-0.363	-0.301	-0.061
1E+13	9	-0.299	-0.223	-0.076
1E+13	10	-0.373	-0.314	-0.059
1E+13	12	-0.193	-0.120	-0.073
	Max	-0.128	-0.043	-0.051
	Average	-0.260	-0.185	-0.074
	Min	-0.375	-0.316	-0.121
	Std Dev	0.089	0.092	0.020

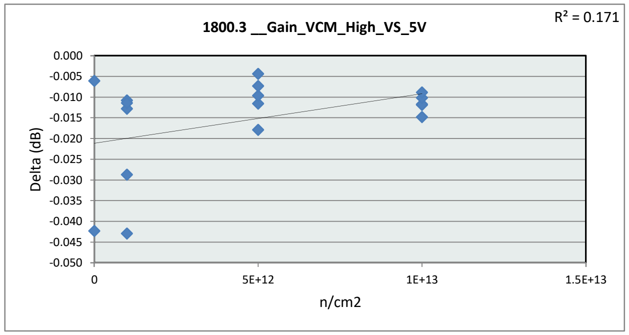


	1800.2 __Gain_VCM_Low_VS_			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	0.99	dB		
Min Limit	-0.99	dB		
n/cm2	0	1E+12	5E+12	1E+13
LL	-0.990	-0.990	-0.990	-0.990
Min	-0.293	-0.198	-0.309	-0.316
Average	-0.168	-0.159	-0.149	-0.255
Max	-0.043	-0.116	-0.071	-0.120
UL	0.990	0.990	0.990	0.990

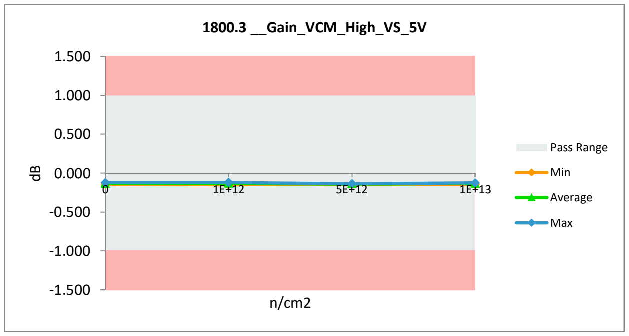


NDD Report
LMH5401-SP

		1800.3 __Gain_VCM_High_VS_5		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	dB	dB	
	Max Limit	0.99	0.99	
	Min Limit	-0.99	-0.99	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-0.149	-0.143	-0.006
0	106	-0.168	-0.125	-0.042
1E+12	1	-0.164	-0.121	-0.043
1E+12	2	-0.145	-0.133	-0.013
1E+12	3	-0.161	-0.150	-0.011
1E+12	4	-0.153	-0.124	-0.029
1E+12	5	-0.150	-0.139	-0.011
5E+12	13	-0.159	-0.141	-0.018
5E+12	14	-0.149	-0.138	-0.012
5E+12	15	-0.148	-0.144	-0.004
5E+12	16	-0.150	-0.140	-0.010
5E+12	17	-0.150	-0.143	-0.007
1E+13	6	-0.147	-0.136	-0.012
1E+13	7	-0.144	-0.132	-0.012
1E+13	9	-0.157	-0.147	-0.010
1E+13	10	-0.143	-0.128	-0.015
1E+13	12	-0.154	-0.145	-0.009
	Max	-0.143	-0.121	-0.004
	Average	-0.152	-0.137	-0.015
	Min	-0.168	-0.150	-0.043
	Std Dev	0.007	0.009	0.012

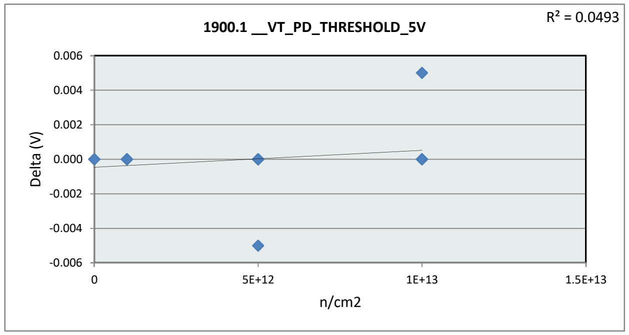


	1800.3 __Gain_VCM_High_VS			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	0.99	dB		
Min Limit	-0.99	dB		
n/cm2	0	1E+12	5E+12	1E+13
LL	-0.990	-0.990	-0.990	-0.990
Min	-0.143	-0.150	-0.144	-0.147
Average	-0.134	-0.133	-0.141	-0.138
Max	-0.125	-0.121	-0.138	-0.128
UL	0.990	0.990	0.990	0.990

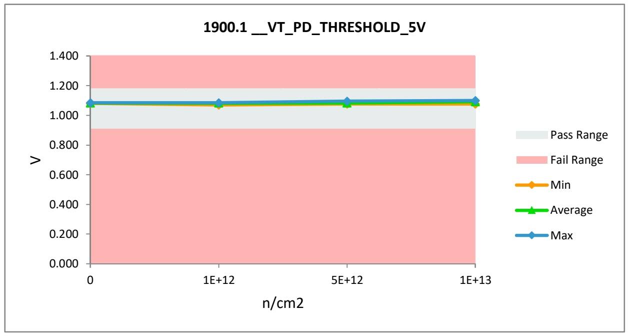


NDD Report
LMH5401-SP

		1900.1 __VT_PD_THRESHOLD_5		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	V	V	
	Max Limit	1.18	1.18	
	Min Limit	0.91	0.91	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.080	1.080	0.000
0	106	1.085	1.085	0.000
1E+12	1	1.070	1.070	0.000
1E+12	2	1.085	1.085	0.000
1E+12	3	1.085	1.085	0.000
1E+12	4	1.085	1.085	0.000
1E+12	5	1.080	1.080	0.000
5E+12	13	1.085	1.085	0.000
5E+12	14	1.090	1.095	-0.005
5E+12	15	1.080	1.080	0.000
5E+12	16	1.075	1.075	0.000
5E+12	17	1.075	1.075	0.000
1E+13	6	1.100	1.100	0.000
1E+13	7	1.100	1.100	0.000
1E+13	9	1.090	1.085	0.005
1E+13	10	1.095	1.095	0.000
1E+13	12	1.075	1.075	0.000
	Max	1.100	1.100	0.005
	Average	1.084	1.084	0.000
	Min	1.070	1.070	-0.005
	Std Dev	0.009	0.009	0.002

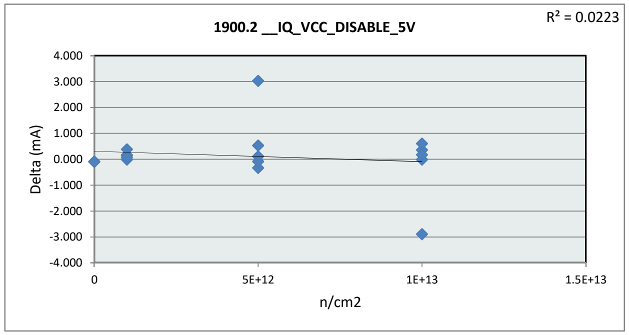


	1900.1 __VT_PD_THRESHOLD			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.18	V		
Min Limit	0.91	V		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.910	0.910	0.910	0.910
Min	1.080	1.070	1.075	1.075
Average	1.083	1.081	1.082	1.091
Max	1.085	1.085	1.095	1.100
UL	1.180	1.180	1.180	1.180

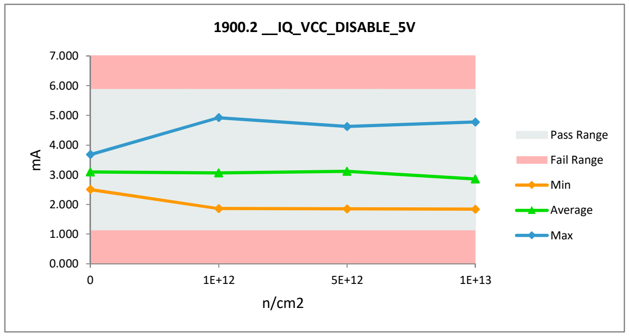


NDD Report
LMH5401-SP

		1900.2 __IQ_VCC_DISABLE_5V		
Test Site		1	1	
Tester		ETS364	ETS364	
Test Number		EF868301	EF868301	
Unit		mA	mA	
Max Limit		5.875	5.875	
Min Limit		1.125	1.125	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	2.414	2.502	-0.088
0	106	3.577	3.680	-0.103
1E+12	1	3.579	3.203	0.376
1E+12	2	3.171	3.022	0.149
1E+12	3	4.913	4.922	-0.009
1E+12	4	2.412	2.256	0.157
1E+12	5	1.932	1.862	0.070
5E+12	13	3.646	3.982	-0.336
5E+12	14	4.884	1.851	3.033
5E+12	15	4.738	4.627	0.110
5E+12	16	2.129	2.216	-0.086
5E+12	17	3.424	2.895	0.529
1E+13	6	1.904	1.918	-0.014
1E+13	7	2.196	1.836	0.359
1E+13	9	1.880	4.772	-2.892
1E+13	10	2.056	1.880	0.176
1E+13	12	4.465	3.855	0.609
	Max	4.913	4.922	3.033
	Average	3.137	3.016	0.120
	Min	1.880	1.836	-2.892
	Std Dev	1.116	1.104	1.074

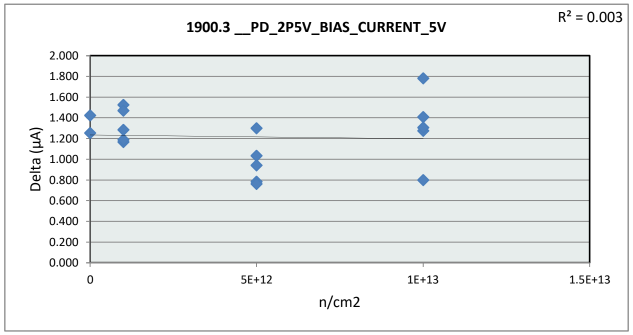


	1900.2 __IQ_VCC_DISABLE_5			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	5.875	mA		
Min Limit	1.125	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	1.125	1.125	1.125	1.125
Min	2.502	1.862	1.851	1.836
Average	3.091	3.053	3.114	2.852
Max	3.680	4.922	4.627	4.772
UL	5.875	5.875	5.875	5.875

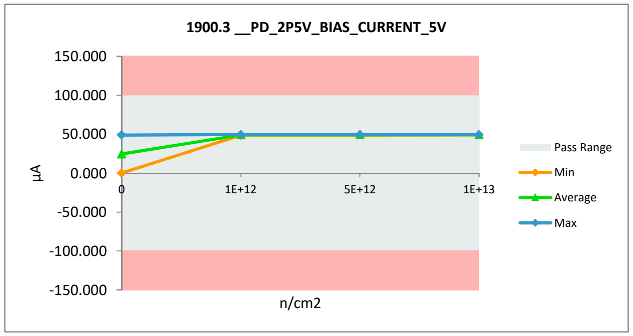


NDD Report
LMH5401-SP

		1900.3 __PD_2P5V_BIAS_CURR		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	µA	µA	
	Max Limit	99	99	
	Min Limit	-99	-99	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	50.708	49.285	1.423
0	106	50.171	48.919	1.252
1E+12	1	50.459	48.935	1.524
1E+12	2	50.202	48.733	1.469
1E+12	3	50.249	48.966	1.282
1E+12	4	50.553	49.387	1.165
1E+12	5	50.225	49.036	1.189
5E+12	13	50.366	49.333	1.033
5E+12	14	50.529	49.231	1.298
5E+12	15	49.852	48.912	0.940
5E+12	16	50.171	49.387	0.784
5E+12	17	50.116	49.356	0.761
1E+13	6	50.109	48.834	1.275
1E+13	7	50.576	48.795	1.781
1E+13	9	50.140	49.340	0.799
1E+13	10	50.623	49.216	1.407
1E+13	12	50.155	48.849	1.306
	Max	50.708	49.387	1.781
	Average	50.306	49.089	1.217
	Min	49.852	48.733	0.761
	Std Dev	0.232	0.235	0.281

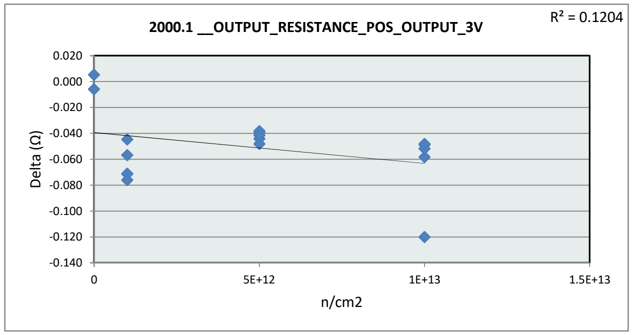


	1900.3 __PD_2P5V_BIAS_CUR			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	99	µA		
Min Limit	-99	µA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-99.000	-99.000	-99.000	-99.000
Min	0.000	48.733	48.912	48.795
Average	24.459	49.012	49.244	49.007
Max	48.919	49.387	49.387	49.340
UL	99.000	99.000	99.000	99.000

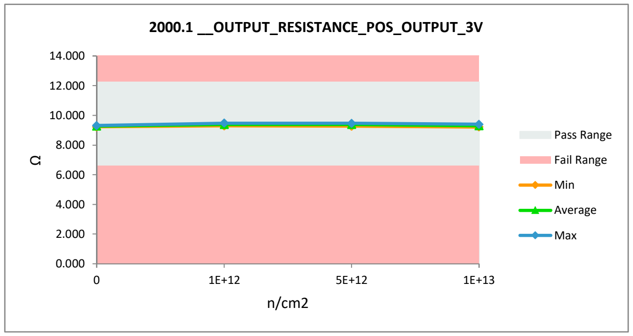


NDD Report
LMH5401-SP

		2000.1 __OUTPUT_RESISTANCE_		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	Ω	Ω	
	Max Limit	12.25	12.25	
	Min Limit	6.6	6.6	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	9.232	9.227	0.005
0	106	9.311	9.316	-0.006
1E+12	1	9.234	9.305	-0.071
1E+12	2	9.416	9.473	-0.057
1E+12	3	9.226	9.297	-0.071
1E+12	4	9.239	9.315	-0.076
1E+12	5	9.394	9.439	-0.045
5E+12	13	9.245	9.285	-0.040
5E+12	14	9.229	9.273	-0.044
5E+12	15	9.418	9.466	-0.048
5E+12	16	9.391	9.429	-0.038
5E+12	17	9.408	9.449	-0.041
1E+13	6	9.164	9.213	-0.049
1E+13	7	9.248	9.300	-0.052
1E+13	9	9.259	9.307	-0.048
1E+13	10	9.136	9.257	-0.120
1E+13	12	9.346	9.405	-0.058
	Max	9.418	9.473	0.005
	Average	9.288	9.339	-0.051
	Min	9.136	9.213	-0.120
	Std Dev	0.091	0.086	0.027



	2000.1 __OUTPUT_RESISTANC			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	12.25	Ω		
Min Limit	6.6	Ω		
n/cm2	0	1E+12	5E+12	1E+13
LL	6.600	6.600	6.600	6.600
Min	9.227	9.297	9.273	9.213
Average	9.272	9.366	9.380	9.296
Max	9.317	9.473	9.466	9.405
UL	12.250	12.250	12.250	12.250



NDD Report
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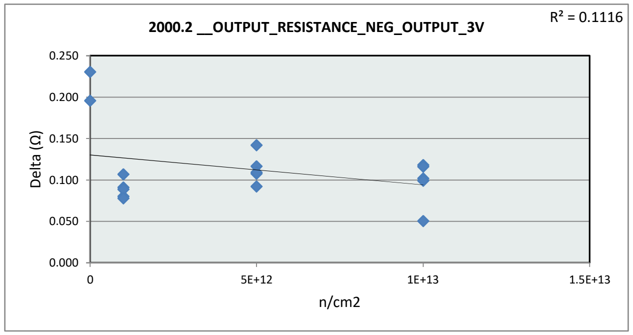
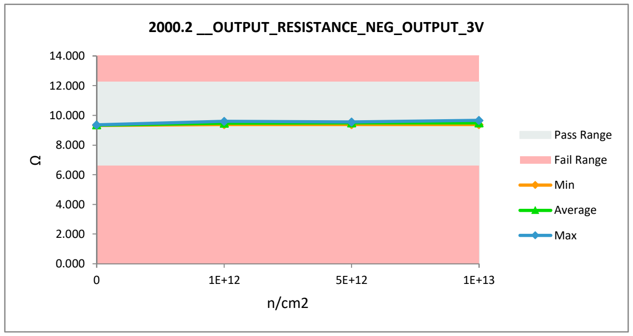
		2000.2 __OUTPUT_RESISTANCE_		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	Ω	Ω	
	Max Limit	12.25	12.25	
	Min Limit	6.6	6.6	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	9.557	9.327	0.230
0	106	9.554	9.358	0.196
1E+12	1	9.472	9.381	0.091
1E+12	2	9.660	9.579	0.080
1E+12	3	9.486	9.397	0.089
1E+12	4	9.523	9.416	0.107
1E+12	5	9.594	9.516	0.078
5E+12	13	9.499	9.382	0.116
5E+12	14	9.566	9.424	0.142
5E+12	15	9.660	9.552	0.108
5E+12	16	9.625	9.516	0.109
5E+12	17	9.635	9.543	0.092
1E+13	6	9.479	9.377	0.102
1E+13	7	9.576	9.458	0.118
1E+13	9	9.526	9.410	0.116
1E+13	10	9.710	9.660	0.051
1E+13	12	9.611	9.512	0.099
	Max	9.710	9.660	0.230
	Average	9.572	9.459	0.113
	Min	9.472	9.327	0.051
	Std Dev	0.071	0.092	0.043



	2000.2 __OUTPUT_RESISTANC			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	12.25	Ω		
Min Limit	6.6	Ω		
n/cm2	0	1E+12	5E+12	1E+13
LL	6.600	6.600	6.600	6.600
Min	9.327	9.381	9.382	9.377
Average	9.342	9.458	9.484	9.483
Max	9.358	9.579	9.552	9.660
UL	12.250	12.250	12.250	12.250



NDD Report
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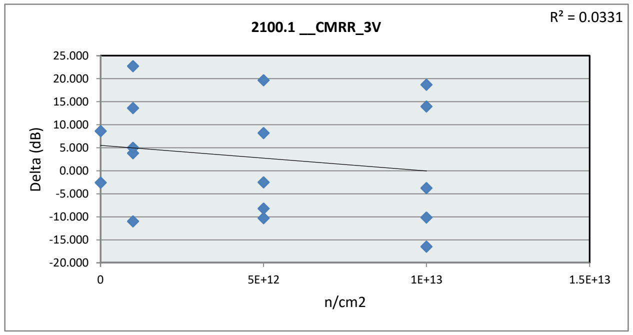
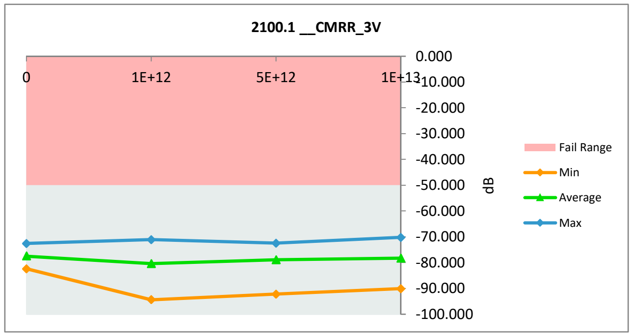
		2100.1 __CMRR_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	dB	dB	
	Max Limit	-50	-50	
	Min Limit			
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-73.780	-82.393	8.614
0	106	-75.153	-72.604	-2.549
1E+12	1	-71.993	-75.797	3.804
1E+12	2	-69.257	-82.887	13.630
1E+12	3	-82.164	-71.176	-10.989
1E+12	4	-73.064	-78.036	4.972
1E+12	5	-71.694	-94.434	22.740
5E+12	13	-81.246	-73.043	-8.203
5E+12	14	-82.805	-72.503	-10.302
5E+12	15	-73.688	-81.909	8.221
5E+12	16	-77.561	-75.030	-2.531
5E+12	17	-72.590	-92.281	19.691
1E+13	6	-71.436	-90.117	18.681
1E+13	7	-82.598	-72.464	-10.134
1E+13	9	-86.727	-70.238	-16.489
1E+13	10	-76.117	-72.363	-3.755
1E+13	12	-72.667	-86.650	13.983
	Max	-69.257	-70.238	22.740
	Average	-76.149	-79.054	2.905
	Min	-86.727	-94.434	-16.489
	Std Dev	5.097	7.914	12.167



	2100.1 __CMRR_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-50	dB		
Min Limit		dB		
n/cm2	0	1E+12	5E+12	1E+13
LL				
Min	-82.393	-94.434	-92.281	-90.117
Average	-77.499	-80.466	-78.953	-78.366
Max	-72.604	-71.176	-72.503	-70.238
UL	-50.000	-50.000	-50.000	-50.000



NDD Report
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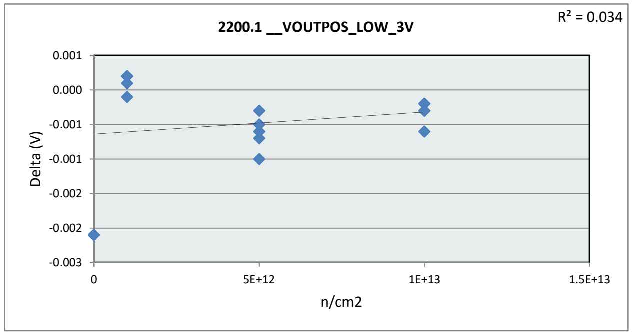
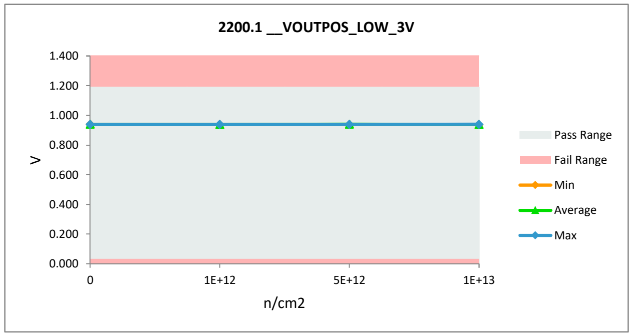
		2200.1 __VOUTPOS_LOW_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	V	V	
	Max Limit	1.19	1.19	
	Min Limit	0.033	0.033	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	0.937	0.939	-0.002
0	106	0.937	0.939	-0.002
1E+12	1	0.938	0.938	0.000
1E+12	2	0.939	0.939	0.000
1E+12	3	0.939	0.938	0.000
1E+12	4	0.938	0.938	0.000
1E+12	5	0.939	0.939	0.000
5E+12	13	0.938	0.939	-0.001
5E+12	14	0.938	0.939	-0.001
5E+12	15	0.938	0.939	-0.001
5E+12	16	0.938	0.938	0.000
5E+12	17	0.938	0.938	0.000
1E+13	6	0.938	0.938	-0.001
1E+13	7	0.938	0.938	0.000
1E+13	9	0.938	0.938	0.000
1E+13	10	0.939	0.939	0.000
1E+13	12	0.938	0.938	0.000
	Max	0.939	0.939	0.000
	Average	0.938	0.939	0.000
	Min	0.937	0.938	-0.002
	Std Dev	0.001	0.000	0.001



	2200.1 __VOUTPOS_LOW_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.19	V		
Min Limit	0.033	V		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.033	0.033	0.033	0.033
Min	0.939	0.938	0.938	0.938
Average	0.939	0.938	0.939	0.938
Max	0.939	0.939	0.939	0.939
UL	1.190	1.190	1.190	1.190



NDD Report
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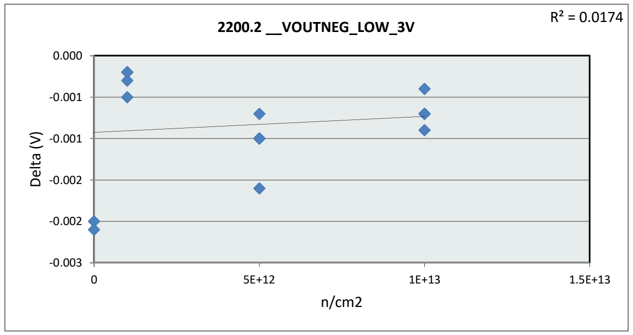
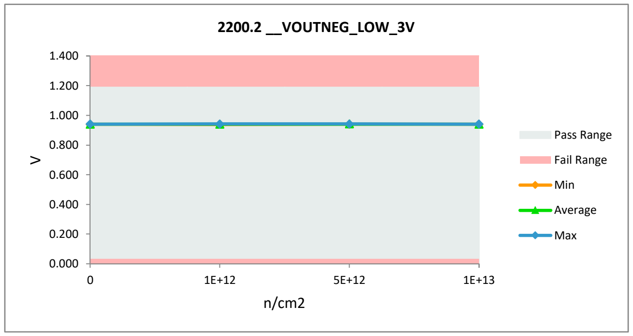
		2200.2 __VOUTNEG_LOW_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	V	V	
	Max Limit	1.19	1.19	
	Min Limit	0.033	0.033	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	0.938	0.940	-0.002
0	106	0.939	0.941	-0.002
1E+12	1	0.939	0.939	0.000
1E+12	2	0.940	0.941	0.000
1E+12	3	0.940	0.940	0.000
1E+12	4	0.940	0.941	-0.001
1E+12	5	0.941	0.941	0.000
5E+12	13	0.939	0.941	-0.002
5E+12	14	0.940	0.941	-0.001
5E+12	15	0.940	0.941	-0.001
5E+12	16	0.940	0.941	-0.001
5E+12	17	0.940	0.940	-0.001
1E+13	6	0.938	0.939	-0.001
1E+13	7	0.940	0.940	-0.001
1E+13	9	0.939	0.940	-0.001
1E+13	10	0.941	0.941	0.000
1E+13	12	0.940	0.940	-0.001
	Max	0.941	0.941	0.000
	Average	0.940	0.940	-0.001
	Min	0.938	0.939	-0.002
	Std Dev	0.001	0.001	0.001



	2200.2 __VOUTNEG_LOW_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.19	V		
Min Limit	0.033	V		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.033	0.033	0.033	0.033
Min	0.940	0.939	0.940	0.939
Average	0.941	0.940	0.941	0.940
Max	0.941	0.941	0.941	0.941
UL	1.190	1.190	1.190	1.190



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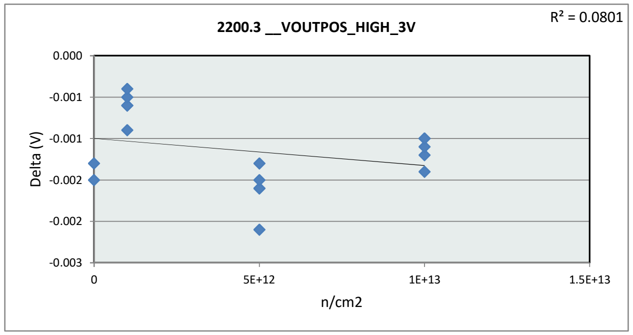
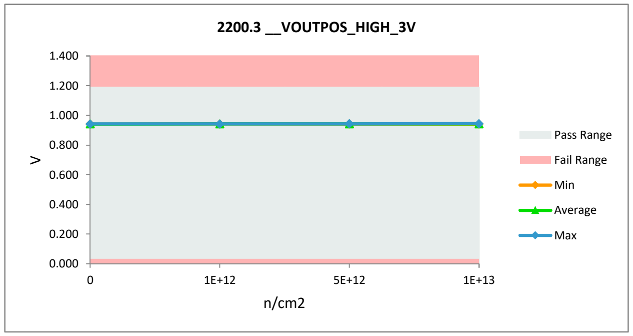
	2200.3 __VOUTPOS_HIGH_3V	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	V	V
Max Limit	1.19	1.19
Min Limit	0.033	0.033

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	0.940	0.941	-0.001
0	106	0.940	0.942	-0.002
1E+12	1	0.942	0.942	-0.001
1E+12	2	0.942	0.942	-0.001
1E+12	3	0.941	0.942	0.000
1E+12	4	0.941	0.942	-0.001
1E+12	5	0.941	0.941	0.000
5E+12	13	0.942	0.944	-0.002
5E+12	14	0.941	0.942	-0.002
5E+12	15	0.940	0.941	-0.002
5E+12	16	0.940	0.942	-0.002
5E+12	17	0.940	0.941	-0.001
1E+13	6	0.942	0.943	-0.001
1E+13	7	0.941	0.942	-0.001
1E+13	9	0.941	0.942	-0.001
1E+13	10	0.942	0.943	-0.001
1E+13	12	0.940	0.941	-0.001
	Max	0.942	0.944	0.000
	Average	0.941	0.942	-0.001
	Min	0.940	0.941	-0.002
	Std Dev	0.001	0.001	0.000



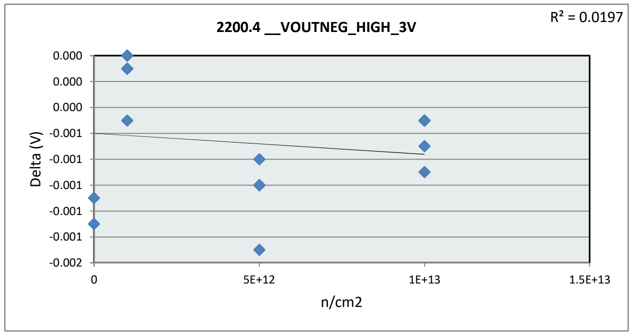
	2200.3 __VOUTPOS_HIGH_3V	
Test Site	1	
Tester	ETS364	
Test Number	EF868301	
Max Limit	1.19	V
Min Limit	0.033	V

n/cm2	0	1E+12	5E+12	1E+13
LL	0.033	0.033	0.033	0.033
Min	0.941	0.941	0.941	0.941
Average	0.941	0.942	0.942	0.942
Max	0.942	0.942	0.944	0.943
UL	1.190	1.190	1.190	1.190

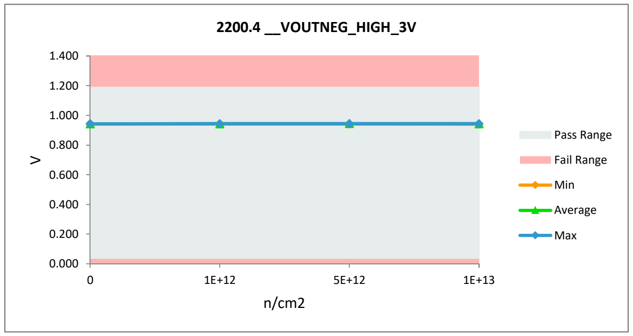


NDD Report
LMH5401-SP

		2200.4 __VOUTNEG_HIGH_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	V	V	
	Max Limit	1.19	1.19	
	Min Limit	0.033	0.033	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	0.941	0.942	-0.001
0	106	0.942	0.943	-0.001
1E+12	1	0.942	0.943	0.000
1E+12	2	0.942	0.942	0.000
1E+12	3	0.943	0.943	0.000
1E+12	4	0.942	0.942	0.000
1E+12	5	0.942	0.942	0.000
5E+12	13	0.943	0.944	-0.002
5E+12	14	0.942	0.943	-0.001
5E+12	15	0.941	0.942	-0.001
5E+12	16	0.941	0.942	-0.001
5E+12	17	0.941	0.942	-0.001
1E+13	6	0.942	0.943	-0.001
1E+13	7	0.942	0.943	-0.001
1E+13	9	0.942	0.942	-0.001
1E+13	10	0.943	0.943	-0.001
1E+13	12	0.941	0.942	-0.001
	Max	0.943	0.944	0.000
	Average	0.942	0.943	-0.001
	Min	0.941	0.942	-0.002
	Std Dev	0.001	0.001	0.000



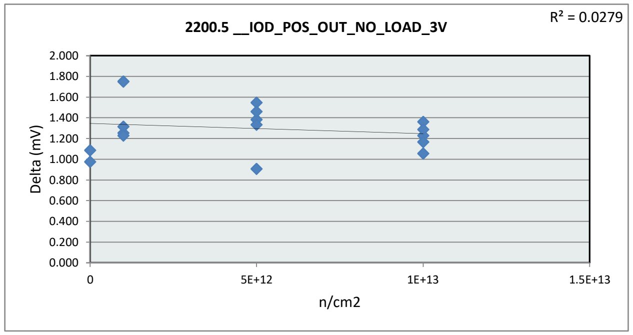
	2200.4 __VOUTNEG_HIGH_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.19	V		
Min Limit	0.033	V		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.033	0.033	0.033	0.033
Min	0.942	0.942	0.942	0.942
Average	0.942	0.942	0.943	0.943
Max	0.943	0.943	0.944	0.943
UL	1.190	1.190	1.190	1.190



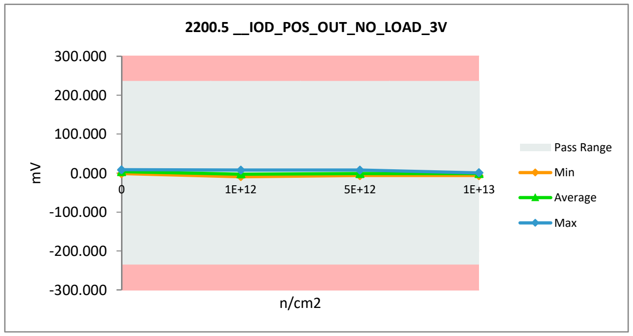
NDD Report
LMH5401-SP

	2200.5 __IOD_POS_OUT_NO_LO	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	mV	mV
Max Limit	235	235
Min Limit	-235	-235

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-0.501	-1.588	1.088
0	106	9.558	8.582	0.976
1E+12	1	9.019	7.766	1.253
1E+12	2	-7.359	-9.109	1.750
1E+12	3	1.686	0.370	1.316
1E+12	4	-3.719	-5.471	1.752
1E+12	5	-6.551	-7.779	1.228
5E+12	13	8.341	7.435	0.906
5E+12	14	0.727	-0.656	1.383
5E+12	15	-3.135	-4.682	1.547
5E+12	16	-3.130	-4.590	1.460
5E+12	17	-5.211	-6.545	1.334
1E+13	6	0.591	-0.465	1.057
1E+13	7	0.096	-1.265	1.361
1E+13	9	1.681	0.454	1.227
1E+13	10	-5.472	-6.757	1.286
1E+13	12	1.911	0.743	1.168
	Max	9.558	8.582	1.752
	Average	-0.086	-1.386	1.299
	Min	-7.359	-9.109	0.906
	Std Dev	5.245	5.403	0.237

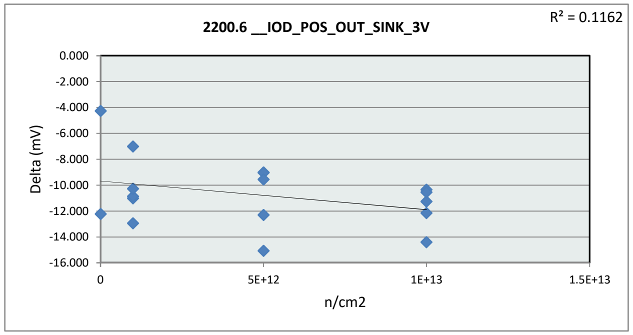


	2200.5 __IOD_POS_OUT_NO_			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	-1.588	-9.109	-6.545	-6.757
Average	3.497	-2.845	-1.808	-1.458
Max	8.582	7.766	7.435	0.743
UL	235.000	235.000	235.000	235.000

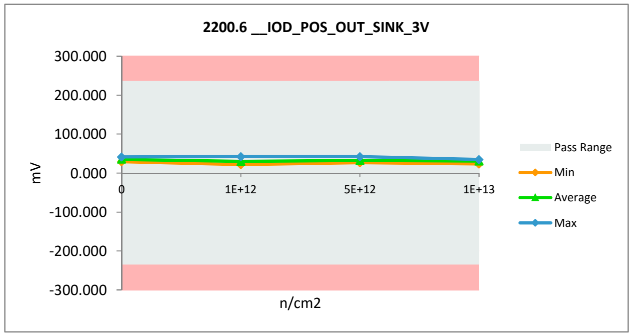


NDD Report
LMH5401-SP

		2200.6 __IOD_POS_OUT_SINK_		
Test Site		1	1	
Tester		ETS364	ETS364	
Test Number		EF868301	EF868301	
Unit		mV	mV	
Max Limit		235	235	
Min Limit		-235	-235	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	16.915	29.135	-12.220
0	106	36.549	40.815	-4.265
1E+12	1	34.676	41.678	-7.003
1E+12	2	8.490	21.436	-12.946
1E+12	3	23.297	34.312	-11.015
1E+12	4	16.171	27.050	-10.879
1E+12	5	13.555	23.826	-10.270
5E+12	13	33.127	42.138	-9.011
5E+12	14	18.105	33.178	-15.073
5E+12	15	19.454	28.489	-9.035
5E+12	16	17.239	29.533	-12.295
5E+12	17	17.036	26.588	-9.552
1E+13	6	19.137	31.290	-12.152
1E+13	7	16.348	30.745	-14.396
1E+13	9	23.288	34.551	-11.263
1E+13	10	12.570	22.931	-10.361
1E+13	12	23.764	34.305	-10.541
	Max	36.549	42.138	-4.265
	Average	20.572	31.294	-10.722
	Min	8.490	21.436	-15.073
	Std Dev	7.825	6.262	2.593



	2200.6 __IOD_POS_OUT_SINK			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	29.135	21.436	26.588	22.931
Average	34.975	29.660	31.985	30.764
Max	40.815	41.678	42.138	34.551
UL	235.000	235.000	235.000	235.000



NDD Report
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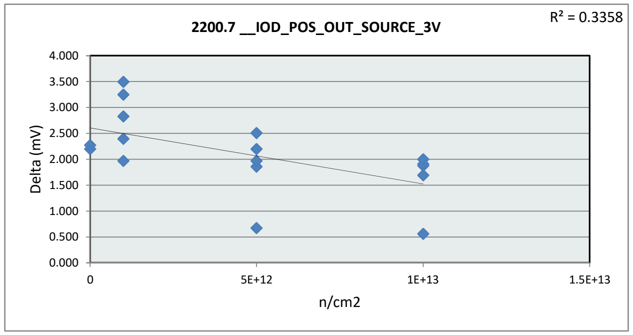
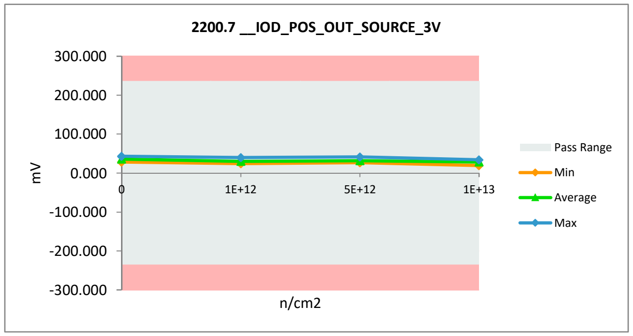
	2200.7 __IOD_POS_OUT_SOURC	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	mV	mV
Max Limit	235	235
Min Limit	-235	-235

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	30.226	28.031	2.195
0	106	45.417	43.145	2.272
1E+12	1	41.598	39.627	1.971
1E+12	2	27.167	23.669	3.498
1E+12	3	36.010	33.613	2.397
1E+12	4	28.775	25.527	3.248
1E+12	5	28.228	25.399	2.829
5E+12	13	41.626	40.955	0.671
5E+12	14	32.818	30.958	1.859
5E+12	15	30.593	28.623	1.970
5E+12	16	30.434	28.237	2.197
5E+12	17	28.582	26.076	2.505
1E+13	6	28.843	27.154	1.688
1E+13	7	30.644	28.771	1.873
1E+13	9	35.654	33.749	1.905
1E+13	10	19.767	19.205	0.562
1E+13	12	34.464	32.463	2.000
	Max	45.417	43.145	3.498
	Average	32.403	30.306	2.097
	Min	19.767	19.205	0.562
	Std Dev	6.260	6.372	0.745



	2200.7 __IOD_POS_OUT_SOU	
Test Site	1	
Tester	ETS364	
Test Number	EF868301	
Max Limit	235	mV
Min Limit	-235	mV

n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	28.031	23.669	26.076	19.205
Average	35.588	29.567	30.970	28.269
Max	43.145	39.627	40.955	33.749
UL	235.000	235.000	235.000	235.000



NDD Report
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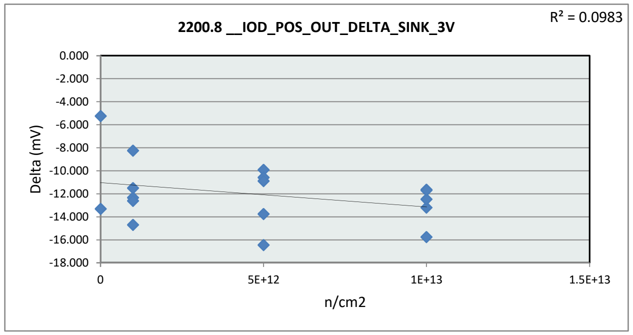
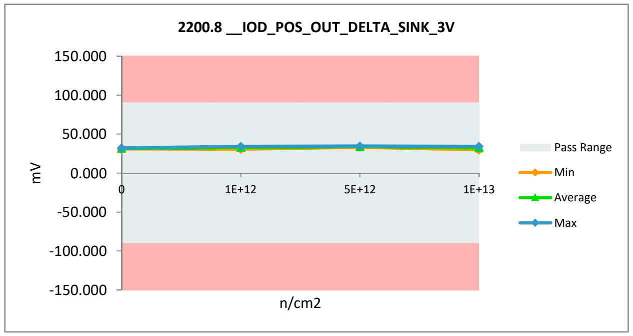
		2200.8 __IOD_POS_OUT_DELTA		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	90	90	
	Min Limit	-90	-90	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	17.416	30.723	-13.307
0	106	26.992	32.233	-5.242
1E+12	1	25.657	33.912	-8.256
1E+12	2	15.848	30.545	-14.697
1E+12	3	21.611	33.942	-12.331
1E+12	4	19.890	32.521	-12.631
1E+12	5	20.106	31.604	-11.498
5E+12	13	24.787	34.703	-9.917
5E+12	14	17.378	33.834	-16.456
5E+12	15	22.588	33.171	-10.583
5E+12	16	20.368	34.123	-13.754
5E+12	17	22.247	33.133	-10.886
1E+13	6	18.546	31.755	-13.209
1E+13	7	16.253	32.010	-15.757
1E+13	9	21.606	34.097	-12.490
1E+13	10	18.041	29.688	-11.647
1E+13	12	21.853	33.562	-11.708
	Max	26.992	34.703	-5.242
	Average	20.658	32.680	-12.022
	Min	15.848	29.688	-16.456
	Std Dev	3.238	1.455	2.692



	2200.8 __IOD_POS_OUT_DELT			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	90	mV		
Min Limit	-90	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-90.000	-90.000	-90.000	-90.000
Min	30.723	30.545	33.133	29.688
Average	31.478	32.505	33.793	32.222
Max	32.233	33.942	34.703	34.097
UL	90.000	90.000	90.000	90.000



NDD Report
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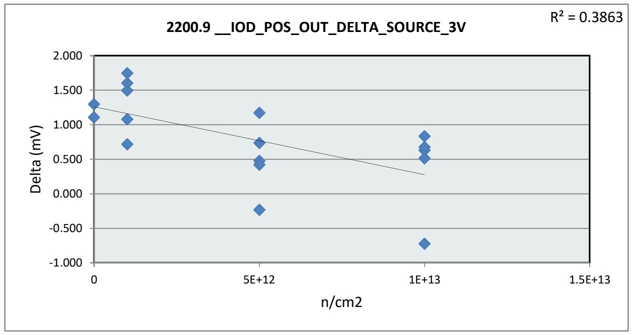
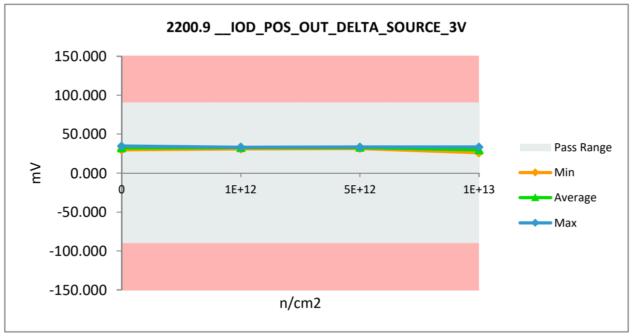
	2200.9 __IOD_POS_OUT_DELTA	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	mV	mV
Max Limit	90	90
Min Limit	-90	-90

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	30.727	29.619	1.108
0	106	35.859	34.563	1.296
1E+12	1	32.579	31.861	0.718
1E+12	2	34.525	32.778	1.747
1E+12	3	34.324	33.243	1.081
1E+12	4	32.494	30.998	1.497
1E+12	5	34.779	33.178	1.601
5E+12	13	33.285	33.520	-0.235
5E+12	14	32.091	31.615	0.476
5E+12	15	33.728	33.305	0.423
5E+12	16	33.564	32.826	0.737
5E+12	17	33.793	32.621	1.171
1E+13	6	28.252	27.620	0.632
1E+13	7	30.549	30.036	0.513
1E+13	9	33.972	33.295	0.678
1E+13	10	25.239	25.963	-0.724
1E+13	12	32.553	31.720	0.833
	Max	35.859	34.563	1.747
	Average	32.489	31.692	0.797
	Min	25.239	25.963	-0.724
	Std Dev	2.609	2.259	0.630



	2200.9 __IOD_POS_OUT_DELT	
Test Site	1	
Tester	ETS364	
Test Number	EF868301	
Max Limit	90	mV
Min Limit	-90	mV

n/cm2	0	1E+12	5E+12	1E+13
LL	-90.000	-90.000	-90.000	-90.000
Min	29.619	30.998	31.615	25.963
Average	32.091	32.412	32.778	29.727
Max	34.563	33.243	33.520	33.295
UL	90.000	90.000	90.000	90.000



NDD Report
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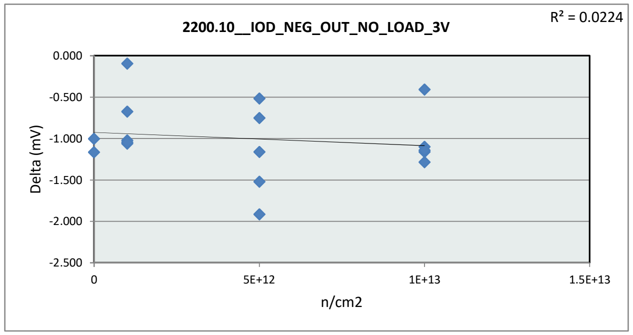
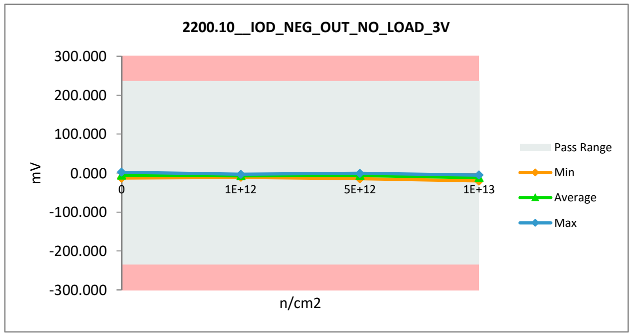
		2200.10__IOD_NEG_OUT_NO_L		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	235	235	
	Min Limit	-235	-235	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-14.540	-13.374	-1.166
0	106	1.188	2.191	-1.003
1E+12	1	-7.237	-6.177	-1.061
1E+12	2	-11.555	-10.878	-0.676
1E+12	3	-4.326	-3.303	-1.023
1E+12	4	-9.265	-8.219	-1.046
1E+12	5	-7.531	-7.437	-0.094
5E+12	13	-4.412	-2.891	-1.521
5E+12	14	-16.028	-14.868	-1.160
5E+12	15	-2.658	-0.743	-1.915
5E+12	16	-8.343	-7.590	-0.754
5E+12	17	-6.400	-5.883	-0.517
1E+13	6	-11.995	-10.895	-1.100
1E+13	7	-14.663	-13.503	-1.160
1E+13	9	-6.602	-5.315	-1.287
1E+13	10	-20.709	-20.302	-0.408
1E+13	12	-11.172	-10.030	-1.142
	Max	1.188	2.191	-0.094
	Average	-9.191	-8.189	-1.002
	Min	-20.709	-20.302	-1.915
	Std Dev	5.443	5.579	0.424



	2200.10__IOD_NEG_OUT_NO_			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	-13.374	-10.878	-14.868	-20.302
Average	-5.591	-7.203	-6.395	-12.009
Max	2.191	-3.304	-0.743	-5.315
UL	235.000	235.000	235.000	235.000



NDD Report
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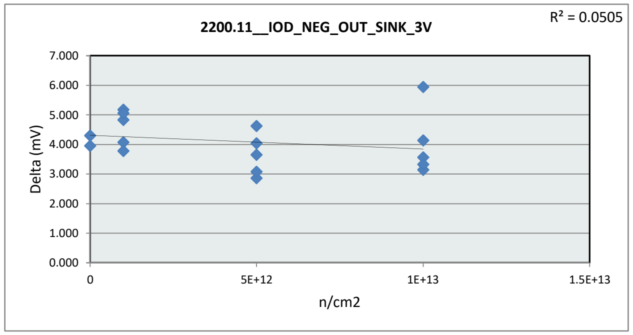
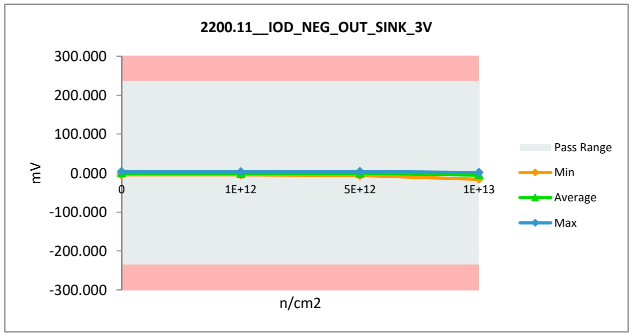
		2200.11__IOD_NEG_OUT_SINK_		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	235	235	
	Min Limit	-235	-235	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	-0.959	-4.914	3.955
0	106	8.478	4.183	4.294
1E+12	1	1.747	-2.327	4.074
1E+12	2	0.067	-5.109	5.175
1E+12	3	6.692	2.912	3.780
1E+12	4	3.691	-1.138	4.829
1E+12	5	3.679	-1.379	5.058
5E+12	13	4.135	1.269	2.866
5E+12	14	-3.507	-6.582	3.075
5E+12	15	7.942	4.294	3.648
5E+12	16	2.568	-1.469	4.037
5E+12	17	4.761	0.139	4.622
1E+13	6	1.020	-2.543	3.563
1E+13	7	-1.672	-4.815	3.144
1E+13	9	4.680	1.349	3.331
1E+13	10	-9.842	-15.783	5.941
1E+13	12	0.845	-3.293	4.138
	Max	8.478	4.294	5.941
	Average	2.019	-2.071	4.090
	Min	-9.842	-15.783	2.866
	Std Dev	4.497	4.802	0.829



	2200.11__IOD_NEG_OUT_SIN			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	-4.914	-5.109	-6.583	-15.784
Average	-0.365	-1.408	-0.470	-5.017
Max	4.184	2.912	4.294	1.349
UL	235.000	235.000	235.000	235.000



NDD Report
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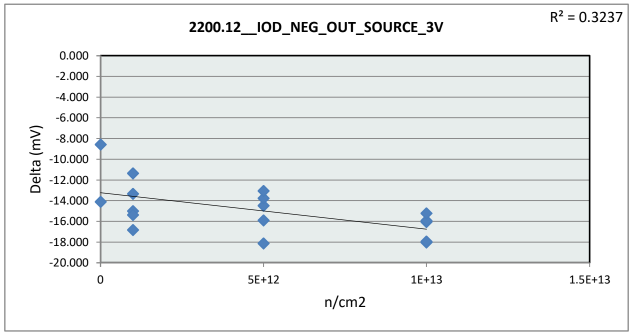
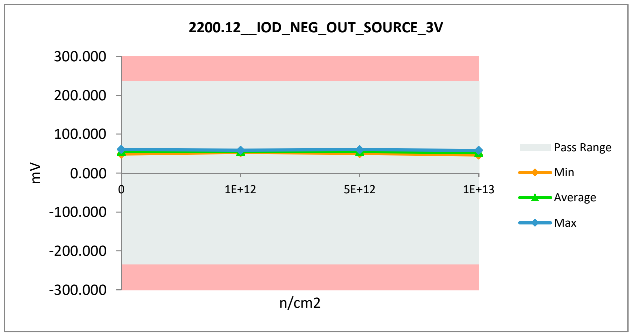
		2200.12__IOD_NEG_OUT_SOUR		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	235	235	
	Min Limit	-235	-235	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	34.597	48.696	-14.099
0	106	52.231	60.813	-8.583
1E+12	1	43.948	55.307	-11.359
1E+12	2	37.267	54.096	-16.829
1E+12	3	42.994	58.012	-15.018
1E+12	4	38.758	54.137	-15.379
1E+12	5	39.307	52.637	-13.330
5E+12	13	45.318	59.803	-14.485
5E+12	14	31.971	50.096	-18.125
5E+12	15	45.104	58.873	-13.770
5E+12	16	38.462	54.359	-15.897
5E+12	17	41.286	54.356	-13.070
1E+13	6	37.049	53.106	-16.057
1E+13	7	33.133	51.178	-18.046
1E+13	9	42.056	58.005	-15.950
1E+13	10	28.113	46.048	-17.935
1E+13	12	37.903	53.115	-15.212
	Max	52.231	60.813	-8.583
	Average	39.382	54.273	-14.891
	Min	28.113	46.048	-18.125
	Std Dev	5.782	3.990	2.467



	2200.12__IOD_NEG_OUT_SOU			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	235	mV		
Min Limit	-235	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-235.000	-235.000	-235.000	-235.000
Min	48.696	52.637	50.096	46.048
Average	54.755	54.838	55.497	52.291
Max	60.813	58.012	59.803	58.005
UL	235.000	235.000	235.000	235.000



NDD Report
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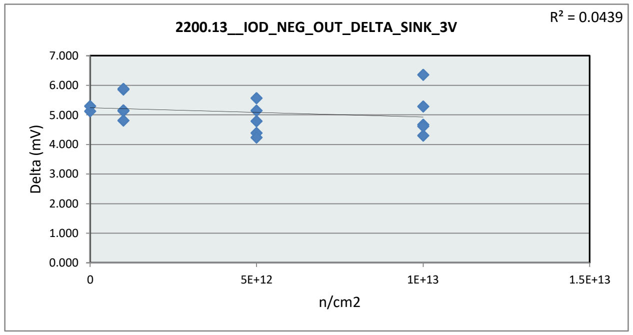
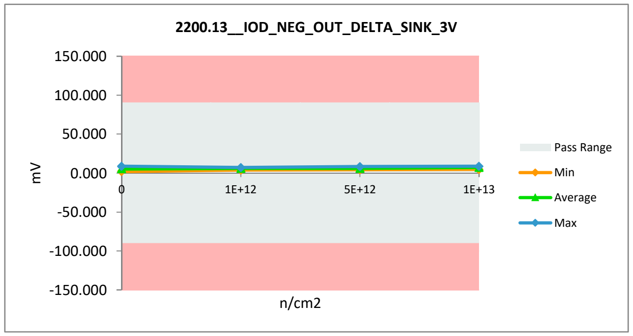
		2200.13__IOD_NEG_OUT_DELTA		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	90	90	
	Min Limit	-90	-90	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	13.580	8.460	5.121
0	106	7.290	1.992	5.298
1E+12	1	8.984	3.849	5.135
1E+12	2	11.621	5.770	5.852
1E+12	3	11.018	6.215	4.802
1E+12	4	12.956	7.081	5.875
1E+12	5	11.210	6.057	5.153
5E+12	13	8.547	4.160	4.387
5E+12	14	12.521	8.285	4.235
5E+12	15	10.600	5.037	5.563
5E+12	16	10.911	6.120	4.791
5E+12	17	11.161	6.022	5.139
1E+13	6	13.015	8.352	4.663
1E+13	7	12.991	8.688	4.304
1E+13	9	11.281	6.664	4.618
1E+13	10	10.867	4.518	6.349
1E+13	12	12.017	6.737	5.279
	Max	13.580	8.688	6.349
	Average	11.210	6.118	5.092
	Min	7.290	1.992	4.235
	Std Dev	1.690	1.824	0.587



	2200.13__IOD_NEG_OUT_DEL			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	90	mV		
Min Limit	-90	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-90.000	-90.000	-90.000	-90.000
Min	1.993	3.850	4.160	4.518
Average	5.226	5.795	5.925	6.992
Max	8.460	7.081	8.285	8.688
UL	90.000	90.000	90.000	90.000



NDD Report
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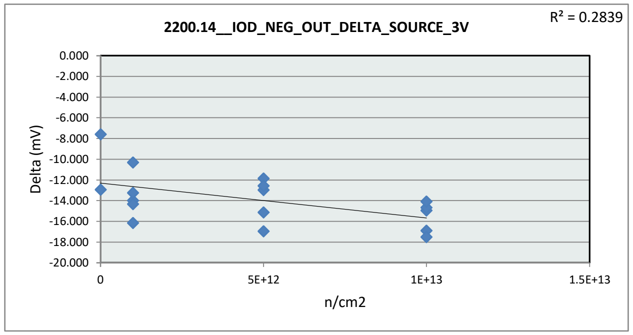
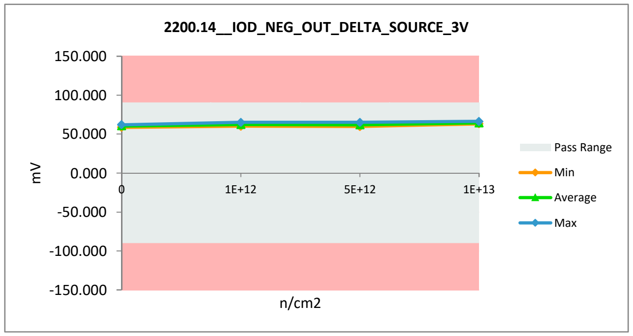
		2200.14__IOD_NEG_OUT_DELTA		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	90	90	
	Min Limit	-90	-90	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	49.137	62.070	-12.933
0	106	51.043	58.622	-7.579
1E+12	1	51.186	61.484	-10.299
1E+12	2	48.822	64.974	-16.153
1E+12	3	47.320	61.315	-13.995
1E+12	4	48.023	62.356	-14.333
1E+12	5	46.839	60.074	-13.236
5E+12	13	49.730	62.694	-12.964
5E+12	14	47.999	64.963	-16.964
5E+12	15	47.761	59.616	-11.854
5E+12	16	46.805	61.949	-15.144
5E+12	17	47.686	60.239	-12.553
1E+13	6	49.045	64.002	-14.957
1E+13	7	47.796	64.681	-16.886
1E+13	9	48.657	63.320	-14.663
1E+13	10	48.822	66.349	-17.527
1E+13	12	49.075	63.145	-14.070
	Max	51.186	66.349	-7.579
	Average	48.573	62.462	-13.889
	Min	46.805	58.622	-17.527
	Std Dev	1.264	2.128	2.515



	2200.14__IOD_NEG_OUT_DEL			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	90	mV		
Min Limit	-90	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-90.000	-90.000	-90.000	-90.000
Min	58.622	60.074	59.616	63.145
Average	60.346	62.041	61.892	64.299
Max	62.070	64.974	64.963	66.349
UL	90.000	90.000	90.000	90.000



NDD Report
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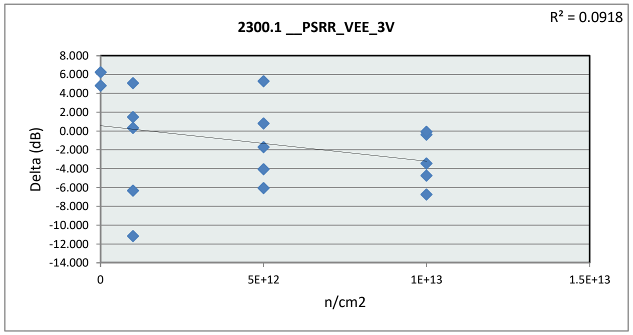
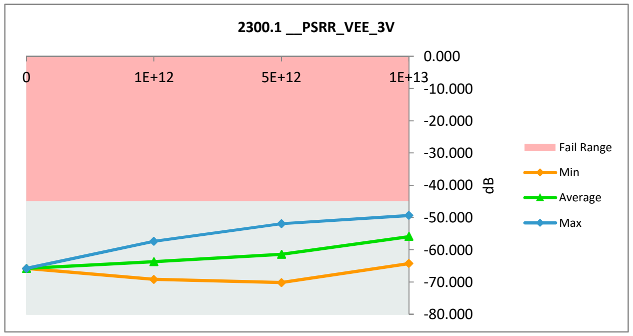
	2300.1 __PSRR_VEE_3V	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	dB	dB
Max Limit	-45	-45
Min Limit		

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-61.001	-65.825	4.824
0	106	-59.588	-65.823	6.234
1E+12	1	-63.773	-57.445	-6.328
1E+12	2	-58.431	-63.508	5.077
1E+12	3	-60.539	-62.038	1.499
1E+12	4	-68.873	-69.198	0.325
1E+12	5	-78.043	-66.872	-11.171
5E+12	13	-55.223	-53.504	-1.719
5E+12	14	-55.982	-51.926	-4.056
5E+12	15	-62.477	-67.768	5.291
5E+12	16	-63.443	-64.243	0.800
5E+12	17	-76.284	-70.233	-6.051
1E+13	6	-54.289	-50.853	-3.436
1E+13	7	-55.829	-51.105	-4.723
1E+13	9	-64.712	-64.311	-0.401
1E+13	10	-56.109	-49.384	-6.726
1E+13	12	-64.166	-64.091	-0.075
	Max	-54.289	-49.384	6.234
	Average	-62.280	-61.066	-1.214
	Min	-78.043	-70.233	-11.171
	Std Dev	6.896	7.091	4.964



	2300.1 __PSRR_VEE_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-45	dB		
Min Limit		dB		
n/cm2	0	1E+12	5E+12	1E+13
LL				
Min	-65.825	-69.198	-70.233	-64.311
Average	-65.824	-63.812	-61.535	-55.949
Max	-65.823	-57.445	-51.927	-49.384
UL	-45.000	-45.000	-45.000	-45.000



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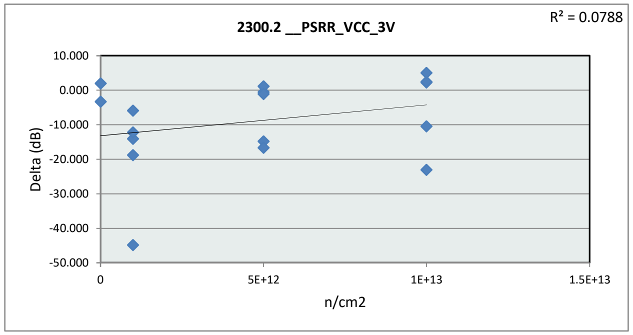
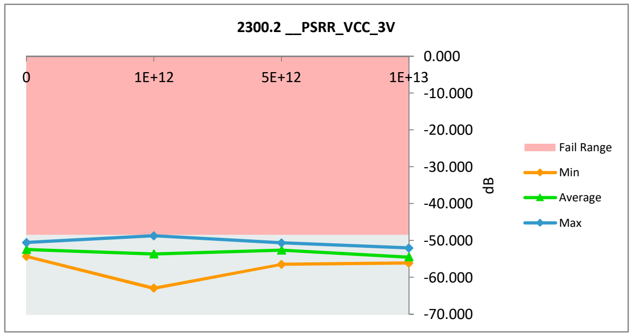
		2300.2 __PSRR_VCC_3V		
Test Site		1	1	
Tester		ETS364	ETS364	
Test Number		EF868301	EF868301	
Unit		dB	dB	
Max Limit		-48.5	-48.5	
Min Limit				
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	-48.608	-50.583	1.975
0	106	-57.674	-54.339	-3.335
1E+12	1	-99.752	-54.939	-44.813
1E+12	2	-65.607	-51.574	-14.033
1E+12	3	-61.025	-48.757	-12.269
1E+12	4	-68.875	-62.972	-5.903
1E+12	5	-69.318	-50.521	-18.797
5E+12	13	-57.022	-56.506	-0.516
5E+12	14	-51.258	-52.354	1.097
5E+12	15	-51.819	-50.702	-1.117
5E+12	16	-65.649	-50.805	-14.844
5E+12	17	-69.869	-53.178	-16.691
1E+13	6	-53.972	-56.185	2.213
1E+13	7	-51.270	-53.701	2.431
1E+13	9	-62.463	-52.048	-10.415
1E+13	10	-49.823	-54.829	5.006
1E+13	12	-78.867	-55.825	-23.043
	Max	-48.608	-48.757	5.006
	Average	-62.522	-53.519	-9.003
	Min	-99.752	-62.972	-44.813
	Std Dev	12.906	3.337	12.644



	2300.2 __PSRR_VCC_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-48.5	dB		
Min Limit		dB		
n/cm2	0	1E+12	5E+12	1E+13
LL				
Min	-54.339	-62.972	-56.506	-56.185
Average	-52.461	-53.752	-52.709	-54.518
Max	-50.583	-48.757	-50.702	-52.048
UL	-48.500	-48.500	-48.500	-48.500



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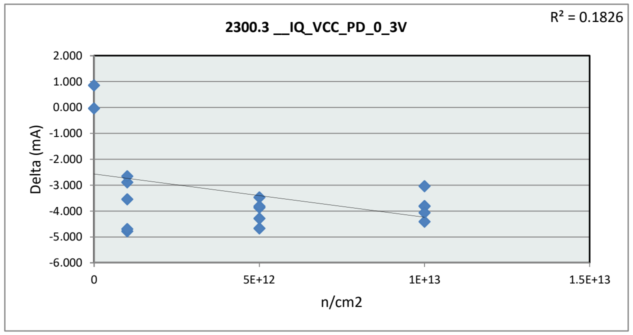
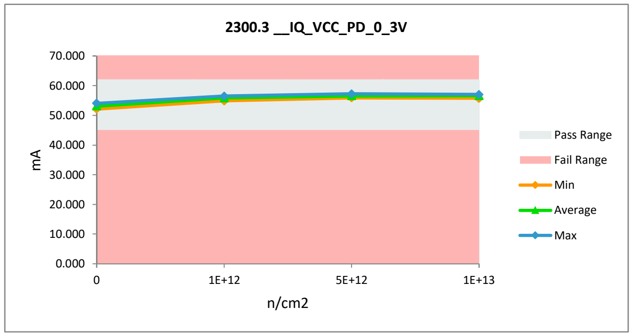
		2300.3 __IQ_VCC_PD_0_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	62	62	
	Min Limit	45	45	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	53.009	52.152	0.857
0	106	54.033	54.067	-0.033
1E+12	1	50.022	54.808	-4.786
1E+12	2	50.709	55.406	-4.697
1E+12	3	53.536	56.432	-2.896
1E+12	4	53.548	56.206	-2.658
1E+12	5	52.666	56.208	-3.542
5E+12	13	52.445	55.921	-3.475
5E+12	14	52.694	56.565	-3.871
5E+12	15	53.426	57.246	-3.821
5E+12	16	51.689	56.359	-4.670
5E+12	17	52.500	56.785	-4.286
1E+13	6	52.667	55.707	-3.040
1E+13	7	52.565	56.974	-4.409
1E+13	9	52.857	56.659	-3.802
1E+13	10	53.100	56.924	-3.824
1E+13	12	52.389	56.451	-4.062
	Max	54.033	57.246	0.857
	Average	52.580	55.934	-3.354
	Min	50.022	52.152	-4.786
	Std Dev	1.004	1.267	1.553



	2300.3 __IQ_VCC_PD_0_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	62	mA		
Min Limit	45	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	45.000	45.000	45.000	45.000
Min	52.152	54.808	55.921	55.707
Average	53.109	55.812	56.575	56.543
Max	54.067	56.432	57.246	56.974
UL	62.000	62.000	62.000	62.000



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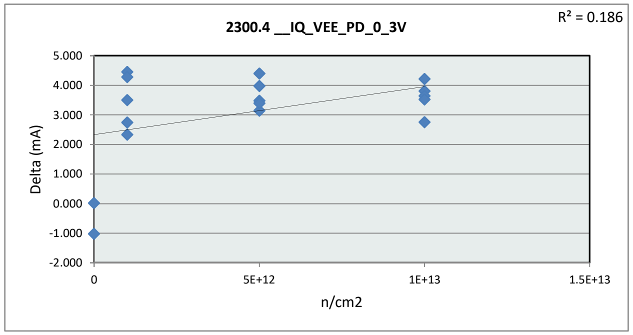
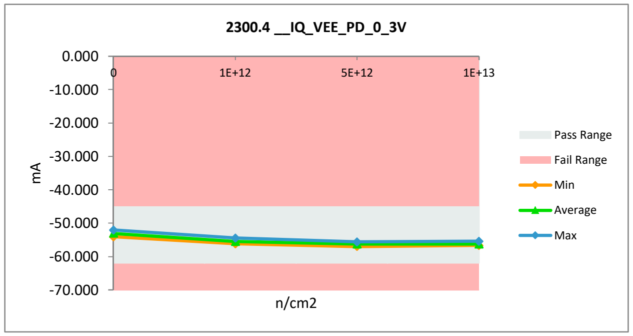
		2300.4 __IQ_VEE_PD_0_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	-45	-45	
	Min Limit	-62	-62	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-53.105	-52.081	-1.024
0	106	-54.043	-54.056	0.013
1E+12	1	-50.038	-54.494	4.456
1E+12	2	-50.852	-55.125	4.274
1E+12	3	-53.433	-56.172	2.738
1E+12	4	-53.626	-55.956	2.330
1E+12	5	-52.447	-55.945	3.499
5E+12	13	-52.476	-55.617	3.141
5E+12	14	-52.757	-56.233	3.476
5E+12	15	-53.585	-56.981	3.396
5E+12	16	-51.714	-56.111	4.397
5E+12	17	-52.577	-56.549	3.972
1E+13	6	-52.653	-55.411	2.758
1E+13	7	-52.491	-56.702	4.211
1E+13	9	-52.619	-56.419	3.800
1E+13	10	-53.012	-56.650	3.638
1E+13	12	-52.698	-56.217	3.520
	Max	-50.038	-52.081	4.456
	Average	-52.596	-55.689	3.094
	Min	-54.043	-56.981	-1.024
	Std Dev	0.991	1.213	1.492



	2300.4 __IQ_VEE_PD_0_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-45	mA		
Min Limit	-62	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-62.000	-62.000	-62.000	-62.000
Min	-54.056	-56.172	-56.981	-56.702
Average	-53.069	-55.538	-56.298	-56.280
Max	-52.081	-54.494	-55.617	-55.411
UL	-45.000	-45.000	-45.000	-45.000



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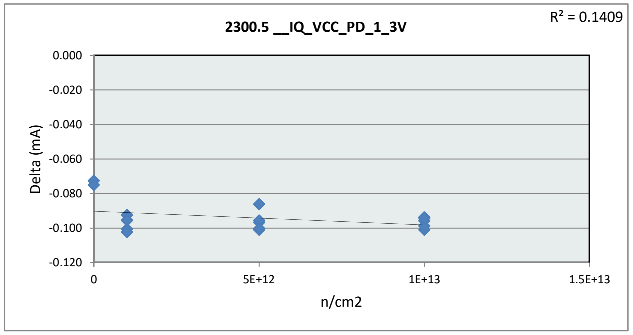
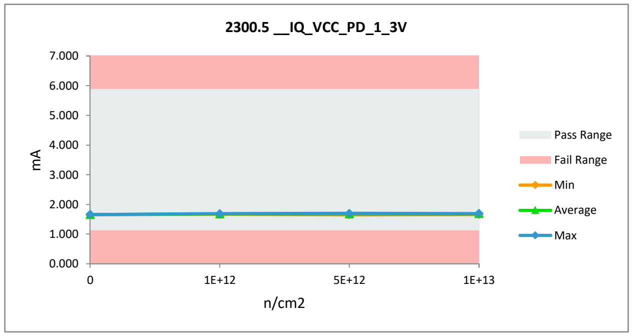
		2300.5 __IQ_VCC_PD_1_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	5.875	5.875	
	Min Limit	1.125	1.125	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.581	1.654	-0.073
0	106	1.583	1.658	-0.075
1E+12	1	1.576	1.668	-0.092
1E+12	2	1.570	1.665	-0.095
1E+12	3	1.585	1.685	-0.101
1E+12	4	1.577	1.679	-0.102
1E+12	5	1.563	1.658	-0.096
5E+12	13	1.585	1.686	-0.101
5E+12	14	1.594	1.691	-0.097
5E+12	15	1.570	1.665	-0.096
5E+12	16	1.570	1.670	-0.100
5E+12	17	1.565	1.651	-0.086
1E+13	6	1.588	1.684	-0.096
1E+13	7	1.595	1.688	-0.094
1E+13	9	1.591	1.692	-0.101
1E+13	10	1.594	1.693	-0.099
1E+13	12	1.568	1.662	-0.094
	Max	1.595	1.693	-0.073
	Average	1.580	1.674	-0.094
	Min	1.563	1.651	-0.102
	Std Dev	0.011	0.014	0.009



	2300.5 __IQ_VCC_PD_1_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	5.875	mA		
Min Limit	1.125	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	1.125	1.125	1.125	1.125
Min	1.654	1.659	1.651	1.662
Average	1.656	1.671	1.673	1.684
Max	1.658	1.685	1.691	1.693
UL	5.875	5.875	5.875	5.875



NDD Report
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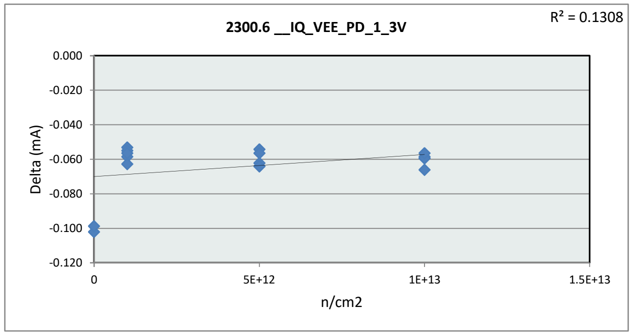
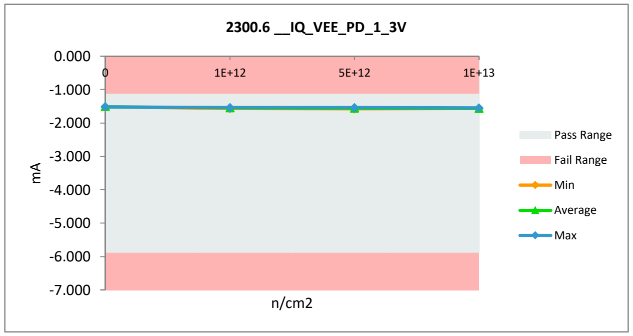
		2300.6 __IQ_VEE_PD_1_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	-1.125	-1.125	
	Min Limit	-5.875	-5.875	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-1.620	-1.518	-0.102
0	106	-1.617	-1.519	-0.099
1E+12	1	-1.607	-1.554	-0.053
1E+12	2	-1.608	-1.553	-0.055
1E+12	3	-1.626	-1.567	-0.058
1E+12	4	-1.620	-1.564	-0.056
1E+12	5	-1.606	-1.543	-0.063
5E+12	13	-1.630	-1.568	-0.062
5E+12	14	-1.631	-1.577	-0.054
5E+12	15	-1.610	-1.553	-0.056
5E+12	16	-1.612	-1.548	-0.064
5E+12	17	-1.605	-1.541	-0.064
1E+13	6	-1.630	-1.564	-0.066
1E+13	7	-1.632	-1.574	-0.059
1E+13	9	-1.633	-1.573	-0.059
1E+13	10	-1.634	-1.575	-0.059
1E+13	12	-1.606	-1.550	-0.056
	Max	-1.605	-1.518	-0.053
	Average	-1.619	-1.555	-0.064
	Min	-1.634	-1.577	-0.102
	Std Dev	0.011	0.018	0.014



	2300.6 __IQ_VEE_PD_1_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	-1.125	mA		
Min Limit	-5.875	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-5.875	-5.875	-5.875	-5.875
Min	-1.519	-1.567	-1.577	-1.575
Average	-1.518	-1.556	-1.557	-1.567
Max	-1.518	-1.543	-1.541	-1.550
UL	-1.125	-1.125	-1.125	-1.125



NDD Report
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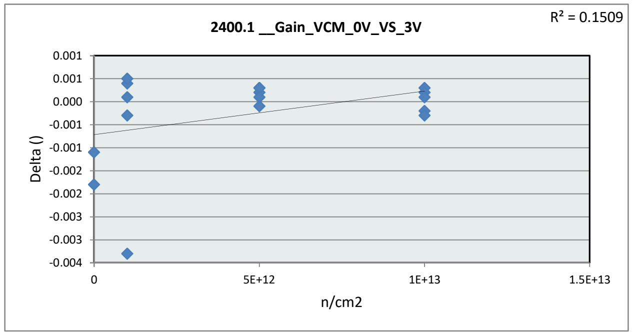
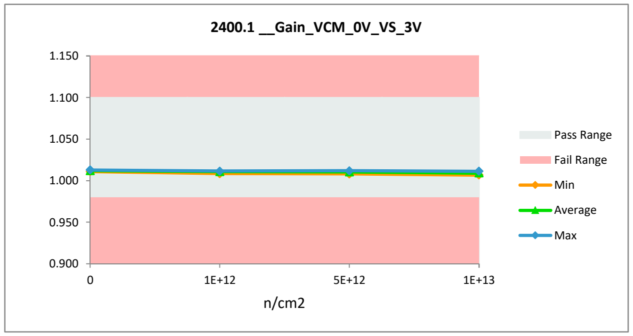
		2400.1 __Gain_VCM_0V_VS_3V		
Test Site		1	1	
Tester		ETS364	ETS364	
Test Number		EF868301	EF868301	
Unit		dB	dB	
Max Limit		1.1	1.1	
Min Limit		0.98	0.98	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.009	1.011	-0.002
0	106	1.012	1.013	-0.001
1E+12	1	1.008	1.011	-0.003
1E+12	2	1.008	1.008	0.000
1E+12	3	1.012	1.012	0.000
1E+12	4	1.011	1.010	0.000
1E+12	5	1.011	1.011	0.000
5E+12	13	1.011	1.011	0.000
5E+12	14	1.008	1.008	0.000
5E+12	15	1.012	1.012	0.000
5E+12	16	1.011	1.011	0.000
5E+12	17	1.010	1.010	0.000
1E+13	6	1.007	1.007	0.000
1E+13	7	1.009	1.009	0.000
1E+13	9	1.012	1.011	0.000
1E+13	10	1.007	1.007	0.000
1E+13	12	1.011	1.011	0.000
	Max	1.012	1.013	0.000
	Average	1.010	1.010	0.000
	Min	1.007	1.007	-0.003
	Std Dev	0.002	0.002	0.001

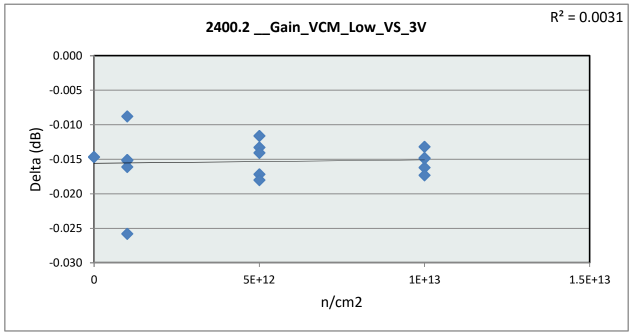


	2400.1 __Gain_VCM_0V_VS_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.1			
Min Limit	0.98			
n/cm2	0	1E+12	5E+12	1E+13
LL	0.980	0.980	0.980	0.980
Min	1.011	1.009	1.008	1.007
Average	1.012	1.011	1.010	1.009
Max	1.013	1.012	1.012	1.011
UL	1.100	1.100	1.100	1.100

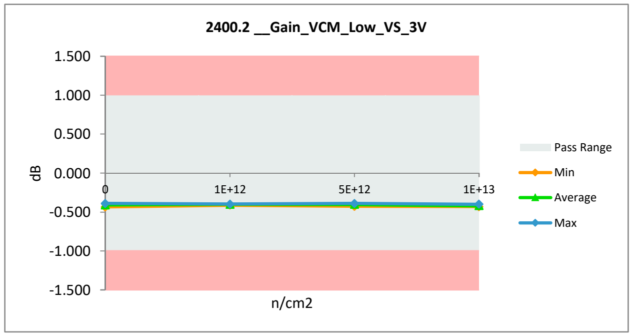


NDD Report
LMH5401-SP

		2400.2 __Gain_VCM_Low_VS_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	dB	dB	
	Max Limit	0.99	0.99	
	Min Limit	-0.99	-0.99	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	-0.449	-0.434	-0.015
0	106	-0.405	-0.391	-0.015
1E+12	1	-0.414	-0.399	-0.015
1E+12	2	-0.419	-0.404	-0.015
1E+12	3	-0.428	-0.412	-0.016
1E+12	4	-0.430	-0.404	-0.026
1E+12	5	-0.409	-0.400	-0.009
5E+12	13	-0.416	-0.403	-0.013
5E+12	14	-0.444	-0.427	-0.017
5E+12	15	-0.409	-0.391	-0.018
5E+12	16	-0.416	-0.402	-0.014
5E+12	17	-0.405	-0.394	-0.012
1E+13	6	-0.436	-0.421	-0.015
1E+13	7	-0.447	-0.430	-0.016
1E+13	9	-0.433	-0.415	-0.017
1E+13	10	-0.446	-0.433	-0.013
1E+13	12	-0.414	-0.399	-0.015
	Max	-0.405	-0.391	-0.009
	Average	-0.425	-0.409	-0.015
	Min	-0.449	-0.434	-0.026
	Std Dev	0.015	0.015	0.003

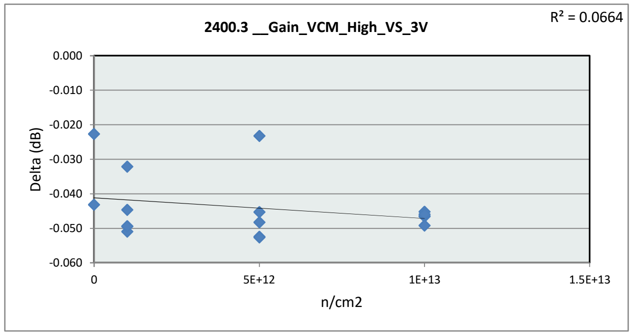


	2400.2 __Gain_VCM_Low_VS_			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	0.99	dB		
Min Limit	-0.99	dB		
n/cm2	0	1E+12	5E+12	1E+13
LL	-0.990	-0.990	-0.990	-0.990
Min	-0.434	-0.412	-0.427	-0.433
Average	-0.412	-0.404	-0.403	-0.420
Max	-0.391	-0.399	-0.391	-0.399
UL	0.990	0.990	0.990	0.990

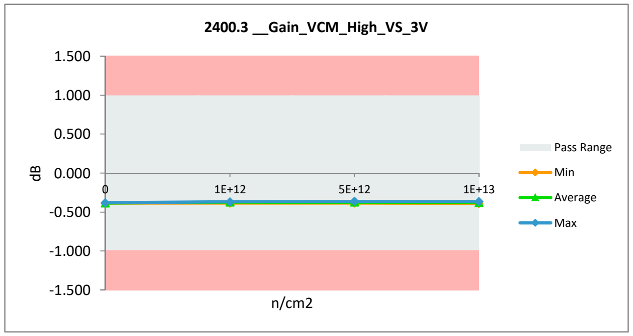


NDD Report
LMH5401-SP

		2400.3 __Gain_VCM_High_VS_3		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	dB	dB	
	Max Limit	0.99	0.99	
	Min Limit	-0.99	-0.99	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-0.431	-0.388	-0.043
0	106	-0.404	-0.382	-0.023
1E+12	1	-0.407	-0.375	-0.032
1E+12	2	-0.422	-0.373	-0.049
1E+12	3	-0.430	-0.385	-0.045
1E+12	4	-0.426	-0.375	-0.051
1E+12	5	-0.418	-0.368	-0.049
5E+12	13	-0.410	-0.387	-0.023
5E+12	14	-0.428	-0.383	-0.045
5E+12	15	-0.421	-0.369	-0.052
5E+12	16	-0.421	-0.373	-0.048
5E+12	17	-0.416	-0.363	-0.053
1E+13	6	-0.435	-0.390	-0.045
1E+13	7	-0.434	-0.388	-0.047
1E+13	9	-0.432	-0.385	-0.046
1E+13	10	-0.437	-0.388	-0.049
1E+13	12	-0.412	-0.366	-0.046
	Max	-0.404	-0.363	-0.023
	Average	-0.423	-0.379	-0.044
	Min	-0.437	-0.390	-0.053
	Std Dev	0.010	0.009	0.009

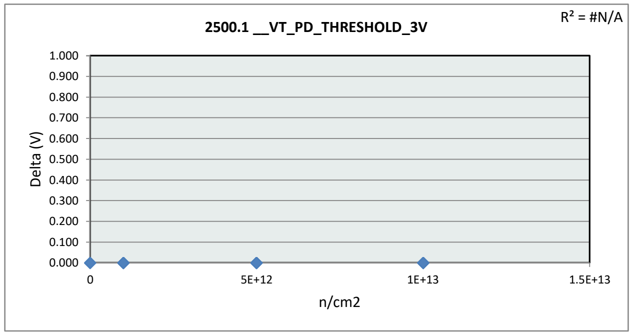


	2400.3 __Gain_VCM_High_VS			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	0.99	dB		
Min Limit	-0.99	dB		
n/cm2	0	1E+12	5E+12	1E+13
LL	-0.990	-0.990	-0.990	-0.990
Min	-0.388	-0.385	-0.387	-0.390
Average	-0.385	-0.375	-0.375	-0.383
Max	-0.382	-0.368	-0.363	-0.366
UL	0.990	0.990	0.990	0.990

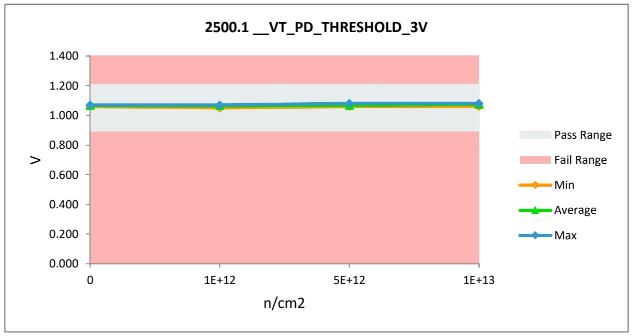


NDD Report
LMH5401-SP

		2500.1 __VT_PD_THRESHOLD_3		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	V	V	
	Max Limit	1.21	1.21	
	Min Limit	0.89	0.89	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.060	1.060	0.000
0	106	1.070	1.070	0.000
1E+12	1	1.050	1.050	0.000
1E+12	2	1.070	1.070	0.000
1E+12	3	1.070	1.070	0.000
1E+12	4	1.070	1.070	0.000
1E+12	5	1.060	1.060	0.000
5E+12	13	1.070	1.070	0.000
5E+12	14	1.080	1.080	0.000
5E+12	15	1.070	1.070	0.000
5E+12	16	1.060	1.060	0.000
5E+12	17	1.060	1.060	0.000
1E+13	6	1.080	1.080	0.000
1E+13	7	1.080	1.080	0.000
1E+13	9	1.070	1.070	0.000
1E+13	10	1.080	1.080	0.000
1E+13	12	1.060	1.060	0.000
	Max	1.080	1.080	0.000
	Average	1.068	1.068	0.000
	Min	1.050	1.050	0.000
	Std Dev	0.009	0.009	0.000

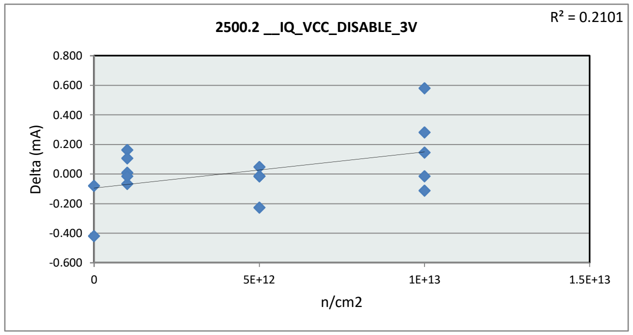


	2500.1 __VT_PD_THRESHOLD			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.21	V		
Min Limit	0.89	V		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.890	0.890	0.890	0.890
Min	1.060	1.050	1.060	1.060
Average	1.065	1.064	1.068	1.074
Max	1.070	1.070	1.080	1.080
UL	1.210	1.210	1.210	1.210

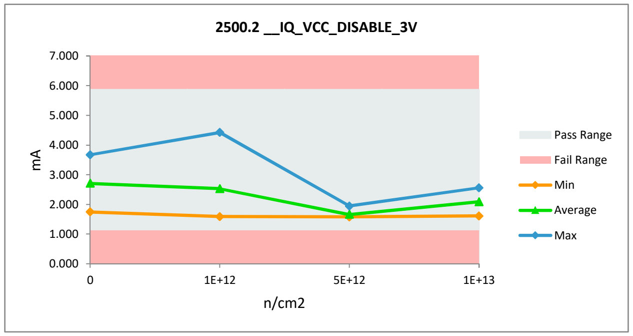


NDD Report
LMH5401-SP

		2500.2 __IQ_VCC_DISABLE_3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	5.875	5.875	
	Min Limit	1.125	1.125	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	3.252	3.670	-0.418
0	106	1.666	1.744	-0.079
1E+12	1	4.588	4.425	0.163
1E+12	2	1.595	1.586	0.010
1E+12	3	2.223	2.290	-0.068
1E+12	4	1.582	1.597	-0.016
1E+12	5	2.835	2.728	0.107
5E+12	13	1.721	1.948	-0.227
5E+12	14	1.594	1.609	-0.015
5E+12	15	1.573	1.587	-0.014
5E+12	16	1.572	1.586	-0.015
5E+12	17	1.624	1.577	0.047
1E+13	6	2.449	2.561	-0.113
1E+13	7	2.835	2.255	0.580
1E+13	9	2.356	2.211	0.146
1E+13	10	1.595	1.610	-0.015
1E+13	12	2.077	1.797	0.280
	Max	4.588	4.425	0.580
	Average	2.184	2.164	0.021
	Min	1.572	1.577	-0.418
	Std Dev	0.823	0.811	0.212

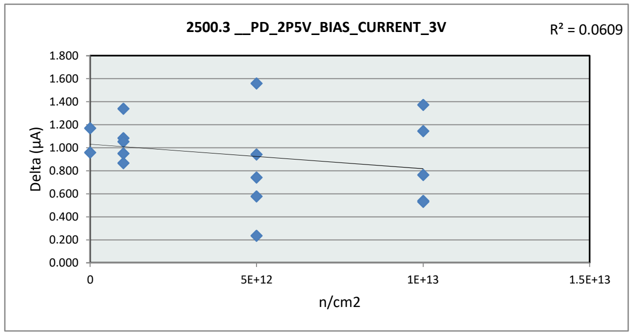


	2500.2 __IQ_VCC_DISABLE_3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	5.875	mA		
Min Limit	1.125	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	1.125	1.125	1.125	1.125
Min	1.744	1.586	1.577	1.610
Average	2.707	2.525	1.662	2.087
Max	3.670	4.425	1.948	2.561
UL	5.875	5.875	5.875	5.875

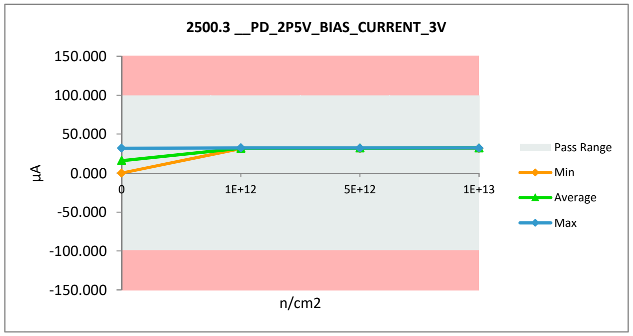


NDD Report
LMH5401-SP

		2500.3 __PD_2P5V_BIAS_CURR		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	µA	µA	
	Max Limit	99	99	
	Min Limit	-99	-99	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	33.078	32.120	0.958
0	106	33.047	31.878	1.168
1E+12	1	32.782	31.699	1.083
1E+12	2	32.455	31.590	0.865
1E+12	3	33.101	31.761	1.340
1E+12	4	33.296	32.346	0.950
1E+12	5	32.759	31.707	1.052
5E+12	13	32.953	32.011	0.943
5E+12	14	32.782	32.206	0.577
5E+12	15	32.689	31.948	0.740
5E+12	16	32.502	32.268	0.234
5E+12	17	32.946	31.387	1.558
1E+13	6	32.556	32.019	0.538
1E+13	7	32.751	32.221	0.530
1E+13	9	32.969	32.206	0.763
1E+13	10	33.132	31.761	1.371
1E+13	12	32.728	31.582	1.145
	Max	33.296	32.346	1.558
	Average	32.854	31.924	0.930
	Min	32.455	31.387	0.234
	Std Dev	0.237	0.281	0.344

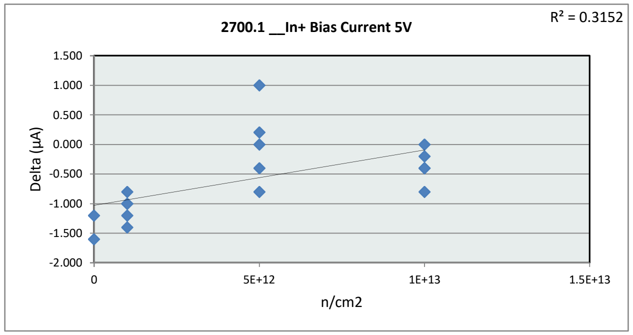


	2500.3 __PD_2P5V_BIAS_CUR			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	99	µA		
Min Limit	-99	µA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-99.000	-99.000	-99.000	-99.000
Min	0.000	31.590	31.387	31.582
Average	15.939	31.821	31.964	31.958
Max	31.878	32.346	32.268	32.221
UL	99.000	99.000	99.000	99.000

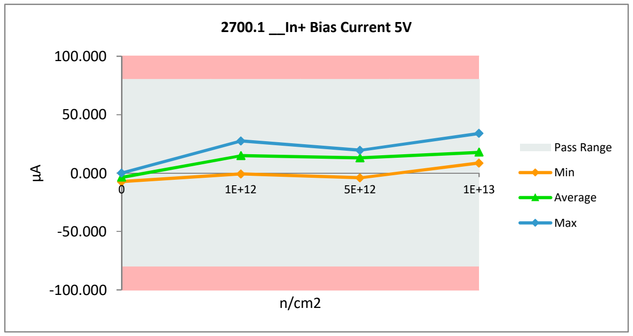


NDD Report
LMH5401-SP

		2700.1 __In+ Bias Current 5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	µA	µA	
	Max Limit	80	80	
	Min Limit	-80	-80	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	16.921	18.523	-1.602
0	106	-8.511	-7.309	-1.202
1E+12	1	-1.702	-0.701	-1.001
1E+12	2	26.333	27.534	-1.201
1E+12	3	6.708	7.509	-0.801
1E+12	4	16.921	17.922	-1.001
1E+12	5	19.725	21.126	-1.401
5E+12	13	-3.104	-4.105	1.001
5E+12	14	19.324	19.324	0.000
5E+12	15	11.715	11.514	0.201
5E+12	16	19.124	19.524	-0.400
5E+12	17	17.722	18.523	-0.801
1E+13	6	12.916	13.317	-0.401
1E+13	7	17.922	17.922	0.000
1E+13	9	8.310	8.511	-0.201
1E+13	10	33.141	33.942	-0.801
1E+13	12	14.518	14.919	-0.401
	Max	33.141	33.942	1.001
	Average	13.411	14.000	-0.589
	Min	-8.511	-7.309	-1.602
	Std Dev	10.560	10.724	0.662

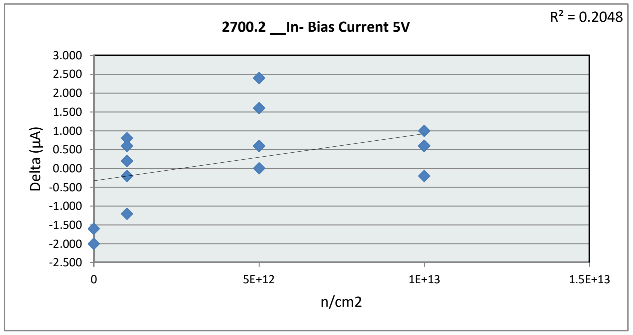


	2700.1 __In+ Bias Current 5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	80	µA		
Min Limit	-80	µA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-80.000	-80.000	-80.000	-80.000
Min	-7.309	-0.701	-4.105	8.511
Average	-3.654	14.678	12.956	17.722
Max	0.000	27.534	19.524	33.942
UL	80.000	80.000	80.000	80.000

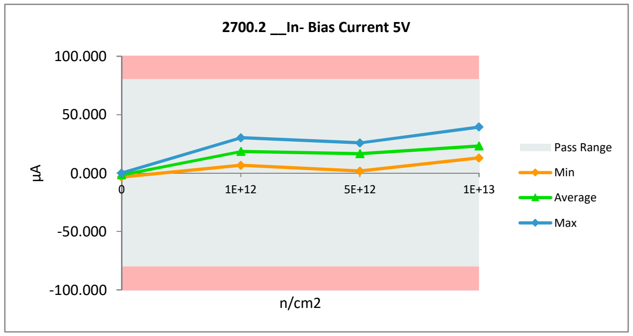


NDD Report
LMH5401-SP

		2700.2 __In- Bias Current 5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	µA	µA	
	Max Limit	80	80	
	Min Limit	-80	-80	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	24.330	26.333	-2.003
0	106	-4.906	-3.304	-1.602
1E+12	1	6.308	6.508	-0.200
1E+12	2	30.338	30.138	0.200
1E+12	3	11.715	10.914	0.801
1E+12	4	21.527	20.926	0.601
1E+12	5	22.528	23.730	-1.202
5E+12	13	4.105	1.702	2.403
5E+12	14	26.333	25.732	0.601
5E+12	15	13.517	11.915	1.602
5E+12	16	21.927	21.327	0.600
5E+12	17	20.926	20.926	0.000
1E+13	6	19.324	18.723	0.601
1E+13	7	25.932	25.332	0.600
1E+13	9	13.517	12.916	0.601
1E+13	10	39.149	39.349	-0.200
1E+13	12	20.325	19.324	1.001
	Max	39.149	39.349	2.403
	Average	18.641	18.382	0.259
	Min	-4.906	-3.304	-2.003
	Std Dev	10.498	10.641	1.094

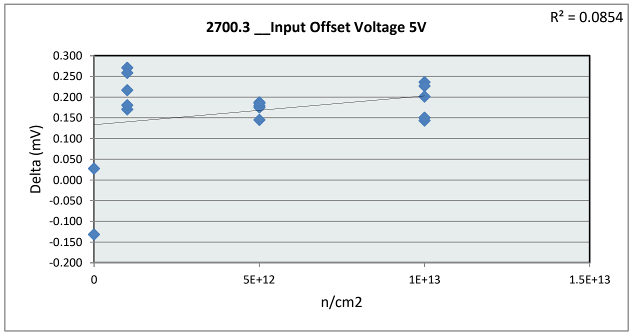


	2700.2 __In- Bias Current 5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	80	µA		
Min Limit	-80	µA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-80.000	-80.000	-80.000	-80.000
Min	-3.304	6.508	1.702	12.916
Average	-1.652	18.443	16.320	23.129
Max	0.000	30.138	25.732	39.349
UL	80.000	80.000	80.000	80.000

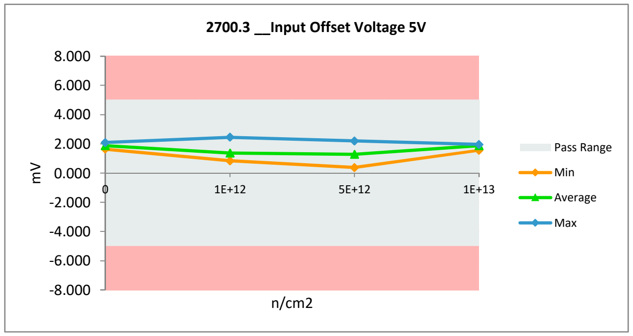


NDD Report
LMH5401-SP

		2700.3 __Input Offset Voltage 5		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	5	5	
	Min Limit	-5	-5	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.957	2.089	-0.132
0	106	1.670	1.643	0.027
1E+12	1	2.720	2.450	0.271
1E+12	2	1.179	0.961	0.217
1E+12	3	1.571	1.312	0.259
1E+12	4	1.403	1.233	0.170
1E+12	5	1.015	0.835	0.180
5E+12	13	2.181	2.002	0.179
5E+12	14	2.376	2.202	0.175
5E+12	15	0.562	0.375	0.187
5E+12	16	1.201	1.056	0.145
5E+12	17	0.923	0.738	0.185
1E+13	6	2.094	1.892	0.202
1E+13	7	2.078	1.934	0.143
1E+13	9	1.793	1.557	0.236
1E+13	10	2.179	1.952	0.227
1E+13	12	2.107	1.957	0.150
	Max	2.720	2.450	0.271
	Average	1.706	1.540	0.166
	Min	0.562	0.375	-0.132
	Std Dev	0.586	0.593	0.094

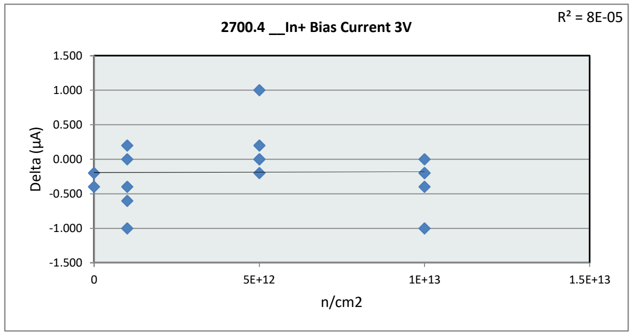


	2700.3 __Input Offset Voltage			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	5	mV		
Min Limit	-5	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-5.000	-5.000	-5.000	-5.000
Min	1.643	0.835	0.375	1.557
Average	1.866	1.358	1.274	1.858
Max	2.089	2.450	2.202	1.957
UL	5.000	5.000	5.000	5.000

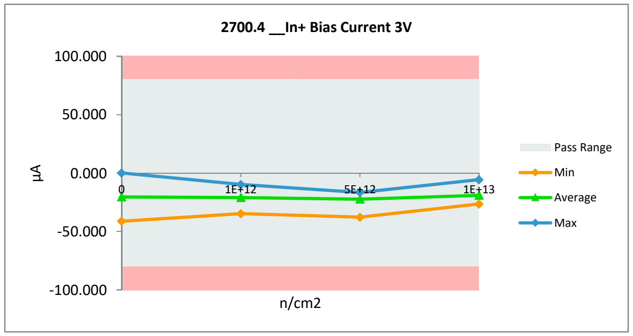


NDD Report
LMH5401-SP

		2700.4 __In+ Bias Current 3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	µA	µA	
	Max Limit	80	80	
	Min Limit	-80	-80	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-19.324	-18.924	-0.400
0	106	-41.352	-41.151	-0.201
1E+12	1	-34.944	-34.944	0.000
1E+12	2	-10.513	-9.912	-0.601
1E+12	3	-27.935	-28.135	0.200
1E+12	4	-18.723	-18.323	-0.400
1E+12	5	-15.319	-14.318	-1.001
5E+12	13	-36.946	-37.947	1.001
5E+12	14	-18.523	-18.323	-0.200
5E+12	15	-22.728	-22.728	0.000
5E+12	16	-16.521	-16.521	0.000
5E+12	17	-16.721	-16.921	0.200
1E+13	6	-23.930	-23.730	-0.200
1E+13	7	-19.324	-19.124	-0.200
1E+13	9	-26.533	-26.533	0.000
1E+13	10	-6.708	-5.707	-1.001
1E+13	12	-20.726	-20.325	-0.401
	Max	-6.708	-5.707	1.001
	Average	-22.163	-21.974	-0.188
	Min	-41.352	-41.151	-1.001
	Std Dev	9.124	9.435	0.467



	2700.4 __In+ Bias Current 3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	80	µA		
Min Limit	-80	µA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-80.000	-80.000	-80.000	-80.000
Min	-41.151	-34.944	-37.947	-26.533
Average	-20.576	-21.126	-22.488	-19.084
Max	0.000	-9.912	-16.521	-5.707
UL	80.000	80.000	80.000	80.000



NDD Report
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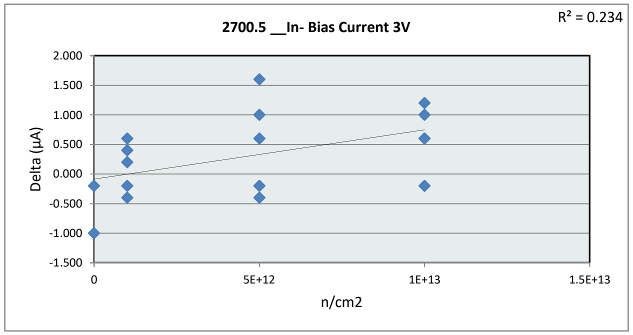
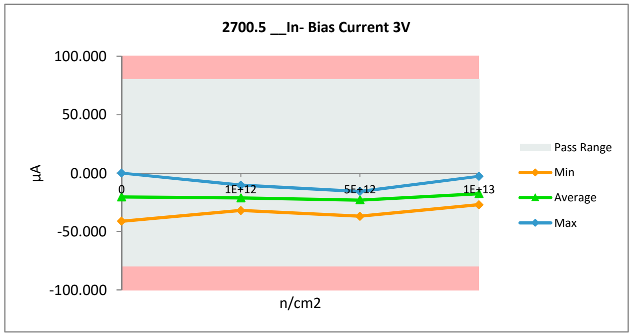
	2700.5 __In- Bias Current 3V	
Test Site	1	1
Tester	ETS364	ETS364
Test Number	EF868301	EF868301
Unit	µA	µA
Max Limit	80	80
Min Limit	-80	-80

n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	-16.120	-15.920	-0.200
0	106	-42.153	-41.151	-1.002
1E+12	1	-31.740	-32.140	0.400
1E+12	2	-10.914	-10.513	-0.401
1E+12	3	-28.536	-29.136	0.600
1E+12	4	-18.723	-18.924	0.201
1E+12	5	-16.521	-16.320	-0.201
5E+12	13	-35.544	-37.146	1.602
5E+12	14	-15.119	-15.720	0.601
5E+12	15	-25.532	-26.533	1.001
5E+12	16	-18.123	-17.722	-0.401
5E+12	17	-18.723	-18.523	-0.200
1E+13	6	-21.727	-22.929	1.202
1E+13	7	-15.519	-16.120	0.601
1E+13	9	-26.533	-27.134	0.601
1E+13	10	-2.904	-2.703	-0.201
1E+13	12	-18.723	-19.725	1.002
	Max	-2.904	-2.703	1.602
	Average	-21.362	-21.668	0.306
	Min	-42.153	-41.151	-1.002
	Std Dev	9.494	9.645	0.687



	2700.5 __In- Bias Current 3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	80	µA		
Min Limit	-80	µA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-80.000	-80.000	-80.000	-80.000
Min	-41.151	-32.140	-37.146	-27.134
Average	-20.576	-21.407	-23.129	-17.722
Max	0.000	-10.513	-15.720	-2.703
UL	80.000	80.000	80.000	80.000



NDD Report
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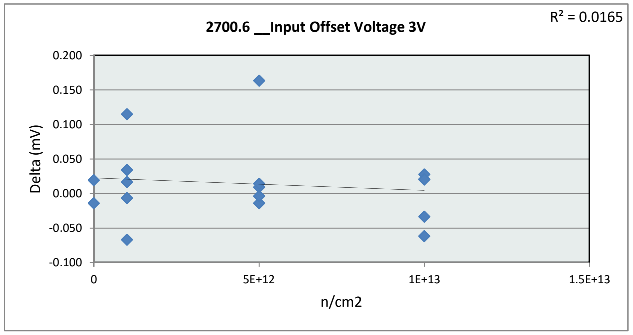
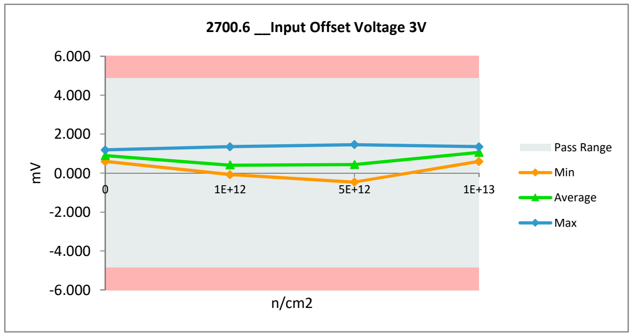
		2700.6 __Input Offset Voltage 3		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mV	mV	
	Max Limit	4.85	4.85	
	Min Limit	-4.85	-4.85	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	1.210	1.191	0.019
0	106	0.578	0.592	-0.014
1E+12	1	1.364	1.347	0.016
1E+12	2	0.173	0.180	-0.007
1E+12	3	0.391	0.357	0.034
1E+12	4	0.330	0.215	0.115
1E+12	5	-0.147	-0.080	-0.067
5E+12	13	1.024	1.015	0.009
5E+12	14	1.476	1.462	0.014
5E+12	15	-0.298	-0.461	0.164
5E+12	16	0.266	0.280	-0.014
5E+12	17	-0.134	-0.130	-0.004
1E+13	6	1.022	1.056	-0.034
1E+13	7	1.290	1.263	0.028
1E+13	9	0.616	0.595	0.021
1E+13	10	1.285	1.347	-0.062
1E+13	12	1.058	1.038	0.020
	Max	1.476	1.462	0.164
	Average	0.677	0.663	0.014
	Min	-0.298	-0.461	-0.067
	Std Dev	0.584	0.600	0.056



	2700.6 __Input Offset Voltage			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	4.85	mV		
Min Limit	-4.85	mV		
n/cm2	0	1E+12	5E+12	1E+13
LL	-4.850	-4.850	-4.850	-4.850
Min	0.592	-0.080	-0.461	0.595
Average	0.892	0.404	0.433	1.060
Max	1.191	1.347	1.462	1.347
UL	4.850	4.850	4.850	4.850



NDD Report
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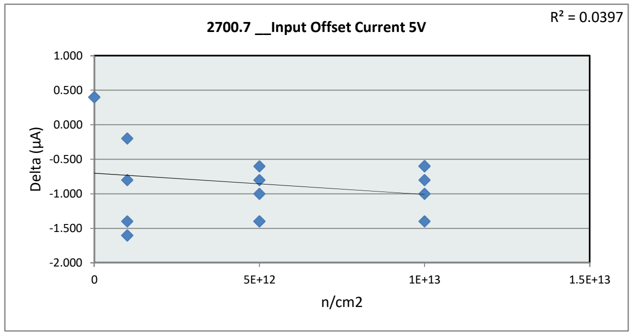
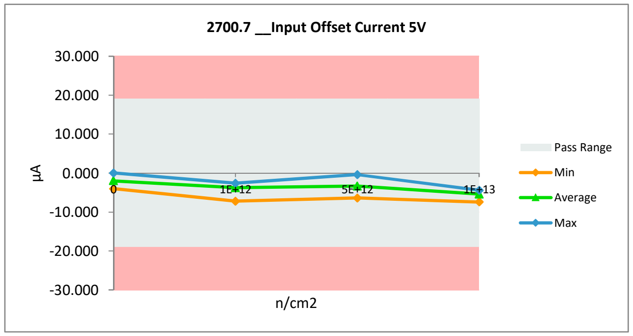
		2700.7 __Input Offset Current 5		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	µA	µA	
	Max Limit	19	19	
	Min Limit	-19	-19	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	-7.409	-7.810	0.401
0	106	-3.605	-4.005	0.400
1E+12	1	-8.010	-7.209	-0.801
1E+12	2	-4.005	-2.604	-1.401
1E+12	3	-5.007	-3.405	-1.602
1E+12	4	-4.606	-3.004	-1.602
1E+12	5	-2.803	-2.604	-0.199
5E+12	13	-7.209	-5.807	-1.402
5E+12	14	-7.009	-6.408	-0.601
5E+12	15	-1.802	-0.401	-1.401
5E+12	16	-2.803	-1.803	-1.000
5E+12	17	-3.204	-2.403	-0.801
1E+13	6	-6.408	-5.406	-1.002
1E+13	7	-8.010	-7.410	-0.600
1E+13	9	-5.207	-4.405	-0.802
1E+13	10	-6.008	-5.407	-0.601
1E+13	12	-5.807	-4.405	-1.402
	Max	-1.802	-0.401	0.401
	Average	-5.230	-4.382	-0.848
	Min	-8.010	-7.810	-1.602
	Std Dev	1.966	2.134	0.619



	2700.7 __Input Offset Current			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	19	µA		
Min Limit	-19	µA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-19.000	-19.000	-19.000	-19.000
Min	-4.005	-7.209	-6.408	-7.410
Average	-2.003	-3.765	-3.364	-5.407
Max	0.000	-2.604	-0.401	-4.405
UL	19.000	19.000	19.000	19.000



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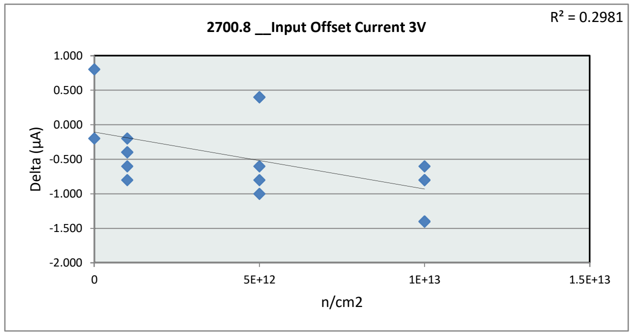
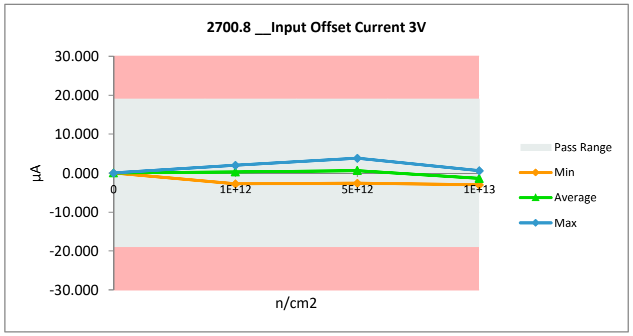
		2700.8 __Input Offset Current 3		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	µA	µA	
	Max Limit	19	19	
	Min Limit	-19	-19	
n/cm2	Serial #	Pre Data.txt	01 post NDD roun	Delta
0	57	-3.204	-3.004	-0.200
0	106	0.801	0.000	0.801
1E+12	1	-3.204	-2.804	-0.400
1E+12	2	0.401	0.601	-0.200
1E+12	3	0.601	1.001	-0.400
1E+12	4	0.000	0.601	-0.601
1E+12	5	1.202	2.002	-0.800
5E+12	13	-1.402	-0.801	-0.601
5E+12	14	-3.404	-2.603	-0.801
5E+12	15	2.804	3.805	-1.001
5E+12	16	1.602	1.201	0.401
5E+12	17	2.002	1.602	0.400
1E+13	6	-2.203	-0.801	-1.402
1E+13	7	-3.805	-3.004	-0.801
1E+13	9	0.000	0.601	-0.601
1E+13	10	-3.804	-3.004	-0.800
1E+13	12	-2.003	-0.600	-1.403
	Max	2.804	3.805	0.801
	Average	-0.801	-0.306	-0.495
	Min	-3.805	-3.004	-1.403
	Std Dev	2.208	2.036	0.601

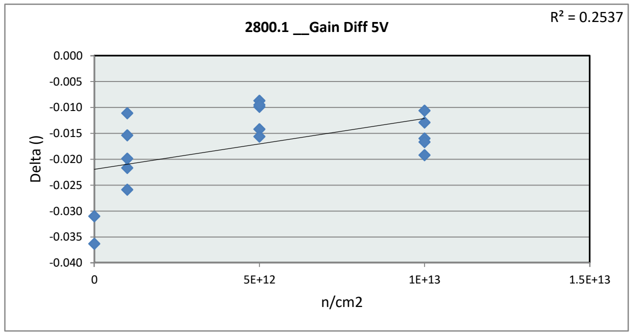


	2700.8 __Input Offset Current			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	19	µA		
Min Limit	-19	µA		
n/cm2	0	1E+12	5E+12	1E+13
LL	-19.000	-19.000	-19.000	-19.000
Min	0.000	-2.804	-2.603	-3.004
Average	0.000	0.280	0.641	-1.362
Max	0.000	2.002	3.805	0.601
UL	19.000	19.000	19.000	19.000

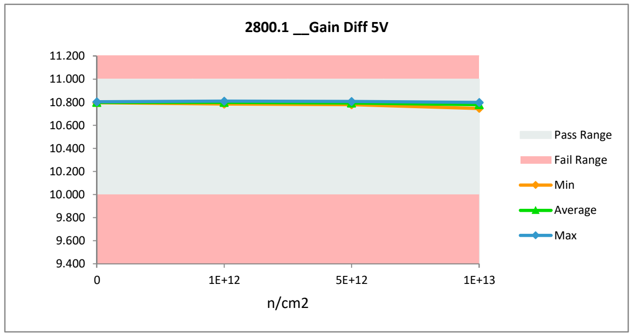


NDD Report
LMH5401-SP

		2800.1 __Gain Diff 5V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit			
	Max Limit	11	11	
	Min Limit	10	10	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	10.763	10.794	-0.031
0	106	10.765	10.802	-0.036
1E+12	1	10.760	10.782	-0.022
1E+12	2	10.793	10.808	-0.015
1E+12	3	10.766	10.786	-0.020
1E+12	4	10.780	10.806	-0.026
1E+12	5	10.795	10.806	-0.011
5E+12	13	10.765	10.779	-0.014
5E+12	14	10.761	10.776	-0.016
5E+12	15	10.790	10.800	-0.010
5E+12	16	10.795	10.804	-0.009
5E+12	17	10.793	10.803	-0.010
1E+13	6	10.729	10.745	-0.016
1E+13	7	10.768	10.781	-0.013
1E+13	9	10.764	10.784	-0.019
1E+13	10	10.769	10.786	-0.017
1E+13	12	10.787	10.797	-0.011
	Max	10.795	10.808	-0.009
	Average	10.773	10.790	-0.017
	Min	10.729	10.745	-0.036
	Std Dev	0.018	0.016	0.008

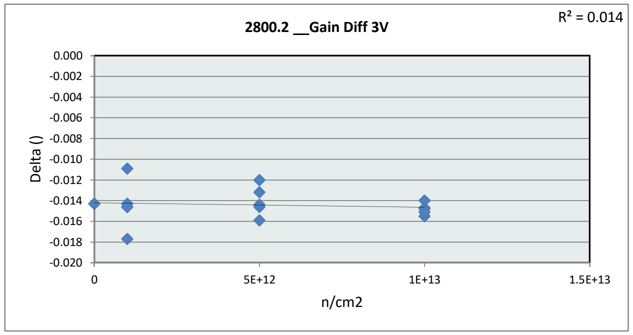


	2800.1 __Gain Diff 5V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	11			
Min Limit	10			
n/cm2	0	1E+12	5E+12	1E+13
LL	10.000	10.000	10.000	10.000
Min	10.794	10.782	10.776	10.745
Average	10.798	10.798	10.792	10.779
Max	10.802	10.808	10.804	10.797
UL	11.000	11.000	11.000	11.000

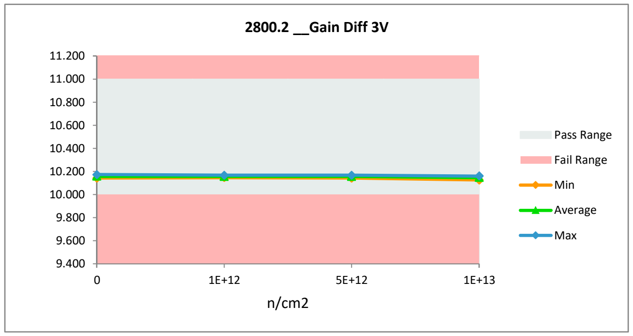


NDD Report
LMH5401-SP

		2800.2 __Gain Diff 3V		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit			
	Max Limit	11	11	
	Min Limit	10	10	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	10.127	10.141	-0.014
0	106	10.159	10.173	-0.014
1E+12	1	10.153	10.168	-0.015
1E+12	2	10.132	10.147	-0.014
1E+12	3	10.142	10.156	-0.015
1E+12	4	10.135	10.153	-0.018
1E+12	5	10.144	10.155	-0.011
5E+12	13	10.153	10.167	-0.014
5E+12	14	10.125	10.141	-0.016
5E+12	15	10.144	10.159	-0.015
5E+12	16	10.138	10.151	-0.013
5E+12	17	10.144	10.156	-0.012
1E+13	6	10.140	10.155	-0.015
1E+13	7	10.125	10.140	-0.015
1E+13	9	10.139	10.154	-0.016
1E+13	10	10.111	10.125	-0.014
1E+13	12	10.144	10.160	-0.015
	Max	10.159	10.173	-0.011
	Average	10.139	10.153	-0.014
	Min	10.111	10.125	-0.018
	Std Dev	0.012	0.012	0.001



	2800.2 __Gain Diff 3V			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	11			
Min Limit	10			
n/cm2	0	1E+12	5E+12	1E+13
LL	10.000	10.000	10.000	10.000
Min	10.141	10.147	10.141	10.125
Average	10.157	10.156	10.155	10.147
Max	10.173	10.168	10.168	10.160
UL	11.000	11.000	11.000	11.000



NDD Report
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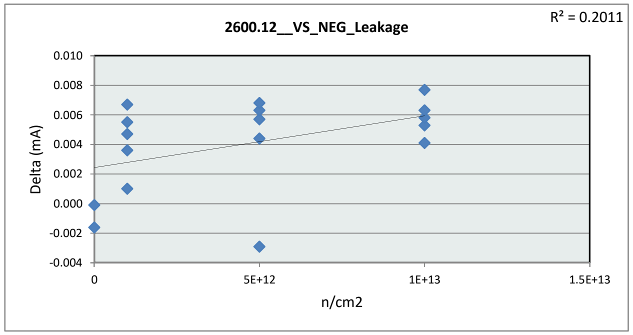
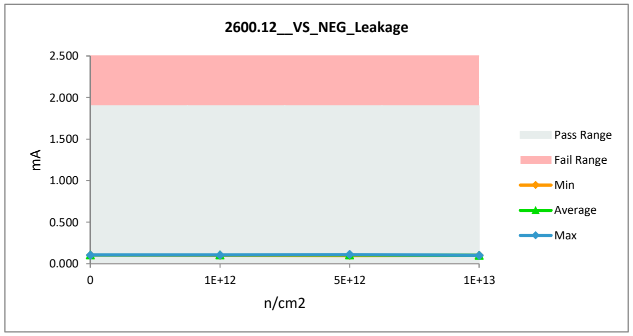
		2600.12__VS_NEG_Leakage		
	Test Site	1	1	
	Tester	ETS364	ETS364	
	Test Number	EF868301	EF868301	
	Unit	mA	mA	
	Max Limit	1.9	1.9	
	Min Limit	0.001	0.001	
n/cm2	Serial #	Pre Data.txt	-01 post NDD roun	Delta
0	57	0.104	0.105	-0.002
0	106	0.106	0.106	0.000
1E+12	1	0.106	0.105	0.001
1E+12	2	0.108	0.102	0.005
1E+12	3	0.105	0.102	0.004
1E+12	4	0.107	0.102	0.005
1E+12	5	0.107	0.100	0.007
5E+12	13	0.106	0.101	0.004
5E+12	14	0.106	0.101	0.006
5E+12	15	0.108	0.111	-0.003
5E+12	16	0.106	0.100	0.006
5E+12	17	0.106	0.099	0.007
1E+13	6	0.106	0.102	0.004
1E+13	7	0.106	0.101	0.005
1E+13	9	0.107	0.101	0.006
1E+13	10	0.108	0.101	0.008
1E+13	12	0.106	0.100	0.006
	Max	0.108	0.111	0.008
	Average	0.106	0.102	0.004
	Min	0.104	0.099	-0.003
	Std Dev	0.001	0.003	0.003



	2600.12__VS_NEG_Leakage			
Test Site	1			
Tester	ETS364			
Test Number	EF868301			
Max Limit	1.9	mA		
Min Limit	0.001	mA		
n/cm2	0	1E+12	5E+12	1E+13
LL	0.001	0.001	0.001	0.001
Min	0.105	0.100	0.099	0.100
Average	0.105	0.102	0.102	0.101
Max	0.106	0.105	0.111	0.102
UL	1.900	1.900	1.900	1.900



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